

CARDIAC RHYTHM DISEASE MANAGEMENT

Product Performance Report

Important Patient Management Information for Physicians



A Message from the Vice President

Quality is much more than an internal business activity. The support and collaboration we receive from physicians, nurses, and others outside our company plays a significant role in many of our quality initiatives. While serving those in your care, you contribute to our ongoing quality efforts. Through sharing your observations, returning explanted products, conducting independent research, you provide us with invaluable information, direction, and advice. Your involvement enhances and expands our ability to effectively track, evaluate, and communicate the performance of our products.

We also rely on your engagement when awareness or action is needed. In the past few weeks, identified physicians with patients who have a Sprint Fidelis® lead received a letter from me and Medtronic outlining important product performance information. If you have not received this Sprint Fidelis letter and would like this information, please contact your Medtronic Representative or Medtronic Technical Services at 1 (800) 723-4636 (US).

Specific to Sprint Fidelis, we are extremely grateful for the invaluable guidance and consultation we received from our Independent Physician Quality Panel members:

R. Hardwin Mead, MD, Palo Alto, CA Steven J. Compton, MD, Anchorage, AK Kevin Hackett, MD, Columbus, OH Hugh Calkins, MD, Baltimore, MD John P. DiMarco, MD, PhD, Charlottesville, VA Mariell Jessup, MD, Philadelphia, PA

We welcome your interest in our Independent Physician Quality Panel. Please direct questions or inquiries regarding this panel to me or David Steinhaus, MD, Vice President and Medical Director, Medtronic Cardiac Rhythm Disease Management.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continue to explore new ways to learn from and expand our system longevity studies. We seek to engage and develop new solutions that leverage our patient management systems, like Medtronic CareLink®, to monitor and measure the performance of products remotely.

As we constantly strive to exceed your needs and expectations, we thank you for your valued contributions.

With appreciation and warm regards,

Reggie Groves

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

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For questions related to this CRDM Product Performance Report, please call US Technical Services at the number above, or write to:

Timothy Smith Medtronic, Inc. 8200 Coral Sea Street NE MS MVN61 Mounds View, MN 55112 USA

email: tim.smith@medtronic.com

For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

Medtronic, Inc.

7000 Central Avenue NE MS T172 Minneapolis, MN 55432-3576 USA

Phone: 1 (800) 328-2518, ext. 44800

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2007 Second Edition

Date cutoff for this edition is July 31, 2007

This report is available online at www.CRDMPPR.medtronic.com

WHAT'S NEW

Malfunction detail for newer CRT, ICD, and IPG models has been expanded to provide additional insight into the performance of these products, see page 10

Sprint Fidelis Advisory, see page 159

New Products

Adapta DR Models ADDRL1 ADDRS1 Virtuoso VR Model D154VWC/D164VWC

Introduction

All product performance reports are not created equal. For over 20 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), Cardiac Resynchronization Therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic Cardiac Rhythm Disease Management (CRDM) uses both returned product analysis and multicenter clinical studies to monitor performance.

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study. Medtronic CRDM is unique in the industry in that we track CRT, ICD, and IPG device survival using both methods.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is

designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

For several years, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted product from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information on page 2 of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see Contact Information on page 2 of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for each individual device and lead in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in the System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined for the study.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads, or
- implanted in patients who are lost to follow-up.

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles *Method for Estimating CRT, ICD, and IPG Device Performance (page 9)* and *Method for Estimating Lead Performance (page 82)*.

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

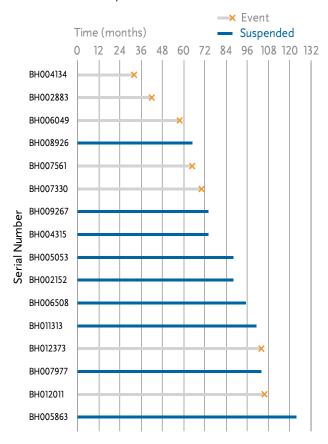


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that 7 of the 16 devices suffered events, and 9 are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval over-estimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices under-estimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The *Interval Survival Probability* (F) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the *Proportion With Event* (E). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

The Cumulative Survival Probabilities from (G) the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	A	В	С	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

A Number Entered	B Number Suspended	C Number of Events	D Effective Sample Size	E Proportion with Event	F Interval Survival Probability	G Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the *Interval Survival Probability* (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.



Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals (for CRT, ICD, and IPG devices) or three-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis
 3rd Edition (Wiley Series in Probability and Statistics)

Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's device registration data and returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications, such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) has functioned normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion - The condition when

- (a) A device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) A device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include an estimated longevity for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from this estimate.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

New Expanded Malfunction Detail

This edition of the Product Performance Report introduces further detail about the nature of the confirmed malfunctions. As with the categorization of Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function, this new detail is presented for the most recently market-released models.

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery – findings linked to the battery and its components

Software/Firmware – findings linked to software or firmware function

Possible Early Battery Depletion – findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive.

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first five years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more malfunctions or battery depletions. This occurs because even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when it has accumulated at least 10,000 implant months, and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in clinical studies (including the System Longevity Study) and the device registration system.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

However, at this time, no adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, the patient mortality rate derived from our device registration system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in our device registration is significantly different from published rates, an adjustment is applied to correct the difference.

7272 InSync ICD

US Market Release	Jul-02	Malfunctions
Registered US Implants	13,000	Therapy Function Not Compromised
Estimated Active US Implants	4,000	Battery
Normal Battery Depletions	365	Electrical Component
Advisories	None	Software/Firmware
		Possible Early Battery Depletion
		Therapy Function Compromised
		Battery

Electrical Component

Product Characteristics

182

168

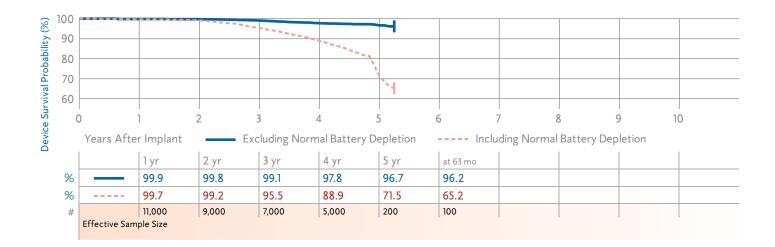
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3 143 14

1

13

NBD Code	VVED
Serial Number Prefix	PJP
Max Delivered Energy	34 J
Estimated Longevity	See page 20

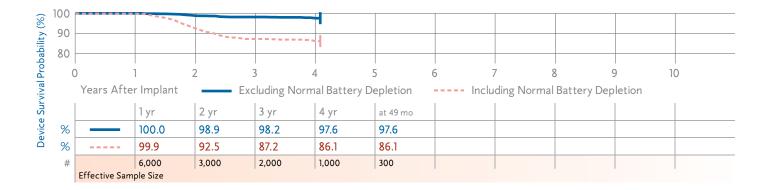


7277 InSync Marquis

US Market Release	Mar-03
Registered US Implants	7,000
Estimated Active US Implants	1,000
Normal Battery Depletions	175
Advisories: See page 161 – 2005 Potent Premature Battery Depletion Due to Battery Short	tial

Malfunctions	72
Therapy Function Not Compromised	62
Battery	1
Electrical Component	8
Software/Firmware	1
Possible Early Battery Depletion	52
Therapy Function Compromised	10
Battery (9 malfunctions related to advisorγ)	9
Electrical Component	1

NBD Code	VVED
Serial Number Prefix	PLT
Max Delivered Energy	30 J
Estimated Longevity	See page 20



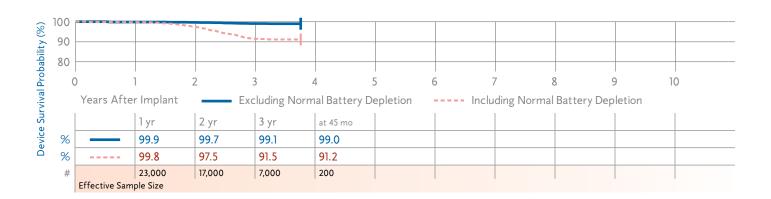


7289 InSync II Marquis

US Market Release	Jul-03	Malfunctions	137
Registered US Implants 28		Therapy Function Not Compromised	109
Estimated Active US Implants	12,000	Electrical Component	13
Normal Battery Depletions		Software/Firmware	1
Advisories: See page 161 – 2005 Potential		Possible Early Battery Depletion	95
Premature Battery Depletion Du Battery Short	ue to	Therapy Function Compromised	28
buttery short		Battery (8 malfunctions related to advisory)	9
		Electrical Component	19

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PRJ
Max Delivered Energy	30 J
Estimated Longevity	See page 20

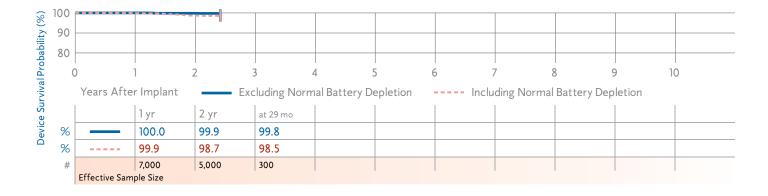


7297 InSync Sentry

US Market Release	Nov-04
Registered US Implants	9,000
Estimated Active US Implants	6,000
Normal Battery Depletions	34
Advisories	None

Malfunctions	11
Therapy Function Not Compromised	10
Battery	1
Electrical Component	3
Possible Early Battery Depletion	6
Therapy Function Compromised	1
Electrical Component	1

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 20

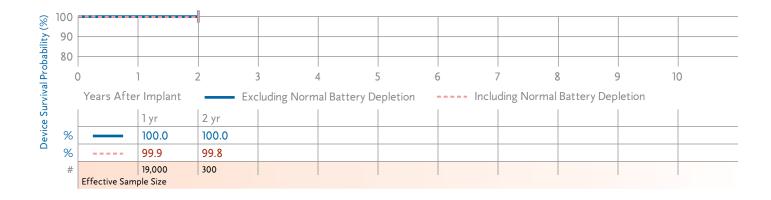




7299 InSync Sentry

US Market Release	Apr-05	Malfunctions	8	NBD Code	VVED
Registered US Implants	29,000	Therapy Function Not Compromised	5	Serial Number Prefix	PRK
Estimated Active US Implants 24,000		Electrical Component	3	Max Delivered Energy	35 J
Normal Battery Depletions	12	Software/Firmware	2	Estimated Longevity	See page 20
Advisories	None	Therapy Function Compromised	3		

Electrical Component



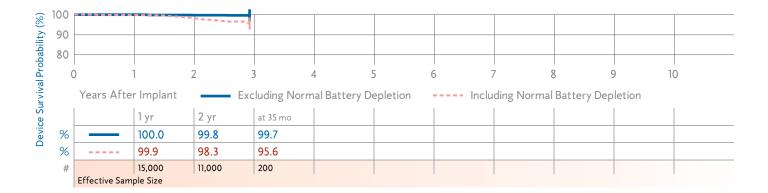
7303 InSync Maximo

US Market Release	Jun-04
Registered US Implants	17,000
Estimated Active US Implants	11,000
Normal Battery Depletions	143
Advisories	None

Product Characteristics

3

Malfunctions	27	NBD Code	VVED
Therapy Function Not Compromised	23	Serial Number Prefix	PRL
Electrical Component	4	Max Delivered Energy	35 J
Software/Firmware	1	Estimated Longevity	See page 20
Possible Early Battery Depletion	18		
Therapy Function Compromised	4		
Electrical Component	4		

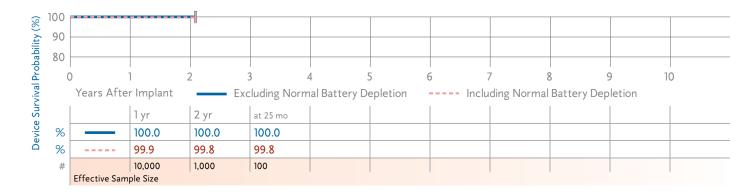




7304 InSync Maximo

Product Characteristics

US Market Release	Apr-05	Malfunctions	4	NBD Code	VVED
Registered US Implants	16,000	Therapy Function Not Compromised	3	Serial Number Prefix	PRL
Estimated Active US Implants	13,000	Battery	1	Max Delivered Energy	35 J
Normal Battery Depletions	7	Electrical Component	2	Estimated Longevity	See page 20
Advisories	None	Therapy Function Compromised	1		
		Electrical Component	1		



8040 InSync

Product Characteristics

US Ma	rket Release		Aug-01 Malfunctions	Malfunctions			28	NBD Code			DDDR	
Registe	ered US Impla	ants	15,000	15,000 Therapy Function Not Compromised		ised	8	Serial N	lumber Pre	fix	PIN	
Estima	nated Active US Implants 5,000) El	Electrical Component		4	Estimat	ted Longev	ity	See page 20		
Norma	al Battery Dep	oletions	220) El	ectrical Interc	onnect		1				
Adviso	ories		None	e Po	ossible Early B	attery Depleti	ion	3				
				Thera	py Function (Compromised		20				
				El	ectrical Interc	onnect		20				
90						*****	```					
90 -		1	2 3		4	5 (5	7		8	9	10
	Years After	r Implant	Exc	luding Norn	nal Battery D	epletion	lı	าcludinย	g Normal	l Battery D	Depletion	
					I	I	1 .					
L		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	79 mo			
%		1 yr 100.0	2 yr 100.0	3 yr 99.9	4 yr 99.8	5 yr 99.6	6 yr 99.4	99				
% %		/	· ·	<u> </u>		<u> </u>	<u> </u>		.4			

Effective Sample Size

20



8042 InSync III

US Market Release	Feb-03
Registered US Implants	23,000
Estimated Active US Implants	14,000
Normal Battery Depletions	43
Advisories	None

Malfunctions	5
Therapy Function Not Compromised	3
Electrical Component	2
Possible Early Battery Depletion	1

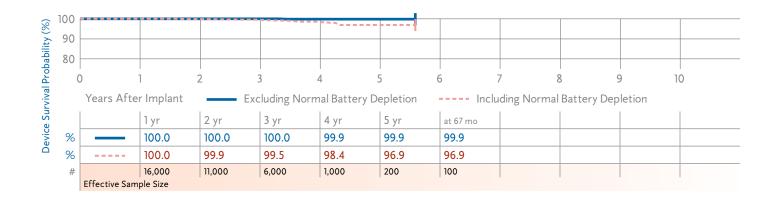
Therapy Function Compromised

Electrical Interconnect

5	NBD Code	DDDR
3	Serial Number Prefix	PKF
2	Estimated Longevity	See page
1		

Product Characteristics

2 2



C154DWK, C164AWK, C174AWK Concerto

US Market Release

Advisories

Registered US Implants

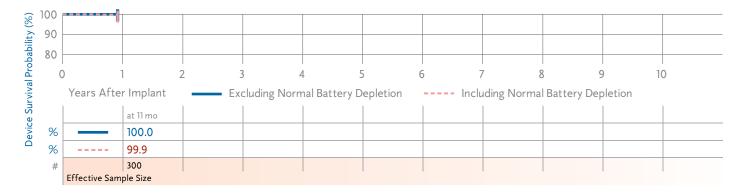
Estimated Active US Implants Normal Battery Depletions

May-06	
20,000	
19,000	
0	

None

Malfunctions
Therapy Function Not Compromised
Electrical Component
Therapy Function Compromised
Electrical Component

4	NBD Code	VVED
2	Serial Number Prefix	PVU, PVT, PVR
2	Max Delivered Energy	35 J
2	Estimated Longevity	See page 20
_		



Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

						Malfunctions	tions			Device Survival Probability (%)	urvival Pro	obability	(%)					
3		Narket esse	bəvərsi; stnslqm	bətsm SU əvi stnsl	ynal Battery Snoitale	rapy Function npromised	rapy ction Not npromised	ls		Years After Implant	er Implaı	1t						
Model Number	Family			tэА	Nor	Con	un∃	toT		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr 8	8 yr	10 yr
8040	InSync	Aug-01	15,000	5,000	220	20 +	∞	28	Excluding Normal Battery Depletion	100.0+	100.0	99.9	99.8 +0.1/-0.1	99.6 +0.1/-0.2	99.4 +0.2/-0.4	99.4 +0.2/-0.4 at 79 mo		
									Including Normal Battery Depletion	99.9 +0.0/-0.1	99.7 +0.1/-0.1	98.4 +0.2/-0.3	96.5 +0.4/-0.4	93.1 +0.6/-0.7	86.4 +2.9/-3.6	82.1 +4.1/-5.1 at 79 mo		
8042	InSync III	Feb-03	23,000 14,000	14,000	43	2 +	3	2	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0	100.0+	99.9	99.9	99.9 +0.0/-0.1 at 67 mo			
									Including Normal Battery Depletion	100.0+0.0/-0.0	99.9 +0.0/-0.1	99.5 +0.1/-0.2	98.4 +0.4/-0.5	96.9 +1.3/-2.2	96.9 +1.3/-2.2 at 67 mo			
C154DWK, C164AWK, C174AWK	Concerto	May-06	20,000 19,000	000,61	0	7	2 =	4	Excluding Normal Battery Depletion	100.0 +0.0/-0.1 at 11 mo								
									Including Normal Battery Depletion	99.9 +0.1/-0.2 at 11 mo								



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

						Estimate	d Longe	vity		Flective	Replacement	
					,***						RI)***	- 1 CU:C
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Life (EOL) Battery Voltage
7272	InSync ICD	DR+LV	66 cc 117 g	34 J	Monthly Quarterly Semiannual	5.4 6.5 6.9	6.3 8.0 8.5	7.3 9.4 10.3	7.8 10.3 11.2	≤ 4.91 V	_	≤ 4.57 V
7277	InSync Marquis	DR+LV split	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.7 5.0 5.5	4.3 6.0 6.7	4.7 7.0 8.0	4.9 7.5 8.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7295	InSync II Protect	DR+LV true	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.7 4.9 5.4	4.0 5.5 6.2	4.2 5.9 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Time Indicators
InSync	8040	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**
InSync III	8042	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**

						Estimate	d Longe	vity		Repl	mmended acement	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cm 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	≤ 2.62 V	_	3 month after RRT or > 16-second charge time

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

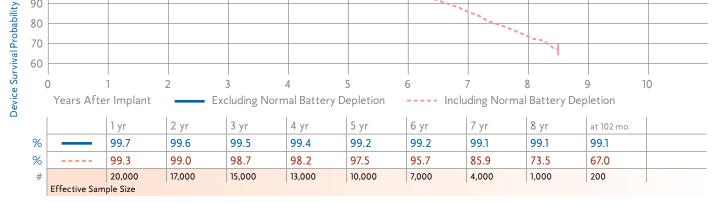
^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing. InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

223 Micro Jewel II				Produc	t Characteris	stics	
US Market Release	Nov-96	Malfunctions	68	NBD Co	de		VVEV
Registered US Implants	10,000			Serial N	umber Prefix		PFR
Estimated Active US Implants	300			Max Del	ivered Energy	,	30 J
Normal Battery Depletions	941			Estimate	ed Longevity		See page 35
Advisories	None						
100							
90			 				
80							
g 70							
80 80 50 50 50 50 50 50 50 50 50 50 50 50 50							
∑ 50					1		
Ans 40					1		
30 Device 30					1		
Э 20 20							

.)()									No.		
20											
10											
		-		1		 -		-	l	. I	
()	1 2	2 .	3 4	1 :	5 6) /	7 8	9	9 10)
	Years After	r Implant	Exc	luding Norm	al Battery De	epletion •	Inclu	ding Normal	Battery Dep	letion	
			2	2	4	le l		7	0		
		l yr	2 yr	3 yr	4 yr	5 yr	буг	7 yr	8 yr	at 105 mo	
%		99.9	99.8	99.7	99.6	99.5	99.3	99.2	98.5	98.5	
%		99.8	99.6	99.3	98.4	96.5	90.3	81.7	57.2	18.2	
#		9,000	8,000	7,000	6,000	5,000	4,000	3,000	1,000	100	
	Effective Samp	ple Size									

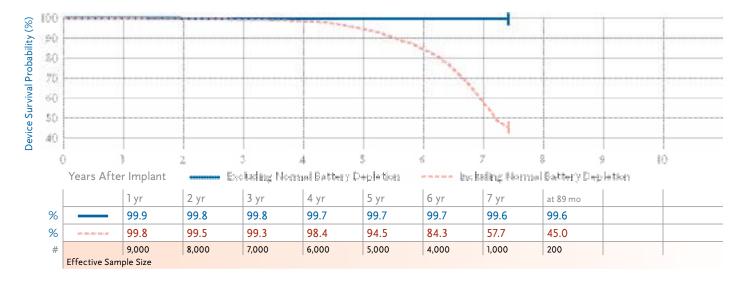
US Market Release	Oct-98	Malfunctions	139	NBD Code	VVEV
Registered US Implants	22,000			Serial Number Prefix	PIP, PLN,
Estimated Active US Implants	7,000				PLP, PLR
Normal Battery Depletions	626			Max Delivered Energy	35 J
Advisories: See page 163 – 1999 Po Circuit Overload	otential			Estimated Longevity	See page 35
<u> </u>					
<u>§</u> 100			*****	•	





7229 GEM II VR Product Characteristics

US Market Release	Jul-99	Malfunctions	26	NBD Code	VVEV
Registered US Implants	11,000			Serial Number Prefix	PJJ
Estimated Active US Implants	2,000			Max Delivered Energy	30 J
Normal Battery Depletions	774			Estimated Longevity	See page 35
Advisories: See page 163 – 1999 Po Circuit Overload also see page 172 – Performance of Battery Discharge Behavior					

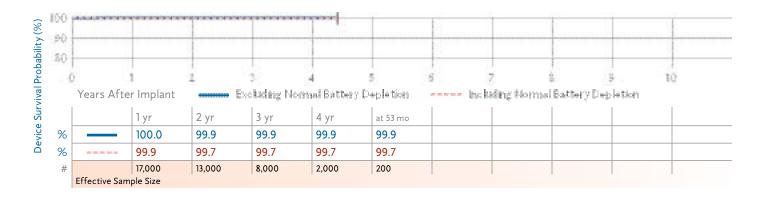


7230 Marquis VR

US Market Release	Dec-02
Registered US Implants	19,000
Estimated Active US Implants	11,000
Normal Battery Depletions	5
Advisories: See page 161 – 2005 Po Premature Battery Depletion Due t	

Malfunctions	20
Therapy Function Not Compromised	14
Electrical Component	10
Possible Early Battery Depletion	3
Other	1
Therapy Function Compromised	6
Battery	1
Electrical Component	5

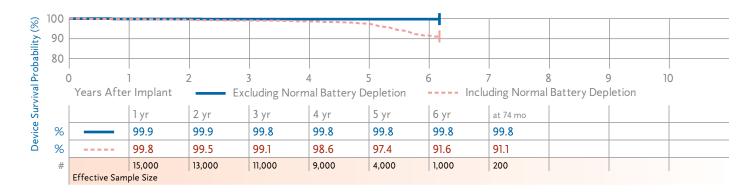
NBD Code	VVEV
Serial Number Prefix	PKD, PLW, PLY
Max Delivered Energy	30 J
Estimated Longevity	See page 35





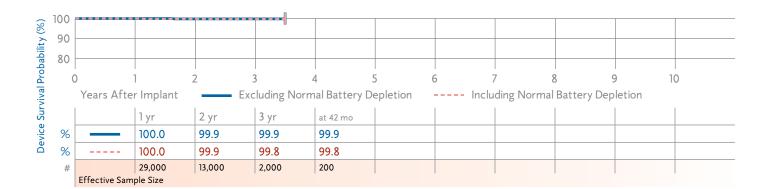
7231 GEM III VR Product Characteristics

US Market Release	Dec-00	Malfunctions	30	NBD Code	VVEV
Registered US Implants	17,000	Therapy Function Not Compromised	22	Serial Number Prefix	PJL
Estimated Active US Implants	9,000	Battery	1	Max Delivered Energy	30 J
Normal Battery Depletions	158	Electrical Component	18	Estimated Longevity	See page 35
Performance Note: see page 172 –		Possible Early Battery Depletion	3		
Performance note on ICD Battery Discharge Behavior		Therapy Function Compromised	8		
Discharge Behavior		Battery	1		
		Electrical Component	7		



7232 Maximo VR **Product Characteristics**

US Market Release	Oct-03	Malfunctions	15	NBD Code	VVED
Registered US Implants	39,000	Therapy Function Not Compromised	9	Serial Number Prefix	PRN
Estimated Active US Implants	33,000	Electrical Component	5	Max Delivered Energy	35 J
Normal Battery Depletions	5	Possible Early Battery Depletion	4	Estimated Longevity	See page 35
Advisories: See page 161 – 2005 Po		Therapy Function Compromised	6		
Premature Battery Depletion Due to Battery Short		Electrical Component	5		
Dattery Short		Possible Early Battery Depletion	1		

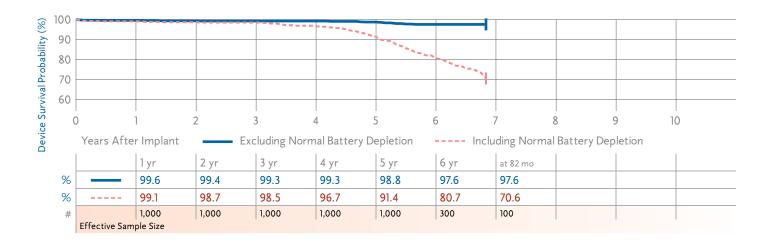




7250 Jewel AF

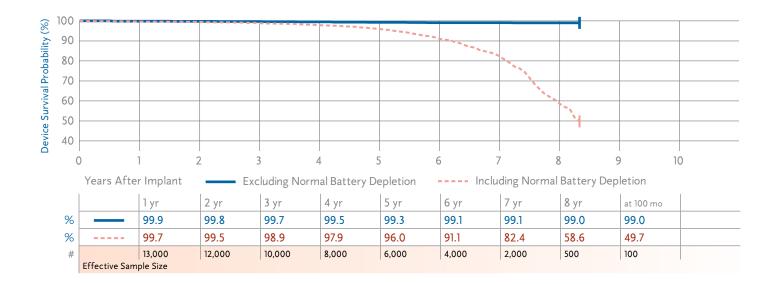
Product Characteristics

US Market Release	Jun-00	Malfunctions	18	NBD Code	VVED
Registered US Implants	1,000			Serial Number Prefix	PID
Estimated Active US Implants	200			Max Delivered Energy	27 J
Normal Battery Depletions 78				Estimated Longevity	See page 35
Advisories	None				



7271 GEM DR

US Market Release	Oct-98	Malfunctions	84	NBD Code	VVED
Registered US Implants	15,000			Serial Number Prefix	PIM
Estimated Active US Implants	4,000			Max Delivered Energy	27 J
Normal Battery Depletions	562			Estimated Longevity	See page 35
Advisories	None				





7273 GEM II DR Product Characteristics

ι	JS Ma	rket Release		Feb-99	Malf	unctions		52	NBD Co	de		VVED
F	Registered US Implants 15,000 Estimated Active US Implants 10		15,000					Serial N	umber Prefix		PJK	
E)				Max De	livered Energy	1	30 J		
١	Norma	al Battery Dep	letions	2,27	l				Estimat	Estimated Longevity		See page 35
F	erfor	mance Note: mance note o arge Behavior										
	100									I	I	
	90						•					
8	80											
Device Survival Probability (%)												
	70											
al Pr	60											
rviv	50											
e Su	40											
evic	30											
Δ	20						1					
	10											
		\ 7	' 	2 3		4	5	6 7		3 9		10
		, ,		۷ 3		4	J	7) :	7	10
		Years After	r Implant	Exc	luding Nor	mal Battery D	epletion	Includir	ng Normal	Battery Dep	letion	
			1 yr	2 yr	3 yr	4 yr	5 yr	at 66 mo				
	%		99.8	· ·	99.6	99.6	99.6	99.6				1
	%		99.5	98.7	95.6	82.2	45.1	12.4				
						_	+					\rightarrow

7274 Marquis DR

US Market Release	Mar-02
Registered US Implants	48,000
Estimated Active US Implants	22,000
Normal Battery Depletions	147
Advisories: See page 161 – 2005 Pot	tential

13,000

Effective Sample Size

12,000

9,000

6,000

Advisories: See page 161 – 2005 Potential Premature Battery Depletion Due to Battery Short

Malfunctions	113
Therapy Function Not Compromised	50
Battery	4
Electrical Component	22
Possible Early Battery Depletion	24
Therapy Function Compromised	63
Battery (36 malfunctions related to advisory)	42

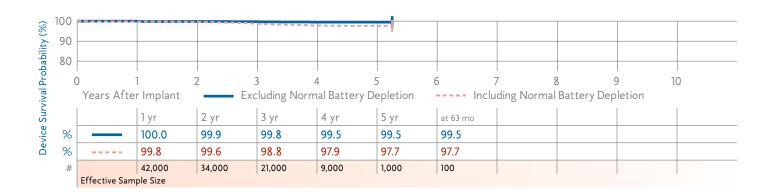
Electrical Component

2,000

200

21

NBD Code	VVED
Serial Number Prefix	PKC
Max Delivered Energy	30 J
Estimated Longevity	See page 35





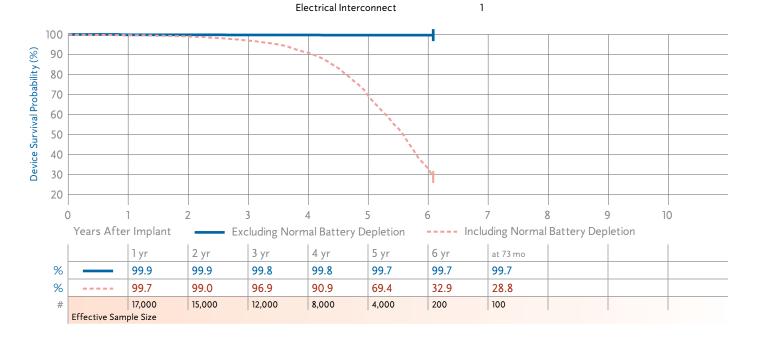
7275 GEM III DR

Discharge Behavior

US Market Release	Nov-00
Registered US Implants	20,000
Estimated Active US Implants	5,000
Normal Battery Depletions	1,684
Performance Note: see page 172 – Performance note on ICD Battery	

Malfunctions	38
Therapy Function Not Compromised	27
Battery	1
Electrical Component	11
Software/Firmware	1
Possible Early Battery Depletion	14
Therapy Function Compromised	11
Battery	2
Electrical Component	8

NBD Code	VVED
Serial Number Prefix	РЈМ
Max Delivered Energy	30 J
Estimated Longevity	See page 35
	·





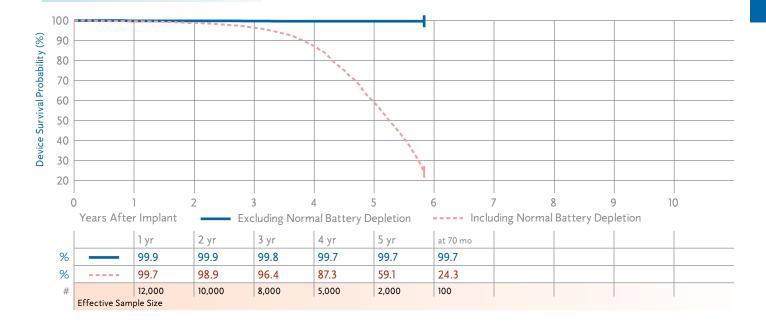
7276 GEM III AT

US Market Release	Feb-01	Malfunctions	31	
Registered US Implants	14,000	Therapy Function Not Compromised	24	
Estimated Active US Implants	3,000	Electrical Component	6	
Normal Battery Depletions	1,314	Software/Firmware	1	
Performance Note: see page 172 –		Possible Early Battery Depletion	17	
Performance note on ICD Battery Discharge Rehavior		Therapy Function Compromised	7	

Product Characteristics

7

NBD Code	DDED	
Serial Number Prefix	PKE	
Max Delivered Energy	30 J	
Estimated Longevity	See page	3.



Electrical Component

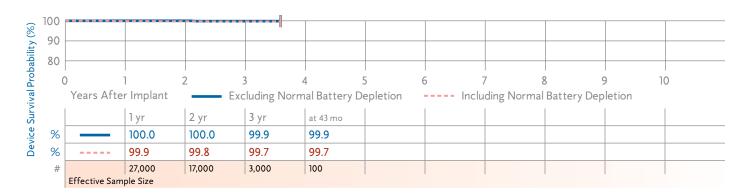
7278 Maximo DR

US Market Release	Oct-03
Registered US Implants	34,000
Estimated Active US Implants	27,000
Normal Battery Depletions	15
Advisories: See page 161 – 2005 Pote	

Premature Battery Depletion Due to **Battery Short**

Malfunctions	15
Therapy Function Not Compromised	9
Electrical Component	7
Possible Early Battery Depletion	2
Therapy Function Compromised	6
Electrical Component	5
Possible Early Battery Depletion	1

NBD Code	VVED	
Serial Number Prefix	PRM	
Max Delivered Energy	35 J	
Estimated Longevity	See page	35





7288 Intrinsic **Product Characteristics**

JS Marke	et Release		Aug-0	4 M	alfunctions			21	NBD Code			VVED
≀egister∈	ed US Impl	ants	30,00	0 т	herapy Fu	nction Not Co	mpromised	15	Serial Numbe	er Prefix		PUB
stimate	d Active U	S Implants	25,00	0	Battery			2	Max Delivere	d Energy		35 J
Normal B	Battery Dep	pletions		8	Electrica	al Component		7	Estimated Lo	ongevity		See page 3
Advisorie	es		Non	e	Softwar	e/Firmware		1				
					Possible	Early Battery	Depletion	5				
				Т	herapy Fui	nction Compr	omised	6				
					Electrica	al Component		6				
100												
100 90 80												
90 —				3	4	5	6	7	8	9		10
90	ears Afte	1	2		4 Iormal Bat	5 ttery Depleti	_	7 Includin	8 g Normal Batt		tion	10
90		1	2		4 Iormal Bat		_	7 Includin	_		tion	10
90		1 r Implant	2 Exc	cluding N	4 Iormal Bat		_	7 Includin	_		tion	10
90		1 r Implant	2 Exc	cluding N	4 Jormal Bat		_	7 Includin	_		tion	10

7290 Onyx **Product Characteristics**

JS Market Release		Mar-04	4 Malfur	nctions			3	NBD Co	ode		VVEV
Registered US Impl	lants	1,000) Thera	apy Function	Not Compromi	sed	2	Serial N	lumber Prefi	x	PRP
Estimated Active U	IS Implants	1,000) El	ectrical Com	ponent		2	Max De	livered Ener	gy	30 J
Normal Battery De	pletions	() Thera	apy Function	Compromised		1	Estimat	ed Longevit	у	See page 3
Advisories		None	e El	ectrical Com	ponent		1				
100											
90											
80											
	1			4							10
0	I	2 3)	4	5 6		/		8	9	10
Years Afte	er Implant	Exc	luding Norn	nal Battery [Depletion -	Incl	uding	g Normal	Battery De	pletion	
	1 yr	2 yr	at 32 mo								
%	99.9	99.5	99.5								
%	99.8	99.0	99.0								
#	1,000	300	100								
Effective Sam	inle Size										

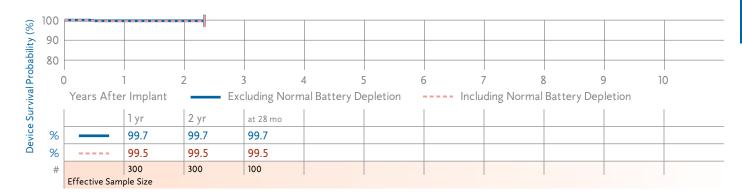
Effective Sample Size



D153ATG, D153DRG EnTrust

Product Characteristics

US Market Release	Jun-05	Malfunctions	2	NBD Code	DDED, VVED
Registered US Implants	400	Therapy Function Not Compromised	1	Serial Number Prefix	PNR
Estimated Active US Implants	300	Possible Early Battery Depletion	1	Max Delivered Energy	30 J
Normal Battery Depletions	0	Therapy Function Compromised	1	Estimated Longevity	See page 36
Advisories	None	Electrical Component	1		



D154ATG, D154DRG EnTrust

ket Release		Jun-05	Malfun	ctions			4	NBD Co	ode		DDED, VVEI
ered US Impla	ants	25,000	Thera	py Function N	Not Compromis	ed	1	Serial N	lumber Prefi	x	PNR
ted Active U	S Implants	23,000	Ele	ectrical Comp	onent		1	Max De	livered Energ	gy	35 J
l Battery Dep	oletions	0	Thera	py Function (Compromised		3	Estimat	ed Longevity	/	See page 36
ries		None	Ele	ctrical Comp	onent		3				
									T		
											10
	1	2 3	4	1	5 6		7	8	8	9	10
Years After	r Implant	Exclu	ding Norm	al Battery D	epletion -	Inclu	uding	Normal	Battery De	pletion	
	1 yr	at 23 mo									
	100.0	100.0									
	100.0	100.0									
	14,000	100					1				
t I r	ered US Implated Active U: Battery Depries Years After	red US Implants ted Active US Implants I Battery Depletions ries 1 Years After Implant 1 yr 100.0	Pred US Implants 25,000 ted Active US Implants 23,000 Battery Depletions 0 ries None 1 2 3 Years After Implant Exclusion 1 2 3 mo 1 1 1 1 2 1 1 1 1 1 1 1 1 1 1 1 1 1 1	Pred US Implants 25,000 Thera ted Active US Implants 23,000 Elected Active US Implants 23,000 Thera in the Implants None Thera in the Implant	Pred US Implants 25,000 Therapy Function Noted Active US Implants 23,000 Electrical Computes None None Therapy Function Of Electrical Computes None None Electrical Computes None Electrical Compute	Therapy Function Not Compromised Electrical Component Therapy Function Not Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Not Component Therapy Function Not Compromised Electrical Component Therapy Function Not Component	Therapy Function Not Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Compromised Electrical Component Electrical Component Flectrical Component Electrical Component Flectrical Component Flectrical Component Electrical Component Flectrical Component Flectric	Pred US Implants 25,000 Therapy Function Not Compromised 1 Ited Active US Implants 23,000 Electrical Component 1 I Battery Depletions 0 Therapy Function Compromised 3 Pries None Electrical Component 3 Flectrical Component 3	Pred US Implants 25,000 Therapy Function Not Compromised 1 Serial Noted Active US Implants 23,000 Electrical Component 1 Max Described Battery Depletions 0 Therapy Function Compromised 3 Estimates None Electrical Component 3 Therapy Function Compromised 3 Estimates None Electrical Component 3 Figure 1	Therapy Function Not Compromised 1 Serial Number Prefix ted Active US Implants 23,000 Electrical Component 1 Max Delivered Energy Estimated Longevity ries None Electrical Component 3 Estimated Longevity Electrical Component 3 Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Therapy Function Compromised 5 Estimated Longevity Therapy Function Compromised 6 Estimated Longevity Therapy Function Compromised 7 Estimated Longevity Therapy Func	Therapy Function Not Compromised 1 Serial Number Prefix Electrical Component 1 Max Delivered Energy Estimated Longevity Therapy Function Compromised 3 Estimated Longevity Electrical Component 3 Figure 1 Figure 2 Figure 3 Figure 3 Figure 3 Figure 4 Fig



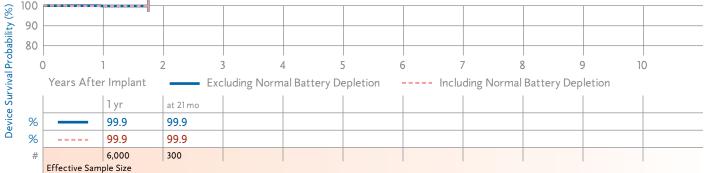
D154AWG, D164AWG Virtuoso

Product Characteristics

JS Market Release	May-06	Malfunctions		3	NBD Code		VVED
Registered US Implants	19,000	Therapy Function Not Co	mpromised	1	Serial Numbe	r Prefix	PVV, PUL
Estimated Active US Implants	18,000	Electrical Component		1	Max Delivere	d Energy	35 J
Normal Battery Depletions	1	Therapy Function Compro	omised	2	Estimated Lo	ngevity	See page 36
Advisories	None	Electrical Component		2			
90							
80 0 1 2	2 3	4 5	6	7 Including	8 R Normal Batte	9 ery Depletion	10
80 0 1 2 Years After Implant	2 3 —— Excludi	4 5 ng Normal Battery Depletio	_	7 Including	8 g Normal Batto	-	
80 0 1 22 Years After Implant at 11 mo 100.0	2 3 Excludi	4 5 ng Normal Battery Depletic	_	7 Includin		-	
80 0 1 22 Years After Implant at 11 mo	2 3 Excludi	4 5 ng Normal Battery Depletio	_	7 Includin		-	

D154VRC EnTrust

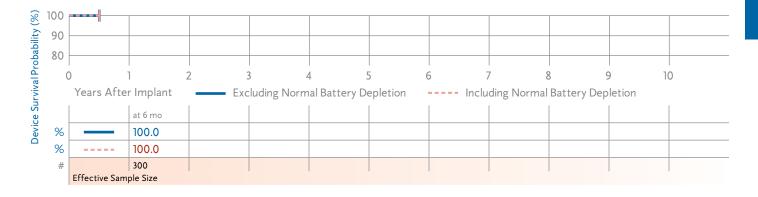
US Market Release	Jun-05	Malfunctions	5	NBD Code	VVEV
Registered US Implants	13,000	Therapy Function Not Compromised	2	Serial Number Prefix	PNT
Estimated Active US Implants	12,000	Electrical Component	1	Max Delivered Energy	35 J
Normal Battery Depletions	1	Possible Early Battery Depletion	1	Estimated Longevity	See page 36
Advisories	None	Therapy Function Compromised	3		
		Electrical Component	3		
§ 100					
0)					





D154VWC, D164VWC Virtuoso

US Market Release	May-06	Malfunctions	1	NBD Code	VVEV
Registered US Implants	6,000	Therapy Function Not Compromised	1	Serial Number Prefix	PUN
Estimated Active US Implants	6,000	Electrical Interconnect	1	Max Delivered Energy	35 J
Normal Battery Depletions	0	Therapy Function Compromised	0	Estimated Longevity	See page 36
Advisories	None				



Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

						Malfunctions	tions			Device S	Device Survival Probability (%)	obability	(%)					
2		Market Sese	istered stnslqml	bətsmi SU əvi stnsl	mal Battery snoisel	erapy Function npromised	rapy ction Not npromised	al		Years Af	Years After Implant	nt						
Number	Family	K ^e le N2	N2 I Ke§	tοΑ		Cor	un⊣	тот		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7223	Micro Jewel II	96-voN	10,000	300	941	1	I	89	Excluding Normal Battery Depletion	99.9 +0.0/-0.1	99.8	99.7 +0.1/-0.1	99.6 +0.1/-0.2	99.5 +0.1/-0.2	99.3 +0.2/-0.3	99.2 +0.2/-0.3	98.5 +0.4/-0.5	98.5 +0.4/-0.5 at 105 mo
									Including Normal Battery Depletion	99.8	99.6	99.3 +0.2/-0.2	98.4 +0.3/-0.3	96.5 +0.4/-0.5	90.3	81.7	57.2 +1.8/-1.9	18.2 +2.5/-2.4 at 105 mo
7227	GEM	Oct-98	22,000	2,000	979	1	I	139	Excluding Normal Battery Depletion	99.7 +0.1/-0.1	99.6	99.5 +0.1/-0.1	99.4 +0.1/-0.1	99.2 +0.1/-0.1	99.2 +0.1/-0.2	99.1 +0.1/-0.2	99.1 +0.2/-0.2	99.1 +0.2/-0.2 at 102 mo
	Advisories: se	Advisories: see page 163 – 1999 Potential Circuit Overload	1999 Potenti	al Circuit Ove	erload	1	I	ı	Including Normal Battery Depletion	99.3 +0.1/-0.1	99.0	98.7 +0.1/-0.2	98.2 +0.2/-0.2	97.5 +0.2/-0.3	95.7 +0.4/-0.4	85.9 +0.8/-0.9	73.5	67.0 +2.3/-2.4 at 102 mo
7229	GEM II VR	66-ln[11,000	2,000	774	1	I	26	Excluding Normal Battery Depletion	99.9 +0.0/-0.1	99.8	99.8 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1	99.6 +0.1/-0.2	99.6 +0.1/-0.2 at 89 mo	
	Advisories: see pagalso see pagalso see pagalso see page 172 – Discharge Behavior	Advisories: see page 163 – 1999 Potential Circuit Overload; also see page 172 – Performance note on ICD Battery Discharge Behavior	1999 Potenti nance note c	al Circuit Ove on ICD Batter	erload; 'Y	1	1	1	Including Normal Battery Depletion	99.8	99.5	99.3 +0.2/-0.2	98.4 +0.3/-0.3	94.5 +0.5/-0.6	84.3 +1.0/-1.0	57.7 +1.9/-2.0	45.0 +2.9/-2.9 at 89 mo	
7230	Marquis VR	Dec-02	000,61	11,000	5	+	14 =	20	Excluding Normal Battery Depletion	100.0	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 53 mo				
	Advisories: se Battery Deple	Advisories: see page 161 – 2005 Potential Premature Battery Depletion Due to Battery Short	2005 Potenti attery Short	ial Premature	a)	(0) (advisory	(0) (0) (0) (advisory-related subset)		Including Normal Battery Depletion	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1	99.7 +0.1/-0.1 at 53 mo				
7231	GEM III VR	Dec-00	17,000	000%	158	+ ∞	22 =	30	Excluding Normal Battery Depletion	99.9	99.9 +0.0/-0.1	99.8	99.8 +0.1/-0.1	99.8	99.8 +0.1/-0.1	99.8 +0.1/-0.1 at 74 mo		
	see page 172 - Discharge Bel	see page 172 – Performance note on ICD Battery Discharge Behavior	ce note on	ICD Battery					Including Normal Battery Depletion	99.8	99.5	99.1 +0.1/-0.2	98.6 +0.2/-0.2	97.4 +0.3/-0.4	91.6 +1.0/-1.2	91.1 +1.2/-1.4 at 74 mo		
7232	Maximo VR	Oct-03	39,000	33,000	22	+	e 	15	Excluding Normal Battery Depletion	100.0	99.9	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 42 mo					
	Advisories: se Battery Deple	Advisories: see page 161 – 2005 Potential Premature Battery Depletion Due to Battery Short	2005 Potent attery Short	ial Prematur		(0) + (advisory-	(0) + (0) = (0) (advisory-related subset)		Including Normal Battery Depletion	100.0+0.0/-0.0	99.9	99.8 +0.1/-0.1	99.8 +0.1/-0.1					
7250	Jewel AF)un-00	1,000	200	78	1	I	18	Excluding Normal Battery Depletion	99.6	99.4	99.3 +0.4/-0.7	99.3	98.8	97.6 +1.0/-1.6	97.6 +1.0/-1.6 at 82 mo		
									Including Normal Battery Depletion	99.1	98.7	98.5	96.7	91.4	80.7	70.6 +4.6/-5.2 at 82 mo		

		10 yr	99.0 +0.2/-0.3 at 100 mo	49.7 +3.7/-3.8 at 100 mo														
		8 yr	99.0	58.6 +2.3/-2.4														
		7 yr	99.1 +0.2/-0.2	82.4 +1.1/-1.2					99.7 +0.1/-0.1 at 73 mo	28.8 +2.7/-2.7 at 73 mo								
		6 yr	99.1 +0.2/-0.2	91.1	99.6 +0.1/-0.1 at 66 mo	12.4 +1.9/-1.8 at 66 mo	99.5 +0.1/-0.1 at 63 mo	97.7 +0.2/-0.2	99.7	32.9 +2.3/-2.2	99.7 +0.1/-0.2 at 70 mo	24.3 +3.0/-2.9 at 70 mo						
		5 yr	99.3 +0.1/-0.2	96.0	99.6 +0.1/-0.1	45.1 +1.4/-1.4	99.5 +0.1/-0.1	97.7 +0.2/-0.2	99.7 +0.1/-0.1	69.4	99.7 +0.1/-0.2	59.1 +1.5/-1.5						
(%)		4 yr	99.5 +0.1/-0.2	97.9 +0.3/-0.3	99.6 +0.1/-0.1	82.2 +0.8/-0.8	99.5 +0.1/-0.1	97.9 +0.2/-0.2	99.8 +0.1/-0.1	90.9 +0.5/-0.5	99.7 +0.1/-0.2	87.3 +0.7/-0.8	99.9 +0.0/-0.1 at 43 mo	99.7 +0.1/-0.1				
Device Survival Probability (%)	ınt	3 yr	99.7 +0.1/-0.1	98.9 +0.2/-0.2	99.6 +0.1/-0.1	95.6 +0.4/-0.4	99.8	98.8 +0.1/-0.1	99.8	96.9	99.8	96.4 +0.4/-0.4	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.9 +0.0/-0.1 at 33 mo	99.7 +0.1/-0.1 at 33 mo	99.5 +0.4/-1.1 at 32 mo	99.0 +0.6/-1.3 at 32 mo
urvival P	Years After Implant	2 yr	99.8	99.5 +0.1/-0.1	99.7	98.7 +0.2/-0.2	99.9	99.6	99.9	99.0	99.9	98.9 +0.2/-0.2	100.0+0.0/-0.0	99.8 +0.0/-0.1	99.9	99.7 +0.1/-0.1	99.5	99.0
Device S	Years A	l yr	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.8	99.5 +0.1/-0.1	100.0+0.0/-0.0	99.8	99.9	99.7 +0.1/-0.1	99.9 +0.0/-0.1	99.7 +0.1/-0.1	100.0+0.0/-0.0	99.9	100.0+0.0/-0.0	99.9	99.9	99.8
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
			Ž	Nor	No	Nor	No	No	No	Nor	Nor	Nor	Nor	Norn	Nor	Norr	No	Norn
	ĮE	stoT	84 Nor	N	52 Nor	Nor	Non		38	Norr	31 Norr	Norr	15 Norr	_	21	Norr	8	Norn
unctions	yqpy ction Mot bəsimorqn Ig	Fun		Nor		Nor				Nor		Norr		_		Norr		Norr
Malfunctions	ction Mot npromised	Con Fund Con		Nor		Nor	50 = 113	(2) = (36) r-related subset)	27 = 38	Norr	24 = 31	Norr	9 = 15	(0) = (0) -related subset)	15 = 21	Norr	2 = 3	Norr
Malfunctions	ppromised rapy ction Mot npromised	Ped no no enu no no on		Nor	_ 52	1	+ 50 = 113	(34) + (2) = (36) (advisory-related subset)	+ 27 = 38	Norr	+ 24 = 31	Non	+ 9 = 15	(0) + (0) = (0) (advisory-related subset)	+ 15 = 21	Norr	+ 2 = 3	Norr
Malfunctions	rapy Function rapy Function rapy rapy ction Not opromised	Act Imp Nor Dep The Con Fund	- 84	Nor	52	1	63 + 50 = 113	(34) + (2) = (36) (advisory-related subset)	11 + 27 = 38		7 + 24 = 31		6 + 9 = 15	(0) + (0) = (0) (advisory-related subset)	6 + 15 = 21	Norr	1 + 2 = 3	Norr
Malfunctions	ive US lants mal Battery nletions rapy Function npromised rapy rapy npromised	Esti Imp Mor Mor Mor The Con The Fun	562 - 84	Nor	2,271 — 52	1	147 63 + 50 = 113	(34) + (2) = (36) (advisory-related subset)	1,684 11 + 27 = 38		1,314 7 + 24 = 31		15 6 + 9 = 15	(0) + (0) = (0) (advisory-related subset)	8 6 + 15 = 21	Norr	0 1 + 2 = 3	Norr
Malfunctions	batem by we US ive US lants mal Battery rispy Function rapy Function rapy we we w	Regg USI Esti Imp Mor Inp The Con	4,000 562 84	Nor	10 2,271 - 52	1	22,000 147 63 + 50 = 113	(34) + (2) = (36) (advisory-related subset)	5,000 1,684 11 + 27 = 38	rmance note on ICD Battery	3,000 1,314 7 + 24 = 31	rmance note on ICD Battery	27,000 15 6 + 9 = 15	(0) + (0) = (0) (advisory-related subset)	25,000 8 6 + 15 = 21	Norr	1,000 0 1 + 2 = 3	Norr
Malfunctions	istered mplants mated ive US lost lost lost mal Battery repy Function repy Function repy Function myromised	Regg USI Esti Imp Mor Inp The Con	15,000 4,000 562 — — 84	Nor	15,000 10 2,271 — 52	1	48,000 22,000 147 63 + 50 = 113		20,000 5,000 1,684 11 + 27 = 38	see page 172 – Performance note on ICD Battery Discharge Behavior	14,000 3,000 1,314 7 + 24 = 31	see page 172 – Performance note on ICD Battery Discharge Behavior	34,000 27,000 15 6 + 9 = 15	_	30,000 25,000 8 6 + 15 = 21	Norr	1,000 1,000 0 1 + 2 = 3	Norr

	C	D
7		

		8 yr										
	nt	7 yr										
		6 yr										
		5 yr										
(%)		4 yr										
obability		3 yr	99.7 +0.2/-1.6 at 28 mo	99.5 +0.4/-1.6 at 28 mo								
Device Survival Probability (%)	Years After Implant	2 yr	99.7 +0.2/-1.6	99.5 +0.4/-1.6	100.0 +0.0/-0.0 at 23 mo	100.0 +0.0/-0.1 at 23 mo			99.9 +0.0/-0.1 at 21 mo	99.9 +0.1/-0.1 at 21 mo		
Device S	Years A	1 yr	99.7 +0.2/-1.6	99.5 +0.4/-1.6	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.1 at 11 mo	99.9 +0.0/-0.1 at 11 mo	99.9	99.9 +0.1/-0.1	100.0 +0.0/-0.1 at 6 mo	100.0 +0.0/-0.1 at 6 mo
,			Excluding Normal Battery Depletion	Including Normal Battery Depletion								
	Įε	toT	7		4		ю		52		_	
tions	rapy toM noita npromised	Fun	-		-		-		2 =		-	
Malfunctions	rapy Function pesimorqu	uo⊃	+		+		5 +		+		+	
	mal Battery eletions	Nor Dep	0		0		_		_		0	
	bətsm SU əvi stnsi	tэА	300		23,000		18,000		12,000		6,000	
	bərətsi stnslqm	N2 I Keĝ	400		25,000		19,000		13,000		6,000	
	Narket sase		Jun-05		Jun-05		May-06		Jun-05		May-06	
		Family	EnTrust DR		EnTrust DR		Virtuoso DR		EnTrust VR		Virtuoso VR	
Model Number						D154AWG D164AWG				D154VWC, D164VWC	1	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

	Family	Connector Style	Volume/ Mass*	Delivered Energy	Estimated Longevity					Elective Replacement		
Model Number					Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time Time	End of Life (EOL) Battery Voltage
7223	Micro Jewel II	Сх	54 cc 97 g	30 J	Monthly Quarterly Semiannual	4.9 6.3 6.8	5.4 7.1 7.7	5.8 7.8 8.5	6.0 8.1 9.0	≤ 4.91 V	_	≤ 4.57 V ^{‡‡}
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V [§]
7229	GEM II VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.6 5.0 5.6	3.9 5.5 6.3	4.1 6.0 6.9	4.2 6.2 7.1	≤ 2.55 V	-	≤ 2.40 V
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7250	Jewel AF	G, H	56 cc* 96 g	27 J	Monthly Quarterly Semiannual	5.3 6.5 7.0	6.1 7.6 8.2	6.7 8.7 9.4	7.0 9.2 10.0	≤ 4.94 V	_	≤ 4.50 V
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7273	GEM II DR	DR	39.5 cc 77 g	30 J	Monthly Quarterly Semiannual	2.8 3.7 4.0	3.2 4.3 4.7	3.5 4.8 5.4	3.7 5.1 5.8	≤ 2.55 V	-	≤ 2.40 V
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	-	≤ 2.40 V
7276	GEM III AT	DR	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.3 4.5	3.8 5.1 5.5	4.3 5.9 6.5	4.5 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7287	Intrinsic 30	DR	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.5 6.2	4.3 6.3 7.2	4.7 7.0 8.2	4.8 7.4 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

^{‡‡} For Model 7223 devices, if charge time exceeds 60 seconds, the devices are at EOL. If 2 consecutive charge cycles exceed 60 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency output VVI pacing are disabled.

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If 3 consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

						stimate	d Longe	rity			nmended	
					**						acement RT)***	_
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D153VRC	EnTrust	Сх	32 cc 63 g	30 J	Monthly Quarterly Semiannual	4.4 6.8 7.9	4.7 7.4 8.7	4.9 7.9 9.5	5.0 8.1 9.8	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 19-second charge time
D154VRC	EnTrust	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 19-second charge time

^{*} Volume and mass differ by connector style.

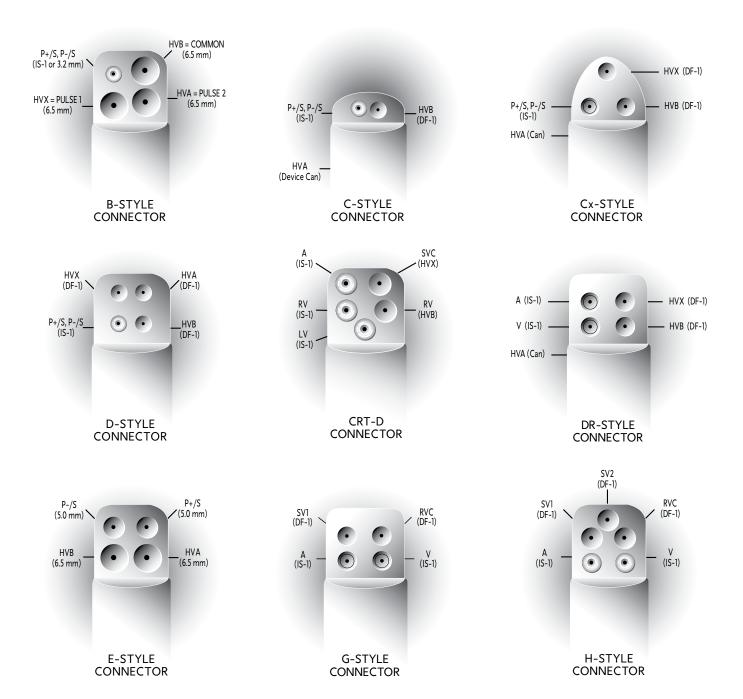
 $[\]ensuremath{^{\star\star}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

 $[\]star\star\star$ The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel.



ICD Connector Styles



Adapta DR ADDR01, ADDR03, ADDR06, ADD01

Product Characteristics

US Marke			Jul-06		nctions			0	NBD Co				R, DDI
Registere	d US Implar	nts	30,000	Ther	apy Function	Not Compromise	ed	0	Serial N	umber Pref	ix		, PWD
Estimated	Active US	Implants	29,000	Ther	apy Function	Compromised		0				PWC	
Normal Ba	attery Depl	etions	0)					Estimate	ed Longevi	ty	See	age 7
Advisories	s		None										
100													
90													
80													
00													
0	1	2	2 3		4	5 6		1 7	8	I 3	9	10	
I	1	2	2 3		4	5 6	,	7	8	3	9	10	
0	1 ears After	Implant		uding Norr	4 mal Battery [Incli	1 7 Iding		Battery D		10	
0	1	Implant at 9 mo		uding Norr	nal Battery [Inclu	1 7 Iding				10	
0				uding Norr	mal Battery C		Inclu	1 7 uding				10	
Ye		at 9 mo		uding Norr	mal Battery [Inclu	7 nding				10	

Adapta DR ADDRL1

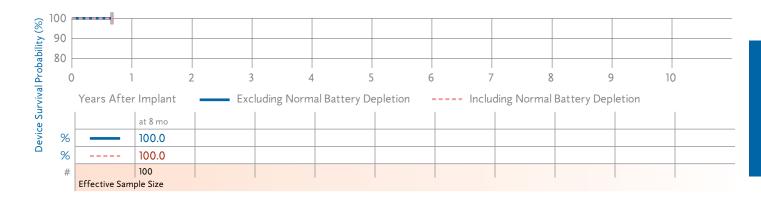
US N	Market Release		Jul-06	Malfun	ctions			0	NBG Co	ode		SSIR
Regi	stered US Impla	ants	1,000	Thera	py Function N	lot Comprom	ised	0	Serial N	lumber Prefix	ĸ	PWM, PWP,
Estir	nated Active U	S Implants	1,000	Thera	py Function (Compromised		0				PWN
Norr	mal Battery Dep	oletions	0						Estimat	ed Longevity	1	See page 78
Advi	isories		None									
<u>@</u> 100							T			I		
	,											
Survival Probability												
Prob			3		,	 - ,						10
vall	0 1			4			5	/	8		9	10
nrv	Years Afte	r Implant	Excludi	ng Norm	al Battery D	epletion	Inc	uding	g Normal	Battery De	pletion	
e o		at 6 mo										
Device	6	100.0										
9	6	100.0										
:	#	200										
	Effective Sam	iple Size										



Adapta DR ADDRS1

Product Characteristics

US Market Release	Jul-06	Malfunctions	0	NBG Code	SSIR
Registered US Implants	3,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWM, PWP,
Estimated Active US Implants	2,000	Therapy Function Compromised	0		PWN
Normal Battery Depletions	0			Estimated Longevity	See page 78
Advisories	None				



Adapta SR ADSR01, ADSR03, ADSR06

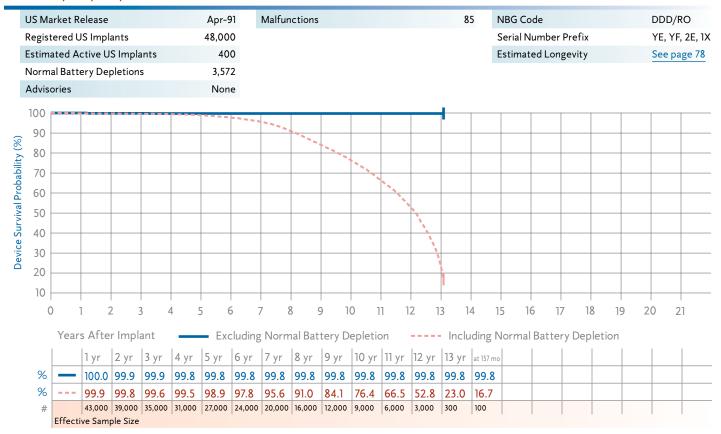
Jan 199		• .,								
US Ma	arket Release		Jul-06	Malfunctions		C	NBG C	ode	SSIR	
Regist	tered US Impl	ants	6,000	Therapy Funct	ion Not Compromis	ed (Serial I	Number Prefix	PWM,	PWI
Estima	ated Active U	S Implants	6,000	Therapy Funct	ion Compromised	C)		PWN	
Norm	al Battery Dep	oletions	0				Estima	ted Longevity	See pa	age 7
Adviso	ories		None							
100 f										
90										
90										
80										
C)	1 2	3	4	5 6	7		8 9	10	
	Years Afte	r Implant	Excludi	ng Normal Batte	ry Depletion -	Inclu	ding Norma	l Battery Depl	etion	
80 80 %		at 8 mo								
%		100.0								
%		100.0								
#		300								
	Effective Sam	ple Size								

AT500 AT501, 7253 Product Characteristics

UCAL LAD L	14 02	NA 16		-	NIDG C. I	2222
US Market Release	Mar-03	Malfunctions		7	NBG Code	DDDRP
Registered US Implants	11,000		n Not Compromi		Serial Number Pref	,
Estimated Active US Implan	nts 7,000	Electrical Cor	•	2	Estimated Longevit	See page 7
Normal Battery Depletions	140	Possible Early	Battery Depletion	on 1		
Advisories	None	Therapy Functio	n Compromised	4		
		Electrical Cor	mponent	3		
		Electrical Inte	erconnect	1		
100						
100 90 80 70 60 50 40			•			
80						
70		1				
60						
50			H			
40						
40						
0 1	2 3	4	5 6	7	8	9 10
Years After Implan	nt Exclu	iding Normal Battery	Depletion -	Includi	ng Normal Battery De	epletion
1 yr	2 yr	3 yr 4 yr	5 yr	at 62 mo		
% 100.0	100.0	100.0 99.7	99.7	99.7		
% 99.9	99.9	99.7 97.0	61.1	53.7		
# 10,000	9,000	5,000 1,000	200	100		

Elite 7074, 7075, 7076, 7077

Effective Sample Size

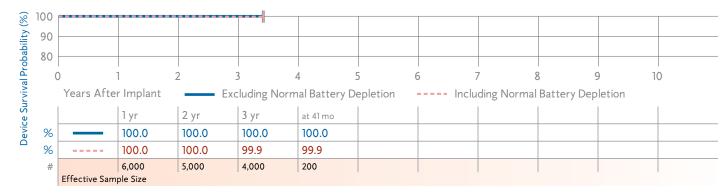




EnPulse DR EIDR01, EIDR03, EIDR06

Product Characteristics

US Market Release	Dec-03	Malfunctions	1	NBG Code	DDDR
Registered US Implants	7,000	Therapy Function Not Compromised	1	Serial Number Prefix	PRA
Estimated Active US Implants	5,000	Electrical Component	1	Estimated Longevity	See page 78
Normal Battery Depletions	2	Therapy Function Compromised	0		
Advisories	None				



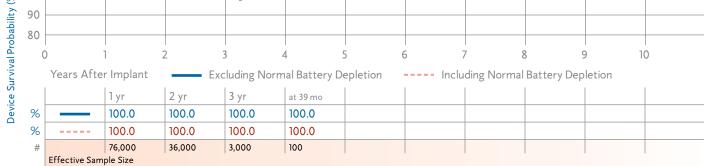
EnPulse DR EIDR21 **Product Characteristics**

US Ma	arket Release		Dec-0	03 Ma	lfunctions			0	NBG Co	de		DDDR	
Regist	tered US Impla	ants	2,00	00 Tł	erapy Function	Not Compron	ised	0	Serial N	umber Prefi	×	PPT	
Estima	ated Active US	S Implants	1,00	00 Tł	erapy Function	Compromised		0	Estimat	ed Longevit	у	See pag	ge 78
Norm	al Battery Dep	oletions		1									
Advis	ories		Nor	ne									
100													
80													
)	 	2	3	4	5	6	7	8	3	9	10	
	Years After	r Implant	Ev	cluding Na	ormal Battery D			ludina	. Normal	Battery De	nletion		
	l cars Arter	,	1	1	I larbattery L	repletion	1	ıuuii iş	3 INOITHAI	Dartery De	Pietion	1	
ָ ט		1 yr	2 yr	3 yr	at 40 mo								
%		100.0	100.0	100.0	100.0								
د %		100.0	100.0	99.8	99.8								
#		2,000	1,000	1,000	100								
	Effective Samp	ple Size											

EnPulse 2 DR E2DR01, E2DR03, E2DR06

Product Characteristics

US Market Release	Feb-04	Malfunctions	6	NBG Code	DDDR
Registered US Implants	100,000	Therapy Function Not Compromised	3	Serial Number Prefix	PNB, PNC,
Estimated Active US Implants	82,000	Electrical Component	3		PNH
Normal Battery Depletions	2	Therapy Function Compromised	3	Estimated Longevity	See page 78
Advisories	None	Battery	1		
		Electrical Component	2		
§ 100					
obability 80					



EnPulse 2 DR E2DR21

rket Release		Feb-04	Malfun	ctions			0	NBG Co	de		DDDR
ered US Impla	nts	12,000) Thera	py Function N	lot Comprom	ised	0	Serial N	umber Prefix	x	PMU
ted Active US	5 Implants	10,000	Thera	py Function C	Compromised		0	Estimat	ed Longevity	/	See page 7
l Battery Dep	letions	7	7								
ries		None	•								
				I					1		
							1				
I		2 3	4	1 :		6	/	3	3	9	10
Years After	Implant	Exc	luding Norm	al Battery D	epletion	Incl	uding	g Normal	Battery De	pletion	
	1 yr	2 yr	3 yr								
	100.0	100.0	100.0								
	100.0	99.8	99.8								
	9,000	4,000	100			_	_				
1	ered US Implated Active US I Battery Depries	reed US Implants ted Active US Implants I Battery Depletions ries 1 Years After Implant 1 yr 100.0	1 2 3 1 2 3 2 3 2 3 3 3 3 3	Thera 12,000 Thera 12,000 Thera 10,000 Thera 10,000 Thera 1 10,000 Thera 1 1 2 3 2 3 4 4 4 4 4 4 4 4 4	Pered US Implants 12,000 Therapy Function Noted Active US Implants 10,000 Therapy Function Of Therapy Func	Therapy Function Not Comprom Therapy Function Not Comprom Therapy Function Compromised I Battery Depletions 7 ries None 1 2 3 4 5 Years After Implant Excluding Normal Battery Depletion 1 yr 2 yr 3 yr 100.0 100.0 100.0	Pered US Implants 12,000 Therapy Function Not Compromised ted Active US Implants 10,000 Therapy Function Compromised I Battery Depletions 7 None 1 2 3 4 5 6 Years After Implant Excluding Normal Battery Depletion Incl 1 yr 2 yr 3 yr 100.0 100.0 100.0 100.0	Therapy Function Not Compromised 0 12,000 Therapy Function Compromised 0 0 18 10,000 Therapy Function Compromised 0 18 10,000 18 10,000 18 10,000 18 10,000 19 10,000 100,00 10	Pered US Implants 12,000 Therapy Function Not Compromised 0 Serial Noted Active US Implants 10,000 Therapy Function Compromised 0 Estimated Active US Implants 7 None None None None None None None None	Therapy Function Not Compromised 0 Serial Number Prefix ted Active US Implants 10,000 Therapy Function Compromised 0 Estimated Longevity I Battery Depletions 7 None	Therapy Function Not Compromised 0 Serial Number Prefix Therapy Function Compromised 0 Estimated Longevity Therapy Function Compromised 0 Estimated Longevity Therapy Function Compromised 0 Facility Estimated Longevity Therapy Function Not Compromised 0 Facility Therapy Function Not Compromised 0 Facility Estimated Longevity Therapy Function Not Compromised 0 Facility Therapy Function Not Compromised 0 Facility Estimated Longevity Therapy Function Not Compromised 1 Facility Th



EnPulse 2 DR E2DR31, E2DR33

Product Characteristics

US Market Releas	se	Feb-04	1 Malfu	nctions			0	NBG Co	de		DDDR
Registered US Im	plants	1,000) Ther	apy Function	Not Compro	mised	0	Serial N	umber Prefix		PNL
Estimated Active	US Implants	1,000) Ther	apy Function	Compromise	ed	0	Estimate	ed Longevity		See page 7
Normal Battery D	Pepletions	()								
Advisories		None	•								
100											
90											
80											
90	1	2 3		1	5	6	7	8		9	10
•	ter Implant	2	,	nal Battery I	Depletion	_	, ncludinį		, Battery Dep		10
	1 yr	2 yr	at 25 mo								
%	100.0	100.0	100.0								
%	100.0	100.0	100.0								

EnPulse 2 SR E2SR01, E2SR03, E2SR06

400

Effective Sample Size

100

100

IIS M	arket Release		Dec-	O3 Mal	functions			3	NBG Code		SSIR
	tered US Impl		25,0		erapy Function	Not Compro	misad	2	Serial Number Prefi	v	PMW, PMY
					• •	•	illiseu	2	Serial Number Frem	X	PNA
	ated Active U		19,0		Electrical Com	•		,	F		6 7
	al Battery De	pletions		3	Possible Early I	, ,		I	Estimated Longevity	У	See page 7
Adviso	ories		No	ne Th	erapy Function	Compromise	d	1			
					Other			1			
90 80 %		1	2	2		5	6	7	8	9	10
5	Years Afte		E:	cluding No	ormal Battery [ncludin	g Normal Battery De		1
i ر		1 yr	2 yr	3 yr	at 40 mo						
%		100.0	100.0	100.0	100.0						
%		100.0	99.9	99.8	99.8						
#		17,000	7,000	1,000	100						
	Effective Sample Size										

EnPulse 2 VDD E2VDD01

Product Characteristics

0.10									110000	t Characte	1150105	
US Ma	ırket Release		Dec-0	3 Malfun	ictions			0	NBG Co	de		VDD
Regist	ered US Impl	ants	1,000) Thera	py Function I	Not Comprom	ised	0	Serial N	umber Prefi	x	PMV
Estima	ated Active U	S Implants	1,000) Thera	py Function (Compromised		0	Estimat	ed Longevity	y	See page 7
Norma	al Battery De	pletions	0									
Adviso	ories		None	e								
100							1			I		
90												
20												
80												
0)	1	2 3	3	4	5	5	7	8	3	9	10
	Years Afte	r Implant	— Exc	luding Norm	nal Battery D	epletion	Inc	luding	g Normal	Battery De	pletion	
90 80 0		1 yr	2 yr	at 28 mo								
%		100.0	100.0	100.0								
%		100.0	100.0	100.0								
#		400	200	100								
	Effective Sam	ple Size										

EnRhythm DR P1501DR

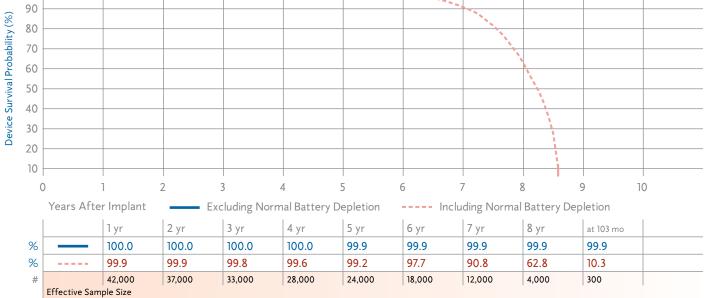
Release	May-0)5 Maltu	nctions			13	NBG Co	de		DDDRP
US Implants	56,00	0 Ther	apy Function	Not Comp	oromised	2	Serial N	umber Pref	ix	PNP
Active US Implants	50,00	00 E	Electrical Component			2	Estimate	ed Longevit	у	See page 78
ttery Depletions		0 Ther	Therapy Function Compromised		11					
Advisories None Electrical Component		11								
i	2	3	4	5	6	7	8		9	10
		cluding Norr	nal Battery	Depletion		Including	g Normal	Battery De	epletion	ı
		at 25 mo								
100.0	100.0	100.0								
100.0	99.9	99.9								
28,000 ective Sample Size	1,000	200								
	ars After Implant 1 yr 100.0 28,000	US Implants 56,00 Active US Implants 50,00 ttery Depletions Nor 1	Sus Implants 56,000 There	Sus Implants 56,000 Therapy Function	Active US Implants 56,000 Electrical Component Therapy Function Not Component Therapy Function Component Therapy Function Component Therapy Function Component Electrical Component Electrical Component Therapy Function Component Therapy Function Component Therapy Function Component Electrical Component Electrical Component Electrical Component Therapy Function Component Therapy Function Not Component	Active US Implants 56,000 Electrical Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Compromised Electrical Component Therapy Function Not Component T	Sustant Sust	Serial Not	US Implants 56,000 Therapy Function Not Compromised 2 Serial Number Prefix	Sus Implants 56,000 Electrical Component 2 Estimated Longevity



Kappa 400 DR KDR401, KDR403

Product Characteristics

\a	ppa 400 DK KDK401, KD	K4U3			Product Characteristics	
	US Market Release	Jan-98	Malfunctions	21	NBG Code	DDD/RO
	Registered US Implants	47,000	Therapy Function Not Compromised	12	Serial Number Prefix	PER, PET
	Estimated Active US Implants	10,000	Electrical Component	9	Estimated Longevity	See page 78
	Normal Battery Depletions	2,767	Electrical Interconnect	1		
	Advisories	None	Possible Early Battery Depletion	2		
			Therapy Function Compromised	9		
			Electrical Component	7		
			Electrical Interconnect	2		
	100					
	90				'	
8						
>	80				7.	



Kappa 400 SR KSR401, KSR403

pu iso oit in	.,									
US Market Release		Feb-	98 Mal	functions			4 NBC	G Code		SSI/R
Registered US Implants		15,0	15,000 Therapy Function Not Compromised		mised	3 Seri	ial Number Pre	al Number Prefix		
Estimated Active U	S Implants	4,0	00	Electrical Co	mponent		3 Estimated Longevity		ity	See page
Normal Battery Dep	pletions	3	83 Th	erapy Functio	on Compromise	ed	1			
Advisories		No	ne	Electrical Int	erconnect		1			
100									-	
90										
80								1		
70										
60										
50										
30										
0	1	2	3	4	5	6	7	8	9	10
Years Afte	r Implant	Ex	cluding No	ormal Battery	/ Depletion	Ir	cluding Nor	mal Battery D	Depletion	
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	
%	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
%	99.9	99.9	99.8	99.6	99.4	98.6	95.2	77.8	53.0	
#	13,000	11,000	9,000	8,000	6,000	4,000	3,000	1,000	100	
Effective Sam	ple Size									

Kappa 600 DR KDR601, KDR603, KDR606

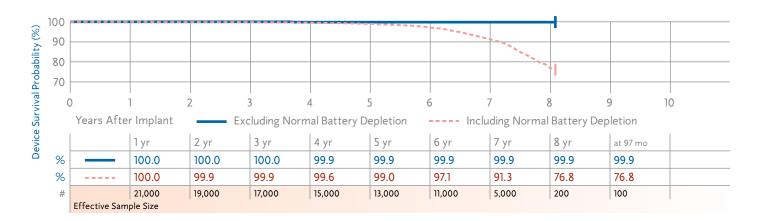
US Market Release	Jan-99
Registered US Implants	24,000
Estimated Active US Implants	8,000
Normal Battery Depletions	536
Advisories Con page 162 2002 Dates	امند

Advisories: See page 162 – 2002 Potential Fractured Power Supply Wires

Malfunctions	20
Therapy Function Not Compromised	3
Electrical Component	3
Therapy Function Compromised	17
Electrical Component	2
Electrical Interconnect (11 malfunctions related to advisory)	15

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PHF, PHH, PHG
Estimated Longevity	See page 79

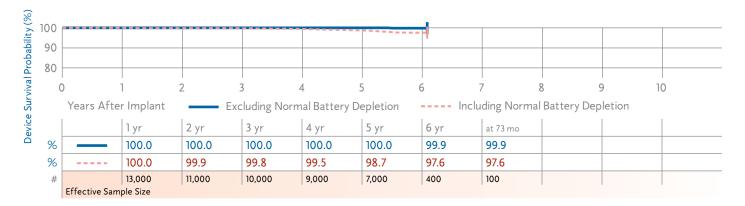


Kappa 600 DR KDR651, KDR653

US Market Release	Mar-01
Registered US Implants	14,000
Estimated Active US Implants	7,000
Normal Battery Depletions	75
Advisories: See page 162 – 2002 Fractured Power Supply Wires	Potential

Malfunctions	4
Therapy Function Not Compromised	2
Electrical Component	1
Possible Early Battery Depletion	1
Therapy Function Compromised	2
Electrical Component	1
Electrical Interconnect (1 malfunction related to advisory)	1

NBG Code	DDD/RO
Serial Number Prefix	PLJ, PLK
Estimated Longevity	See page 79





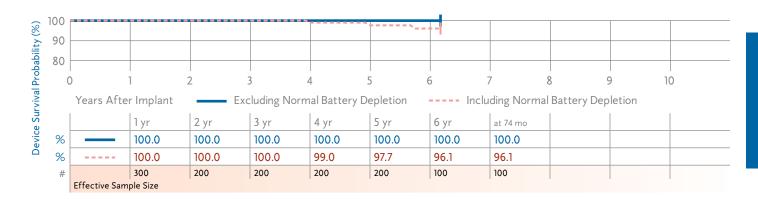
Kappa 700 D KD701, KD703, KD706

Fractured Power Supply Wires

US Market Release	Jan-99
Registered US Implants	300
Estimated Active US Implants	100
Normal Battery Depletions	4
Advisories: See page 162 – 2002 Potenti	al

Product Characteristics

Malfunctions	0	NBG Code	DDD
Therapy Function Not Compromised	0	Serial Number Prefix	PHK
Therapy Function Compromised	0	Estimated Longevity	See page 79



Kappa 700 DR KDR701, KDR703, KDR706

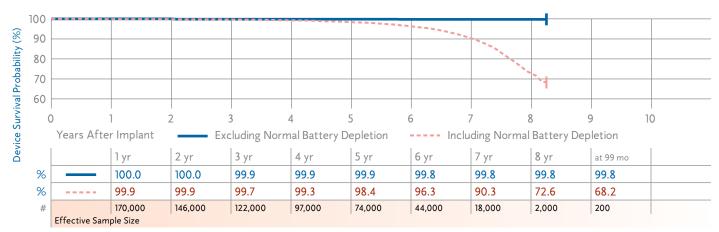
US Market Release	Feb-99		
Registered US Implants	192,000		
Estimated Active US Implants	94,000		
Normal Battery Depletions	2,818		
Advisories: See page 162 – 2002 Potential			

Fractured Power Supply Wires

Malfunctions	199
Therapy Function Not Compromised	27
Battery	1
Electrical Component	20
Electrical Interconnect	3
Possible Early Battery Depletion	3
Therapy Function Compromised	172
Electrical Component	14
Electrical Interconnect	158

(117 malfunctions related to advisory)

/RO
PGY,
age 79



Kappa 700 DR KDR721

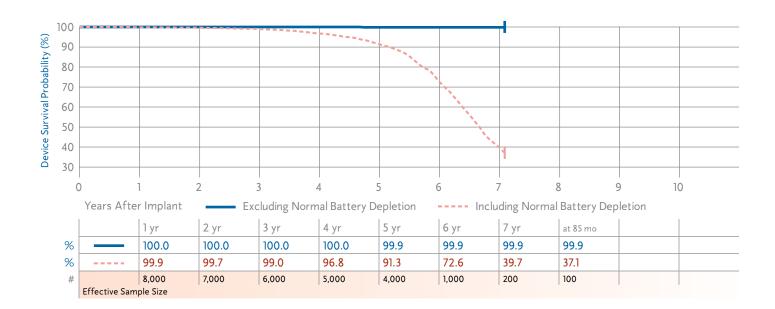
US Market Release	Feb-99
Registered US Implants	10,000
Estimated Active US Implants	2,000
Normal Battery Depletions	698

Advisories: See page 162 – 2002 Potential Fractured Power Supply Wires

Malfunctions 5 Therapy Function Not Compromised 1 **Electrical Component** 1 **Therapy Function Compromised** 4 Electrical Interconnect (4 malfunctions related to advisorγ)

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PGR
Estimated Longevity	See page 79



Kappa 700 SR KSR701, KSR703, KSR706

pa 700 SK KSK701,1	(3K/03, K3K/00					FIC	ouct Charact	teristics	
US Market Release	Feb-	99 Mal	functions			9 NB	G Code		SSI/R
Registered US Implants	55,00	00 Th	erapy Functio	n Not Compr	omised	3 Ser	ial Number Pre	fix	PHT, PHW,
Estimated Active US Impla	nts 22,00	00	Electrical Cor	nponent		2			PHU
Normal Battery Depletions	7.	24	Possible Early	Battery Dep	letion	1 Est	imated Longev	ity	See page
Advisories	No	ne Th	erapy Functio	n Compromis	ed	6			
			Electrical Cor	nponent		4			
			Electrical Inte	erconnect		2			
100									
90 80 70 60 0 1 Years After Impla						= _	•		
90									
80							` .		
70									
60									
0 1	2	3	4	5	6	7	8	9	10
Years After Impla	nt — Ex	cluding No	rmal Battery	Depletion	In	icluding Nor	mal Battery D	Depletion	
1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 98 mo	
% 100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
% 99.9	99.9	99.6	99.0	97.7	95.3	89.1	72.0	70.2	
# 44,000	35,000	28,000	22,000	16,000	9,000	4,000	300	100	
Effective Sample Size									



Kappa 700 VDD KVDD701

Registered US Implants

Estimated Active US Implants

Fractured Power Supply Wires

Advisories: See page 162 – 2002 Potential

Normal Battery Depletions

US Market Release

Jan-99 2,000 1,000 51

Malfunctions	
Therapy Function Not Compromised	
Therapy Function Compromised	
Electrical Interconnect (3 malfunctions related to advisory)	

3

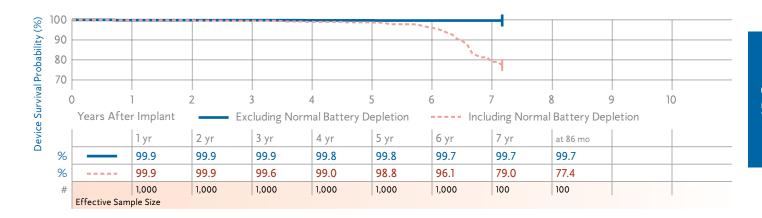
0

3

3

Product Characteristics NBG Code VDD/RO PHP Serial Number Prefix

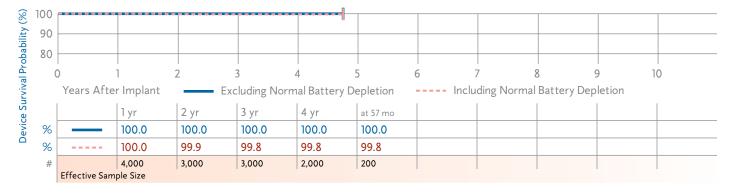
Estimated Longevity See page 79



Kappa 800 DR KDR801, KDR803

US Market Release	Jan-02
Registered US Implants	4,000
Estimated Active US Implants	3,000
Normal Battery Depletions	3
Advisories	None

Malfunctions	0	NBG Code	DDD/RO
Therapy Function Not Compromised	0	Serial Number Prefix	PKW, PKY
Therapy Function Compromised	0	Estimated Longevity	See page 79



Kappa 900 DR KDR901, KDR903, KDR906

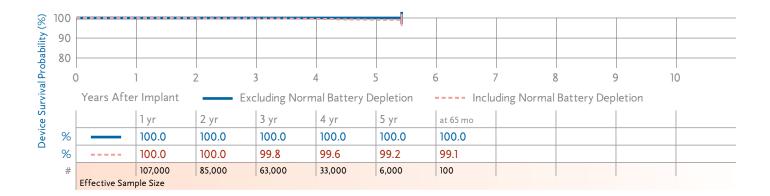
US Market Release Registered US Implants **Estimated Active US Implants** Normal Battery Depletions

Advisories

Jan-02	Malfunctions	20
125,000	Therapy Function Not Compromised	10
86,000	Electrical Component	10
141	Therapy Function Compromised	10
None	Electrical Component	7
	Electrical Interconnect	3

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PKM, PKN, PKP
Estimated Longevity	See page 79

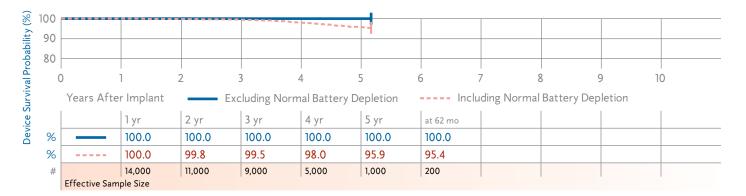


Kappa 920 DR KDR921

US Market Release Jan-02 Registered US Implants 16,000 **Estimated Active US Implants** 10,000 Normal Battery Depletions 99 Advisories None

Malfunctions			
Therapy Function	on Not Compro	mised	
Therapy Function Compromised			
Electrical Int	terconnect		

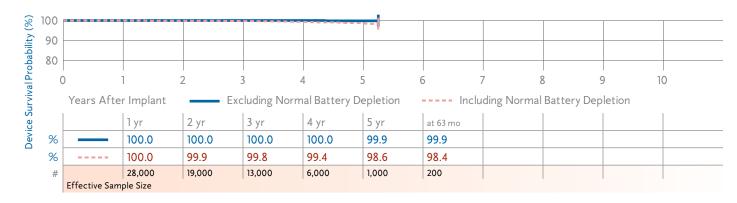
1	NBG Code	DDD/RO
0	Serial Number Prefix	PKR
1	Estimated Longevity	See page 79
1		





Kappa 900 SR KSR901, KSR903, KSR906

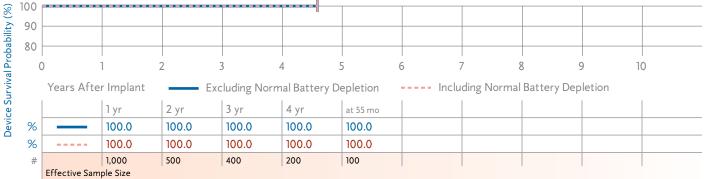
US Market Release	Jan-02	Malfunctions	9	NBG Code	VVEV
Registered US Implants	37,000	Therapy Function Not Compromised	7	Serial Number Prefix	PLF, PLG,
Estimated Active US Implants	22,000	Electrical Component	7		PLH
Normal Battery Depletions	45	Therapy Function Compromised	2	Estimated Longevity	See page 79
Advisories	None	Electrical Interconnect	2		



Kappa 900 VDD KVDD901

Product Characteristics

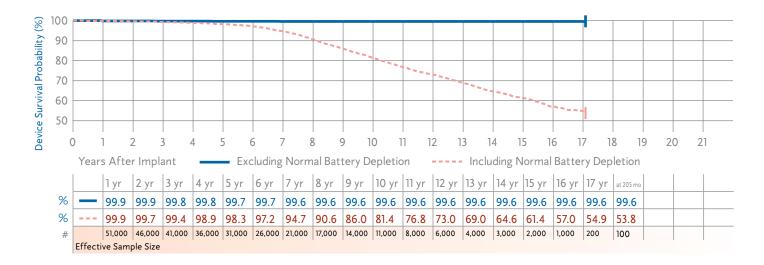
pp					
US Market Release	Jan-02	Malfunctions	0	NBG Code	VDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PLE
Estimated Active US Implants	400	Therapy Function Compromised	0	Estimated Longevity	See page 79
Normal Battery Depletions	0				
Advisories	None				
- 100					



Legend 8416, 8417, 8417M, 8418, 8419

Product Characteristics

US Market Release	Aug-89	Malfunctions	143	NBG Code	SSIRO
Registered US Implants	57,000			Serial Number Prefix	XT, WJ, WN,
Estimated Active US Implants	3,000				ZT
Normal Battery Depletions	2,645			Estimated Longevity	See page 79
Advisories	None				



Legend II 8424, 8426, 8427

Product Characteristics

US M	arket R	elease				Nov-9	91	Malfun	ctions					36	5 1	NBG Co	de				SSII	RO
Regis	tered U	IS Impl	ants			59,00	0								9	Serial N	umber	Prefix			2P,	2T, 2U
Estim	ated A	ctive U	S Impla	ants		6,00	0								E	stimat	ed Lon	gevity			See	page 79
Norm	al Batte	ery De	pletion	s		1,77	4															
Advis	ories					Non	e															
100									I	ı									I			
80																						
70																						
70																1						
60																						
(ο .	1 2	2 3	3 4	4 5	5 6	5 7	7 8	3 9) 10	0 1	1 1:	2 1:	3 14	4 1	5 1	5 17	7 1	8	19	20	21
90 80 70 60	Year	s Afte	r Impl	ant		— Ехс	luding	Norm	al Bat	tery D	epletic	n		Inclu	ding N	Iormal	Batte	ry Dep	letio	n		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 vr	15 vr	at 183 mo					
%		100.0				99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9					
%		99.9	99.7	99.5	99.2	98.8	98.1	97.2	i e	91.9	89.2		83.1	79.4	74.8	70.5	69.9					
#			46,000									10,000		5,000	2,000	400	100					

Effective Sample Size

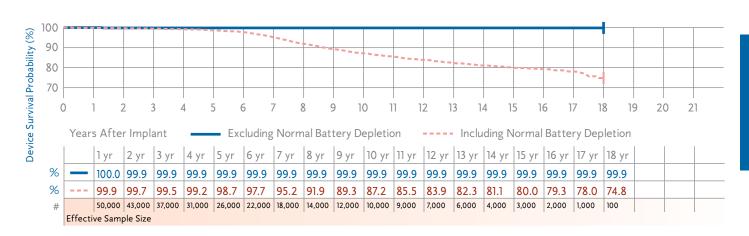


Minix/Minix ST 8330, 8331, 8331M, 8340, 8341, 8341M, 8342

Product Characteristics

US Market Release	Dec-89	Malfunctions	49	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	5,000			Estimated Longevity	See page 79
Normal Battery Depletions	1,473				

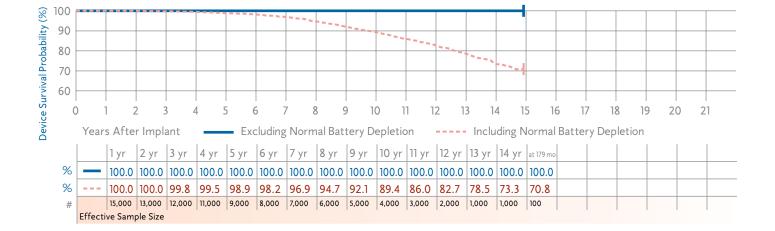
Advisories: See page 167 – 1991 Potential Delayed Restoration of Permanent Settings



Minuet 7107, 7108 **Product Characteristics**

None

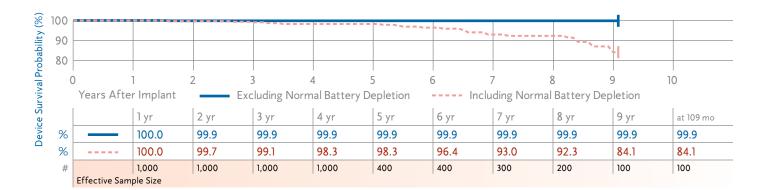
US Market Release	Mar-92	Malfunctions	4	NBG Code	DDDCO
Registered US Implants	17,000			Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	2,000			Estimated Longevity	See page 79
Normal Battery Depletions	582				



Advisories

Preva D 7068 **Product Characteristics**

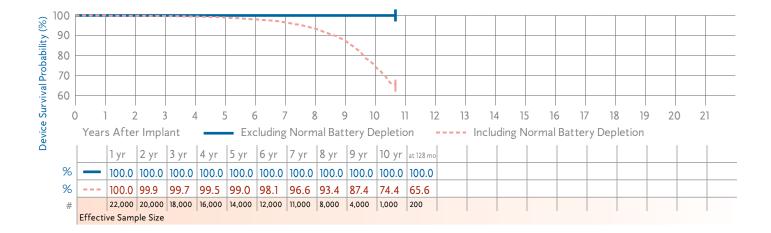
US Market Release	Nov-96	Malfunctions	1	NBG Code	DDI
Registered US Implants	1,000			Serial Number Prefix	PIE
Estimated Active US Implants	200			Estimated Longevity	See
Normal Battery Depletions	24				
Advisories	None				



Preva DR 7088, 7089 **Product Characteristics**

None

US Market Release	Jul-96	Malfunctions	3	NBG Code	DDD/RO
Registered US Implants	26,000			Serial Number Prefix	PGJ, PGK
Estimated Active US Implants	6,000			Estimated Longevity	See page 80
Normal Battery Depletions	797				



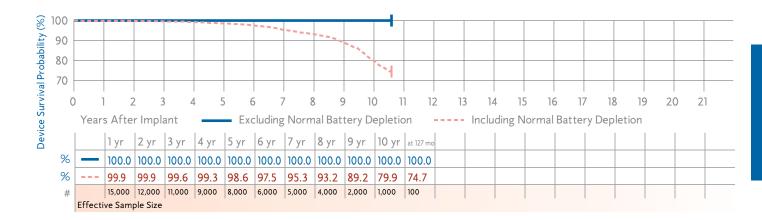
Advisories



Preva SR 8088, 8089

Product Characteristics

US Market Release	Jul-96	Malfunctions	1	NBG Code	SSI/R
Registered US Implants	18,000			Serial Number Prefix	PGL, PC
Estimated Active US Implants	3,000			Estimated Longevity	See pag
Normal Battery Depletions	347				
Advisories	None				

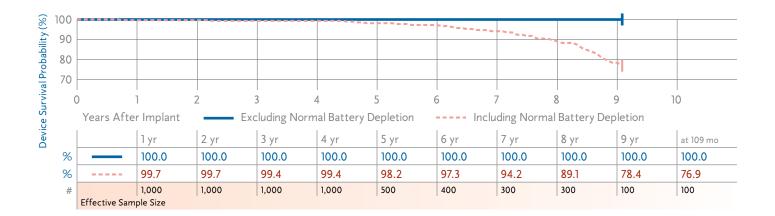


Preva ST DR 7078

Advisories

Product Characteristics

US Market Release	Nov-96	Malfunctions	0	NBG Code	DDD/RO
Registered US Implants	1,000			Serial Number Prefix	PIF
Estimated Active US Implants	100			Estimated Longevity	See page 80
Normal Battery Depletions	39				



None

3,000 3,000 2,000 2,000 1,000 1,000

99.8 99.8 99.2 99.1

Prevail S 8085, 8086

%

99.9

Effective Sample Size

Product Characteristics

US Ma	arket R	elease				Oct-9	5	Malfun	ctions						1	NBG C	ode					SSI	
Regist	tered U	S Impl	ants			4,000)									Serial N	lumbe	r Pre	efix			PGL	., PGM
Estima	ated A	ctive U	S Impla	nts		1,000)									Estima	ed Lo	ngev	ity			See	page 8
Norm	al Batte	ery Dep	oletions	5		20)																
Adviso	ories					None	e																
100																							
90																						<u> </u>	
80																							
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		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 125 mo											
%	_	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9											

95.1

98.5 97.5 96.3 95.1

1,000 1,000 1,000 200

Prodigy D 7864, 7865, 7866

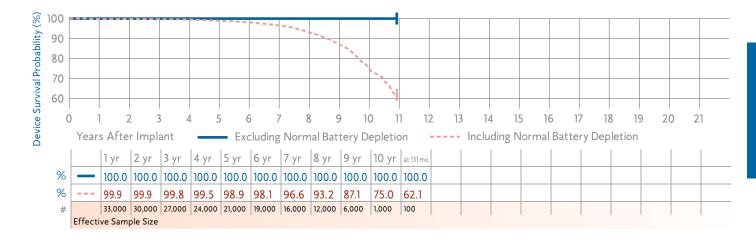
US Ma	rket R	elease				Oct-9	5	Malfun	ctions						0	NB	G Cod	de						DDDO	CO
Regist	ered U	S Impl	ants			3,00	0									Ser	ial Nu	ımbei	r Pre	efix					PDM,
Estima	ated A	tive U	S Impla	nts		1,00	0																	PDN	
Norma	al Batte	ery Dep	oletions	S		7	6									Estimated Longevity				See p	age 8				
Adviso	ories					Non	e																		
100																									
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20										7															
80											1														
90 - 80 - 70 -																									
0	1	2	2 3	3 4	. 5	6	5 7	8	9) [0 1	1 12	2 1	3 1	4	15	16	1	7	18		19	20) 2	21
	Years	s Afte	r Impla	ant		E xc	luding	Norm	al Bat	tery D	epletio	on		Incl	uding	, Nor	mall	Batte	ery [Depl	etio	n			
		1 yr	2 yr	3 vr	4 yr	5 yr	6 yr	7 vr	8 yr	9 yr	10 vr	at 127 mc													
%		100.0	100.0	100.0	/		100.0		100.0		i e	100.0													
%		99.9	99.7	99.4			97.8	97.1	96.0	91.1	82.3	76.8			+				+	_		+			
#						2,000	1,000	1,000	1,000	1,000	300	100													
	Effecti	ve Sami	1	_,	_,_,	_,_,	,,,,,,,,	.,	,,,,,,,	.,	1	1		1			-		1			1	-		1



Prodigy DR 7860, 7861, 7862

Product Characteristics

US Market Release	Oct-95	Malfunctions	11	NBG Code	DDD/RO
Registered US Implants	38,000			Serial Number Prefix	PDH, PDJ,
Estimated Active US Implants	9,000				PDK
Normal Battery Depletions	1,127			Estimated Longevity	See page 8
Advisories	None				



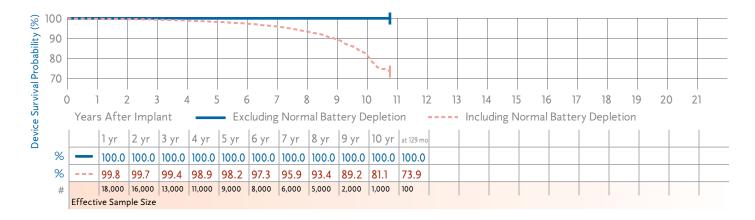
Prodigy S 8164, 8165, 8166

US Ma	ırket R	elease				Oct-9	5	Malfun	ctions					0		NBG Co	ode					SSIC	
Regist	ered U	S Impla	ants			2,00	0									Serial N	lumber	r Prefix	(PEG, F	PEH,
Estima	ated A	ctive U	S Impla	ants		40	0															PEJ	
Norm	al Batte	ery Dep	oletion	S		2	3									Estimat	ed Lor	ngevity	,			See pa	age 80
Adviso	ories					Non	е																
100											-					1			_				
90											-									_			
90 80																							
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2		I_			L .								l								1		I
ט ט		1 yr	2 yr	3 yr	4 yr	5 yr	,		8 yr	9 yr		at 124 mo								_			
% %		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0											
%		99.9	99.9	99.8	99.2	99.2	99.2	98.9	97.3	94.5	91.4	88.9											
#		2,000	1,000	1,000	1,000	1,000	1,000	1,000	1,000	400	200	100											
	Effecti	ve Samp	ole Size																				

Prodigy SR 8158, 8160, 8161, 8162

Product Characteristics

US Market Release	Oct-95	Malfunctions	5	NBG Code	SS
Registered US Implants	22,000			Serial Number Prefix	PE
Estimated Active US Implants	4,000				PE
Normal Battery Depletions	433			Estimated Longevity	Se
Advisories	None				



Sensia DR SEDR01, SED01

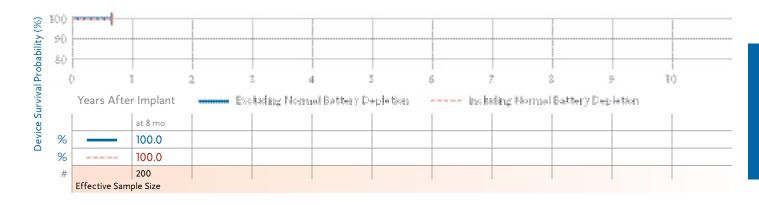
		,										
US Ma	ırket Release		Jul-06	Malfunc	tions			0	NBG Co	de		SSI/R
Regist	ered US Impla	nts	10,000	Therap	y Function N	lot Comprom	ised	0	Serial N	umber Prefix		DDD, DDDR
Estima	ated Active US	S Implants	9,000	Therap	y Function C	ompromised		0 Estimated Longevi		ed Longevity		See page 8
Norma	al Battery Dep	letions	0									
Adviso	ories		None									
100												
ا د	•											
5												
80												
<u>a</u> () 1		2 3	4			6	7	`		9	10
<u>.</u>	Years After	^r Implant	Exclud	ing Norma	Battery De	epletion	Incl	uding	g Normal	Battery Dep	oletion	
ו ל		at 8 mo										
% %		100.0										
%		100.0										
#		300										
	Effective Samp	ole Size										



Sensia SR SESR01, SES01

Product Characteristics

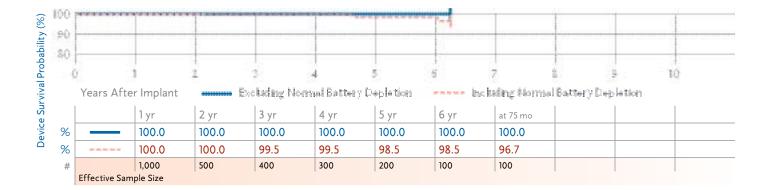
US Market Release	Jul-06	Malfunctions	0	NBG Code	SSIR, SSI
Registered US Implants	6,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWR, PWS
Estimated Active US Implants	6,000	Therapy Function Compromised	0	Estimated Longevity	See page 80
Normal Battery Depletions	0				
Advisories	None				



Sigma 100 S SS103, SS106

Separation of Interconnect Wires

9					
US Market Release	Aug-99	Malfunctions	0	NBG Code	SSI
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJG, PJH
Estimated Active US Implants	200	Therapy Function Compromised	0	Estimated Longevity	See page 80
Normal Battery Depletions	3				
Advisories: See page 160 – 2005 Poten	tial				



Aug-99

16,000

8,000

34

Sigma 200 DR SDR203

Registered US Implants **Estimated Active US Implants**

Normal Battery Depletions

Advisories: See page 160 - 2005 Potential Separation of Interconnect Wires

US Market Release

Malfunctions	4
Therapy Function Not Compromised	1
Electrical Component	1
Therapy Function Compromised	2
Electrical Component	1

2

Electrical Interconnect

(1 malfunction related to advisory)



Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PJD
Estimated Longevity	See page 80

00											
90								•			
30											
)	1	2	2	1	-	6	7	8	9	10
C)	I	_	3	4	5	O	/	0	7	10
	Years Afte	r Implant	E	Excluding No	rmal Battery	Depletion		cluding Norr	o nal Battery D	_	
	Years Afte	r Implant 1 yr	2 yr	Excluding No	rmal Battery 4 yr	Depletion 5 yr		cluding Norr	_	_	10
%	Years Afte	1-	1				In		nal Battery D	_	10
%	Years Afte	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	nal Battery D	_	

Sigma 200 SR SSR203

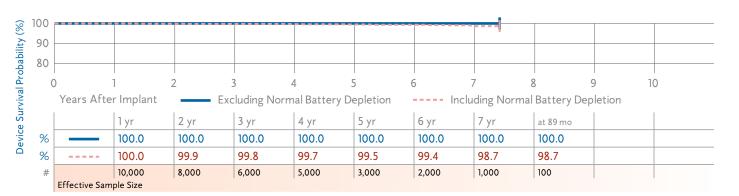
US Market Release	Sep-99
Registered US Implants	12,000
Estimated Active US Implants	5,000
Normal Battery Depletions	17

Advisories: See page 160 - 2005 Potential Separation of Interconnect Wires

Malfunctions	2
Therapy Function Not Compromised	0
Therapy Function Compromised	2
Electrical Interconnect	2

(2 malfunctions related to advisory)

Product Characteristics NBG Code SSI/R Serial Number Prefix PJG **Estimated Longevity** See page 80



Aug-99

104,000

62,000

111



Sigma 300 DR SDR303, SDR306

Estimated Active US Implants

Separation of Interconnect Wires

Advisories: See page 160 - 2005 Potential

Normal Battery Depletions

US Market Release

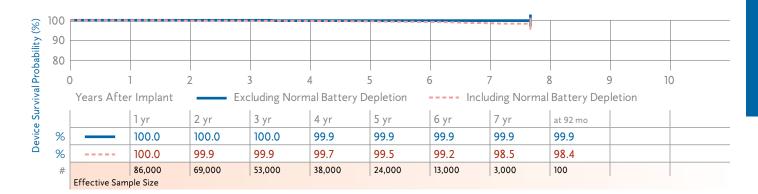
Registered US Implants

Malfunctions 62 Therapy Function Not Compromised 8 **Electrical Component** 4 **Electrical Interconnect** 3 Possible Early Battery Depletion 1 **Therapy Function Compromised** 54 **Electrical Component** 6

48

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PJD, PJE
Estimated Longevity	See page 80



Electrical Interconnect (27 malfunctions related to advisory)

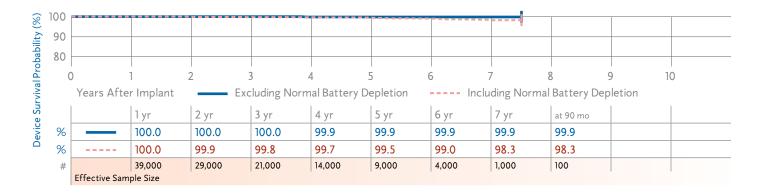
Sigma 300 SR SSR303, SSR306

US Market Release	Sep-99
Registered US Implants	52,000
Estimated Active US Implants	25,000
Normal Battery Depletions	60
Advisories: See page 160 – 2005 Po	otential

Separation of Interconnect Wires

Malfunctions	12
Therapy Function Not Compromised	1
Electrical Component	1
Therapy Function Compromised	11
Electrical Component	3
Electrical Interconnect (5 malfunctions related to advisory)	8

NBG Code	SSI/R
Serial Number Prefix	PJG, PJH
Estimated Longevity	See page 80

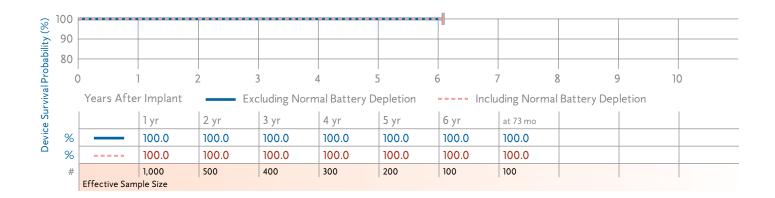


Sigma 300 VDD SVDD303

Separation of Interconnect Wires

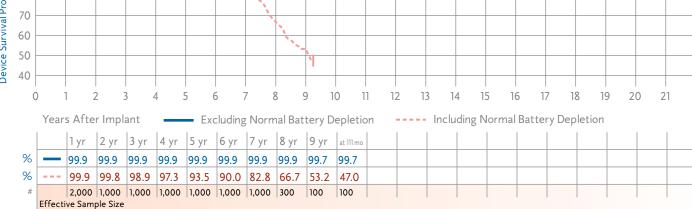
Product Characteristics

US Market Release	Sep-99	Malfunctions	0	NBG Code	VDDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJD
Estimated Active US Implants	300	Therapy Function Compromised	0	Estimated Longevity	See page 80
Normal Battery Depletions	0				
Advisories: See page 160 – 2005 Pe	otential				



Thera D 7944, 7945, 7946

	,,																
US Market Re	lease		Jan-95	Malfu	nctions				2	2	NBG Co	de				DDDC	0
Registered US	Implants		2,000								Serial N	lumber	Prefix			PBD, P	BE,
Estimated Act	tive US Implan	ts	0													PBF	
Normal Battery Depletions			175								Estimat	ed Lon	gevity			See pa	age 8
Advisories			None														
100						_	I							1			
						•											
80																	
70																	
90 80 70 60																	
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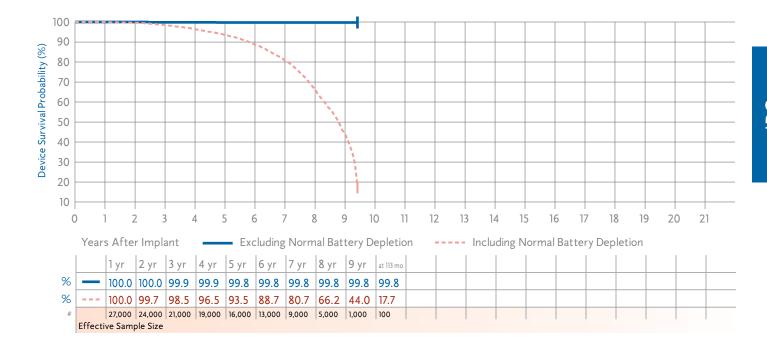




Thera DR-40 7940, 7941, 7942

Product Characteristics

US Market Release	Jan-95	Malfunctions	37	NBG Code	DDD/RO
Registered US Implants	30,000			Serial Number Prefix	PAF, PAP,
Estimated Active US Implants	1				PAT
Normal Battery Depletions	3,027			Estimated Longevity	See page 8
Advisories	None				



Effective Sample Size

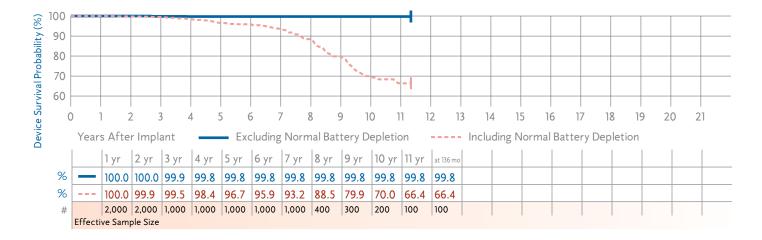
he	ra [)R-5	0 795	0, 795	1, 7952	2											Produ	ict Ch	narac	teris	tics			
L	IS Ma	arket R	elease				Jan-9	5	Malfun	ctions						1	NBG C	ode					DDI	D/RO
R	egist	ered L	JS Impl	ants			5,00	0									Serial	Numb	er Pr	efix				R, PBV,
Е	stim	ated A	ctive U	S Impla	ants		40	0															PBV	V
١	lorm	al Batt	ery Dep	oletion	S		23	6									Estima	ated L	onge	vity			See	page 80
4	dvis	ories					Non	e																
· •	100																							
Device Survival Probability (%)	90																						_	
ap	80											***												
ro D	70											1												
	60																							
our.													Y											
e E	50																						_	
Ų	()	1 2	2	3 4	4 !	5 6	5 7	7 8	3 9	9 1	0 1	1 1	2 1:	3 1	4	15	16	17	18	19)	20	21
		Year	s Afte	r Impl	ant		E xc	luding	Norm	nal Bat	tery D	epletio	on		Inclu	ding	Norma	al Bat	tery	Deple	etion			
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 143 mo							1			
	%		100.0	100.0	100.0	100.0	100.0	100.0	-	1	 '	100.0	100.0	100.0										
	%		i -	100.0	i		99.2			95.9	i	86.6	74.2	i e									\top	
	#						3,000							100										



Thera S 8944, 8945, 8946

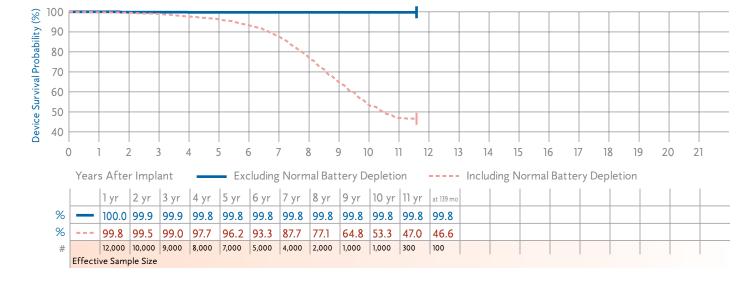
Product Characteristics

US Market Release	Jan-95	Malfunctions	3	NBG Code	SSI/R
Registered US Implants	3,000			Serial Number Prefix	PBG, PE
Estimated Active US Implants	100				PBJ
Normal Battery Depletions	84			Estimated Longevity	See pag
Advisories	None				



Thera SR 8940, 8941, 8942

US Market Release	Jan-95	Malfunctions	16	NBG Code	SSI/R
Registered US Implants	14,000			Serial Number Prefix	PAU, PAV
Estimated Active US Implants	200				PAW
Normal Battery Depletions	818			Estimated Longevity	See page
Advisories	None				

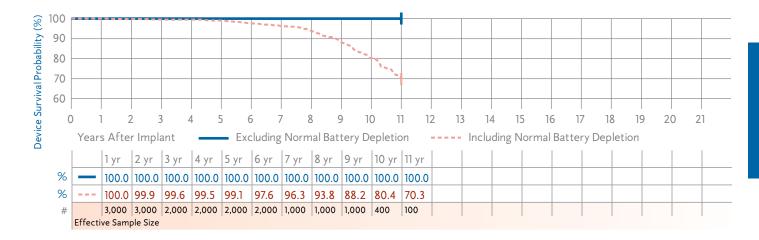




Thera-i D 7964i, 7965i, 7966i

Product Characteristics

US Market Release	Oct-95	Malfunctions	1	NBG Code	DDDCO
Registered US Implants	3,000			Serial Number Prefix	PDE, PDF,
Estimated Active US Implants	1,000				PDG
Normal Battery Depletions	114			Estimated Longevity	See page 8
Advisories	None				



Thera-i DR 7960i, 7961i, 7962i

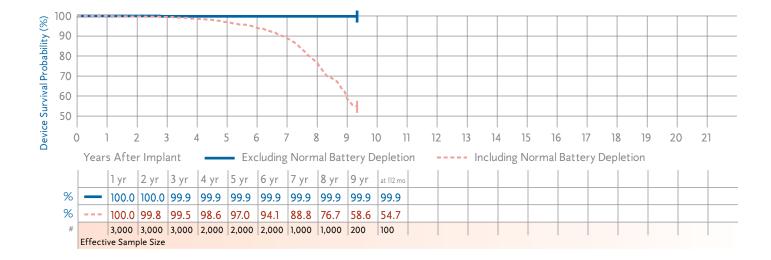
Product Characteristics

US Market Release	Oct-95 Malfunction	ns 5	0 NBG Code	DDD/RO
Registered US Implants	122,000		Serial Number Prefix	PDB, PDC,
Estimated Active US Implants	22,000			PDD
Normal Battery Depletions	5,227		Estimated Longevity	See page 8
Advisories	None			
100				
90		•		
80				
70				
60				
50				
40		1		
		0 10 11 12 12		
	3 0 7 0	9 10 11 12 13 1	14 15 16 17 18 19	20 21
Years After Implant	Excluding Normal I		uding Normal Battery Depletion	
1 yr 2 yr 3 yr 4	yr 5 yr 6 yr 7 yr 8 y	r 9 yr 10 yr 11 yr at 137 mo		
% 100.0 100.0 100.0 10	0.0 100.0 99.9 99.9 99	9 99.9 99.9 99.9 99.9		
	9.5 99.0 98.2 96.6 93			
# 109,000 99,000 89,000 80,	,000 71,000 62,000 53,000 42,	00 26,000 10,000 2,000 100		

Effective Sample Size

Thera-i DR 7968i **Product Characteristics**

US Market Release	Jul-96	Malfunctions	3	NBG Code	DDD/RO
Registered US Implants	4,000			Serial Number Prefix	PGH
Estimated Active US Implants	400			Estimated Longevity	See page 8
Normal Battery Depletions	216				
Advisories	None				



Thera-i S 8964i, 8965i, 8966i

		,	, -																	-			
US Ma	rket R	elease				Oct-9	5	Malfun	ctions					1		NBG Co	de				5	SSIR	
Regist	ered U	IS Impl	ants			4,00	0									Serial N	lumber	Prefix	<			PDY, P	EA,
Estima	ated A	ctive U	S Impla	ants		1,00	0														P	PEB	
Norma	al Batte	ery De	pletion	s		4	5								1	Estimat	ed Lor	gevity	,		5	See pa	ge
Adviso	ories					Non	e																
100 г																							

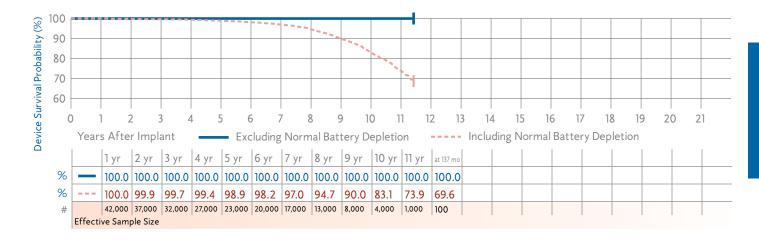
90																							
80																			+	+	_		
0)]	1 2	2 3	3 4	1 5	5 6	5 7	7 8	3 9)[0 1	1 12	2 1:	3 14	1	5 1	6 1	7	18	19	20	2	1
	Voor	ς Λf+ο	r Impl	ont-		Гии	.l ali.a a	Nlawa	al Date	tow.D	منده امد			Inclu	dina N	Jorma	Dotto	ry Do	nloti	0.00			
	rear	SAILE	ı ımpı	arii.		EXC	luding			, ,	,			iriciu	airig i	iorriai	Dalle	ry Del	pieti	OH			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr											
%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0											
%		99.9	99.9	99.8	99.3	98.9	98.2	97.5	96.4	93.5	92.8	88.6											
#		3,000	3,000	2,000	2,000	2,000	1,000	1,000	1,000	1,000	400	100											
	Effecti	ve Samı	ple Size																				



Thera-i SR 8960i, 8961i, 8962i

Product Characteristics

US Market Release	Oct-95	Malfunctions	7	NBG Code
Registered US Implants	50,000			Serial Number Prefix
stimated Active US Implants	8,000			
Normal Battery Depletions	1,133			Estimated Longevity
Advisories	None			



Thera-i VDD 8968i

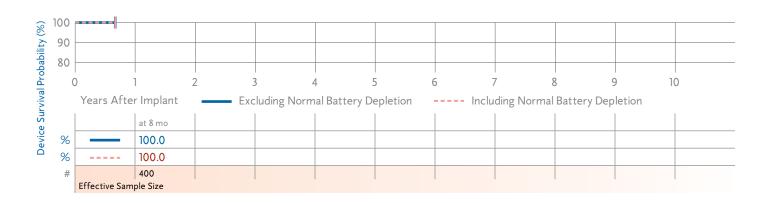
US Ma	arket R	elease				Mar-9	6	Malfun	ctions						0	NBG	Code					V	DD	
Regist	ered U	S Impl	ants			5,000	0									Seria	Num	ber P	refix			Pi	C	
Estima	ated A	ctive U	S Impla	ints		1,000	C									Estim	ated	Longe	evity			S	ee pa	ige 8
Norma	al Batte	ery Dep	oletion	5		6	7																	
Adviso	ories					Non	e																	
100										****											Τ	\top		
90										_	1										+			
80											-1										+	_		_
0) .	1 2	2 3	3 4	1 5	6	7	7 8	3 9)[0 1	1 12	2 13	3 1	4	15	16	17	18		19	20	2	1
	Year	s Afte	r Impla	ant		- Exc	luding	Norm	al Bat	tery D	epletic	n		Inclu	ıding	Norm	al Ba	ttery	Deple	etior	1			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 130 mo												
%		100.0	100.0	100.0	100.0		100.0	100.0	100.0	100.0	100.0	100.0												
%		100.0	99.8	99.6	99.6	99.3	99.2	99.2	98.5	96.9	90.6	83.6												
#				3,000	3,000	3,000	2,000	2,000	2,000	1,000	1,000	100												
	Effecti	ve Sam	ole Size																					

Advisories

Versa DR VEDR01 **Product Characteristics**

None

US Market Release	Jul-06	Malfunctions	0	NBG Code	DDDR
Registered US Implants	11,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWH
Estimated Active US Implants	10,000	Therapy Function Compromised	0	Estimated Longevity	See page 81
Normal Battery Depletions	0				



Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

						Malfunctions	ctions		,	Device	Device Survival Probability (%)	Probab	ility (%)								
kļiu	del mber	Market ease	gistered Implants	bətsmi SU əvi: stnsk	rmal Battery snoiteld	erapy Function mpromised	erapy Iction Mot mpromised	ls		Years A	Years After Implant	plant									
Fan	oM inN			t5A		Cor	un⊣	ът		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr 8	8 yr	10 yr	12 yr	14 yr	16 yr
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Jul-06	30,000	29,000	0	+	0	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 9 mo											
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 9 mo											
Adapta DR	ADDRL1)ul-06	1,000	1,000	0	+	0	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 6 mo											
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 6 mo											
Adapta DR	ADDRS1)ul-06	3,000	2,000	0	+	0	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 8 mo											
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 8 mo											
Adapta SR	ADSR01, ADSR03, ADSR06)ul-06	000'9	000'9	0	+	0	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0 at 8 mo											
									Including Normal Battery Depletion	100.0 +0.0/-0.0 at 8 mo											
AT500	AT501, 7253	Mar-03	11,000	7,000	140	4	3	7	Excluding Normal Battery Depletion	100.0+0.0/-0.1	100.0+	100.0+0.0/-0.1	99.7 +0.2/-0.4	99.7 +0.2/-0.4	99.7 +0.2/-0.4 at 62 mo						
	System Fol	70 – Perfo Ilow-Up Pr	rmance no otocol	see page 170 – Performance note on AT500 Pacing System Follow-Up Protocol	Pacing				Including Normal Battery Depletion	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.7 +0.1/-0.2	97.0	61.1	53.7 +5.6/-6.0 at 62 mo						
Elite	7074, 7075, 7076,	Apr-91	48,000	400	3,572	1	I	85	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.8 +0.0/-0.0	99.8 +0.0/-0.1	99.8	99.8	99.8	99.8	99.8	99.8 +0.0/-0.1 at 157 mo	
									Including Normal Battery Depletion	99.9	99.8	99.6 +0.1/-0.1	99.5 +0.1/-0.1	98.9 +0.1/-0.1	97.8	95.6 +0.2/-0.3 +	91.0	76.4	52.8	16.7 +2.5/-2.3 at 157 mo	
EnPulse DR	EIDR01, EIDR03, EIDR06	Dec-03	2,000	2,000	2	+	_	-	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.1	100.0 +0.0/-0.1 at 41 mo								
									Including Normal Battery Depletion	100.0+0.0/-0.0	100.0	99.9 +0.1/-0.2	99.9 +0.1/-0.2 at 41 mo								

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		16 yr															
	_	14 yr															
	_	12 yr															
	_	10 yr														99.9 +0.0/-0.0 at 103 mo	10.3 +1.8/-1.6 at 103 mo
	_	yr														99.9 +0.0/-0.0 +0.0 at	62.8 +1.0/-1.0 +1 at
	_	× ×														99.9	90.8 +0.4/-0.5 +1
	_	yr 7														99.9	97.7
	_	yr 6														99.9	99.2 97+0.1/-0.1
ty (%)	_	4 yr 100.0 +0.0/-0.0	99.8 +0.1/-0.5	100.0 +0.0/-0.0 at 39 mo	100.0 +0.0/-0.0 at 39 mo					100.0 +0.0/-0.0 at 40 mo	99.8 +0.1/-0.4 at 40 mo					100.0 + 0.0/-0.0+	99.6
Device Survival Probability (%)	_	3 yr 100.0 100.0 100.0 100.0	99.8 +0.1/-0.5 +6	100.0 +0.0/-0.0 +0 at	100.0 +0.0/-0.0 at	100.0+0.0/-0.0	99.8	100.0 +0.0/-0.0 at 25 mo	100.0 +0.0/-0.0 at 25 mo	100.0 +0.0/-0.0 at	99.8 +0.1/-0.4 at	100.0 +0.0/-0.0 at 28 mo	100.0 +0.0/-0.0 at 28 mo	100.0 +0.0/-0.0 at 25 mo	99.9 +0.0/-0.1 at 25 mo	0.00-0.0+	99.8
urvivall	er Im	2 yr 100.0 +0.0/-0.0	100.0 +	100.0+	0.00+	100.0+	99.8	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 +	100.0+	99.9 + 10.0/-0.1	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 a	99.9 +0.0/-0.1 a	100.0+	99.9
Device S	Years Af	1 yr 100.0 100.0/-0.0		100.0+	100.0+	100.0+	100.0+	100.0+	100.0+	100.0+	100.0 + 0.0/-0.0 +	100.0+	100.0 + 0.0/-0.0 +	100.0+	100.0 + 0.0/-0.0 +	100.0+	99.9
		Excluding Normal Battery	Depletion Including Normal Battery	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	lead	N	Depletion Including Normal Battery	6 Excluding Normal Batter	Including Normal Battery Dep letion	Excluding Normal Battery Depletion	Including Normal Battery Depletior	0 Excluding Normal Battery Depletion	Including Normal Battery Depletior	3 Excluding Normal Battery Depletior	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletior	13 Excluding Normal Battery Depletion	Including Normal Battery Depletion	21 Excluding Normal Batter Depletio	Including Normal Battery Depletion
tions	notion Not ompromised		Depletio Includin Normal Batter	Norm	Including Normal Battery Depletion	Nora	Including Normal Battery Depletior	Nora	Including Normal Battery Depletior	Nor	Including Normal Battery Depletion	Norm	Including Normal Battery Depletion	Nor	Including Normal Battery Depletion	Nor	Includin Normal Batter Depletio
Malfunctions	ompromised		Depletio Includin Normal Batter	6 Norm	Including Normal Battery Depletion	O Norm	Including Normal Battery Depletior	0 Norm	Including Normal Battery Depletior	3 Norm	Including Normal Battery Depletion	O	Including Normal Battery Depletion	13 Norn	Including Normal Battery Depletion	= 21 Norm	Includin Normal Batter Depletio
Malfunctions	ompromised netion Not ompromised		Depletio Includin NormalBatter	+ 3 = 6 Norm	Including Normal Battery Depletion	Norm	Including Normal Battery Depletion	0 = 0 +	Including Normal Battery Depletion	+ 2 = 3 Norm	Including Normal Battery Depletion	0 = 0 +	Including Normal Battery Depletion	+ 2 = 13 Norm	Including Normal Battery Depletion	+ 12 = 21 Norm	Includin Normal Batter Depletio
Malfunctions	spletions rerapy Function ompromised rerapy rerapy ompromised ompromised		Depletio Includin NormalBatter	2 3 + 3 = 6 Norm	Including Normal Battery Depletion	7 0 + 0 = 0 Norm	Including Normal Battery Depletion	0 = 0 + 0 0 Norm	Including Normal Battery Depletion	3 1 + 2 = 3 Norm	Including Normal Battery Depletion	0 = 0 + 0 Orm	Including Normal Battery Depletion	0 II + 2 = 13 Norm	Including Normal Battery Depletion	2,767 9 + 12 = 21 Norm	Includin Normal Batter Depletio
Malfunctions	fimplants timated tive US splants crive US splants crive US crive	1,000 TO	Depletio Includin NormalBatter	82,000 2 3 + 3 = 6 Norm	Including Normal Battery Depletion	10,000 7 0 + 0 = 0 Norm	Including Normal Battery Depletion	1,000 0 + 0 = 0 Norm	Including Normal Battery Depletion	19,000 3 1 + 2 = 3 Norm	Including Normal Battery Depletion	1,000 0 + 0 = 0 Norm	Including Normal Battery Depletion	50,000 0 11 + 2 = 13 Norm	Including Normal Battery Depletion	10,000 2,767 9 + 12 = 21 Norm	Includin Normal Batter Depletio
Malfunctions	signatered filmplants filmplants filmplants filmsted filmological filmsted filmsted filmsted filmsted filmstery film	2,000 1,000 1 0 + 0 = 0 Norm	Depletio Includin NormalBatter	100,000 82,000 2 3 + 3 = 6 Norm	Including Normal Battery Depletion	12,000 10,000 7 0 + 0 = 0 Norm	Including Normal Battery Depletion	1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	25,000 19,000 3 1 + 2 = 3 Norm	Including Normal Battery Depletion	1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	56,000 50,000 0 II + 2 = 13 Norm	Including Normal Battery Depletion	47,000 10,000 2,767 9 + 12 = 21 Norm	Including Normal Batter Depletio
Malfunctions	Impler Single of the state of t	Dec-03 2,000 1,000 1 0 + 0 = 0	Depletio Includin NormalBatter	Feb-04 100,000 82,000 2 3 + 3 = 6 Norm		Feb-04 12,000 10,000 7 0 + 0 = 0 Norm	Including Normal Battery Depletion	Feb-04 1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	Dec-03 25,000 19,000 3 1 + 2 = 3 Norm	Including Normal Battery Depletion	Dec-03 1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	May-05 56,000 50,000 0 11 + 2 = 13 Norm	Including Normal Battery Depletion	Jan-98 47,000 10,000 2,767 9 + 12 = 21 Norm	Including Normal Batter Depletio
Malfunctions	signatered filmplants filmplants filmplants filmsted filmological filmsted filmsted filmsted filmsted filmstery film	지 US RU	Depletio Includin NormalBatter	100,000 82,000 2 3 + 3 = 6 Norm		12,000 10,000 7 0 + 0 = 0 Norm	Including Normal Battery Depletion	1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	25,000 19,000 3 1 + 2 = 3 Norm	Including Normal Battery Depletion	1,000 1,000 0 0 + 0 = 0 Norm	Including Normal Battery Depletion	56,000 50,000 0 II + 2 = 13 Norm	Including Normal Battery Depletion	47,000 10,000 2,767 9 + 12 = 21 Norm	Including Normal Batter Depletio

Device Survival Summary continued

					E	Malfunctions	ions		E	Device	Surviva	Device Survival Probability (%)	ility (%)								
γlii	del nber	ysket Narket	istered stnalqm	bətsm SU əvi stna	mal Battery letions	rapy Function npromised rapy	ction Not oppomised	Įŧ		Years A	Years After Implant	plant									
Fam	ooM nuM	Kele US I		tοA		Con	un⊣	Tota		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 400 SR	KSR401, KSR403	Feb-98	15,000	4,000	383	+	3 =	4	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0 +0.0/-0.0	100.0	100.0+0.0/-0.0	0.00-/0.0+	100.0+	100.0+	100.00+	100.0 +0.0/-0.1 at 108 mo			
								2	Including Normal Battery Depletion	99.9 +0.0/-0.1	99.9	99.8 +0.1/-0.1	99.6	99.4	98.6	95.2	77.8	53.0 +3.7/-3.8 at 108 mo			
Kappa 600 DR	KDR601, KDR603, KDR606	Jan-99	24,000	8,000	536	+	n 	20	Excluding Normal Battery Depletion	100.0	100.0	100.0	99.9	99.9	99.9 +0.0/-0.1	99.9	99.9	99.9 +0.0/-0.1 at 97 mo			
	Advisories Power Sup	Advisories: see page Power Supply Wires	162 – 2002	Advisories: see <u>page 162</u> – 2002 Potential Fractured Power Supply Wires	actured	(TI) + (O) (advisory-rela	= (ted subs	_	Including Normal Battery Depletion	100.0+0.0/-0.0	99.9	99.9	99.6 +0.1/-0.1	99.0	97.1	91.3	76.8	76.8 +2.2/-2.4 at 97 mo			
Kappa 600 DR	KDR651, KDR653	Mar-01	14,000	2,000	75	+	2 =	4	Excluding Normal Battery Depletion	100.0	0.0/0.0+	100.0	100.0+0.0/-0.1	100.0+	+0.0/-0.1	99.9 +0.0/-0.1 at 73 mo					
	Advisories Power Sup	s: see page oply Wires	162 – 2002	Advisories: <u>see page 162</u> – 2002 Potential Fractured Power Supply Wires	actured	(1) + (0) (advisory-re) = ated sub		Including Normal Battery Depletion	100.0+0.0/-0.1	99.9	99.8	99.5	98.7	97.6	97.6 +0.4/-0.5 at 73 mo					
Kappa 700 D	KD701, KD703, KD706	Jan-99	300	001	4	+	II O	0	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 74 mo					
	Advisories: Power Supp	Advisories: see page Power Supply Wires	162 – 2002	see <u>page 162</u> – 2002 Potential Fractured by Wires	actured	(1) + ((advisory-r	$\frac{(1)}{(advisory-related subset)}$		Including Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	99.0	97.7 +1.4/-3.8	96.1	96.1 +2.2/-4.7 at 74 mo					
Kappa 700 DR	KDR701, KDR703, KDR706	Feb-99	192,000	94,000	2,818	172 +	. = .72	N 661	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	99.9 +0.0/-0.0	99.9	99.9	99.8	99.8	99.8	99.8 +0.0/-0.0 at 99 mo			
	Advisories Power Sup	Advisories: <u>see page</u> Power Supply Wires	<u> 162</u> – 2002	Advisories: <u>see page 162</u> – 2002 Potential Fractured Power Suppl <mark>y Wires</mark>	actured	(117) + (0) (advisory-rel) = ated su		Including Normal Battery Depletion	99.9	99.9	99.7 +0.0/-0.0	99.3	98.4	96.3	90.3	72.6	68.2 +1.6/-1.7 at 99 mo			
Kappa 700 DR	KDR721	Feb-99	000,01	2,000	869	4	" -	2	Excluding Normal Battery Depletion	100.0	100.0+	100.0	100.0	99.9	1.0-/0.0+	99.9	99.9 +0.0/-0.1 at 85 mo				
	Advisories Power Sup	Advisories: see page Power Supply Wires	<u> 162</u> – 2002	see page $162 - 2002$ Potential Fractured by Wires	actured	(4) + (4) (advisory-rel	ated sub		Including Normal Battery Depletion	99.9 +0.0/-0.1	99.7	99.0	96.8	91.3	72.6	39.7 +3.2/-3.3	37.1 +3.5/-3.5 at 85 mo				
Kappa 700 SR	KSR701, KSR703, KSR706	Feb-99	55,000	22,000	724	+	33 II	6	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	0.00-/0.0+	100.0+0.0/-0.0	100.0+	100.00+	100.0 +0.0/-0.1 at 98 mo			
									Including Normal Battery Depletion	99.9	99.9	99.6	99.0	97.7	95.3	89.1	72.0	70.2 +2.8/-3.1 at 98 mo			

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		16 yr													99.6 +0.1/-0.1 at 205 mo	53.8 +2.1/-2.1 at 205 mo
		14 yr													99.6 +0.1/-0.1	64.6 +0.9/-0.9
		12 yr													99.6 +0.1/-0.1	73.0
		10 yr													99.6	81.4
		8 yr	99.7 +0.2/-0.6 at 86 mo	77.4 +4.3/-5.2 at 86 mo											99.6	90.6
		7 yr	99.7	79.0				2							99.6	94.7
		6 yr	99.7 +0.2/-0.6	96.1			100.0 +0.0/-0.0 at 65 mo	99.1 +0.2/-0.2 at 65 mo	99.9 +0.1/-0.2 at 63 mo	98.4 +0.5/-0.7 at 63 mo			100.0 +0.0/-0.1 at 62 mo	95.4 +0.9/-1.1 at 62 mo	99.7 +0.1/-0.1	97.2
		5 yr	99.8 +0.1/-0.5	98.8	100.0 +0.0/-0.0 at 57 mo	99.8 +0.1/-0.2 at 57 mo	100.0	99.2	99.9	98.6 +0.3/-0.5	100.0 +0.0/-0.0 at 55 mo	100.0 +0.0/-0.0 at 55 mo	100.0+	95.9	99.7	98.3 +0.1/-0.1
bility (%		4 yr	99.8	99.0	100.0	99.8	100.0	99.6	100.0	99.4 +0.1/-0.2	100.0	100.0	100.0+	98.0 +0.3/-0.4	99.8	98.9 +0.1/-0.1
Device Survival Probability (%)	nplant	3 yr	99.9 +0.1/-0.4	99.6	100.0	99.8	100.0	99.8	100.0	99.8 +0.1/-0.1	100.0	100.0	100.0	99.5	99.8	99.4 +0.1/-0.1
e Surviv	Years After Implant	2 yr	99.9 +0.1/-0.4	99.9	100.0+0.0/-0.0	99.9	100.0	100.0	100.0	99.9 +0.0/-0.1	100.0	100.0	100.0	99.8 +0.1/-0.1	99.9	99.7 +0.0/-0.1
Devic	Years	1 yr	99.9 +0.1/-0.4	99.9 +0.1/-0.4	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0+0.0/-0.0	100.0	9.99	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion												
	al	тот	8	(3) ubset)	0		20		6		0		٦		143	
ctions	rapy ction Mot npromised al	Cor	0 3	= ted subs	0 0		10 = 20		7 = 9		0 = 0		0 = 1		_ 143	
Malfunctions	pesimorqn	The Fun Cor	Ш	= ed subs	Ш		II		ш		П		П		143	
Malfunctions	rapy rapy ction Mot npromised	The Cor The Fun Fun Cor	 0 +	(3) + (0) = $(advisory-related subs$	0 +		+ 10 +		+ 7		 		II O +		2,645 143	
Malfunctions	repy Function repy Function inapy repy ction Not besimore	Act Imp Mon Dep The Con The Fun Tool	3 + 0	(3) + (0) = $(advisory-related subs$	0 +		= 01 + 01		2 + 7 =		0 +		0 +		1	
Malfunctions	ive US lants mal Battery vietnons repy Function npromised repy repy	Esti Mon Mon The Con The Fun Fun Con	3 + 0	(3) + (0) = $(advisory-related subs$	0 +		141 10 + 10 =		45 2 + 7 =		0 + 0		0 + 1		2,645 — —	
Malfunctions	mated jve US ive US lants mal Battery mal Battery rapy Function rapy Functi	Reju Regu US: Feti Imp Mor Inp The Cor	1,000 51 3 + 0 =	(3) + (0) = $(advisory-related subs$	3,000 3 0 + 0 =		86,000 141 10 + 10 =		22,000 45 2 + 7 =		0 0 + 0 0 + 0 0		10,000 99 1 + 0 =		3,000 2,645 — —	
Malfunctions	Market sase istered implants ive US ive US lants mal Battery lants rapy Function repy Function repy Function repy Function	USIN Regard The Dept The Funn	2,000 1,000 51 3 + 0 =	= ted subs	4,000 3,000 3 0 + 0 =		125,000 86,000 141 10 + 10 =		37,000 22,000 45 2 + 7 =		1,000 400 0 + 0 =		16,000 10,000 99 1 + 0 =		57,000 3,000 2,645	

Device Survival Summary continued

		16 yr	99.9 +0.0/-0.0 at 183 mo	69.9 +1.6/-1.6 at 183 mo	99.9 +0.0/-0.0 at 216 mo	74.8 +1.9/-2.0	100.0 +0.0/-0.1 at 179 mo	70.8 +2.1/-2.3 at 179 mo								
		14 yr	99.9 +0.0/-0.0 +0.0 +0.0 +0.0 +0.0 +0.0 +0.0 +0.0	74.8 6. +0.9/-1.0 +1 at	99.9 +0.0/-0.0 +0.0/-0.0 at	81.1 74+0.7/-0.7	100.0 +0.0/-0.1 +0	73.3 70 +1.7/-1.8 +2 at								
		12 yr 1	96 6.00-0.0+	83.1 74+0.6/-0.6	96.9 0.0-/0.0+	83.9 +0.6/-0.6	100.0 +0.0/-0.1	82.7 73 +1.0/-1.1 +1			100.0 +0.0/-0.0 at 128 mo	65.6 +2.5/-2.6 at 128 mo	100.0 +0.0/-0.1 at 127 mo	74.7 +2.9/-3.2 at 127 mo		
		10 yr 12	99.9	89.2 +0.4/-0.4 +0.	09.9	87.2 +0.5/-0.5 +0.	100.0 10.0+0.0/-0.0+	89.4 82 +0.7/-0.8 +1.0	99.9 +0.1/-0.9 at 109 mo	84.1 +4.2/-5.5 at 109 mo	100.0 +0.0/-0.0	74.4 65.6 +1.4/-1.5 +2.5/ at 128	100.0 +0.0/-0.1 at	79.9 74. +1.8/-1.9 +2. at	100.0 +0.0/-0.0 at 109 mo	76.9 +4.9/-6.0 at 109 mo
			99.9	94.8 89.	99.9 0.0-/0.0+	91.9 +0.4/-0.4	100.0 + 0.0/-0.1 +0.0	94.7 89.4			100.0 + 0.0/-0.0 + 0.0	93.4 +0.4/-0.5 +1.4	100.0 100.0+	93.2 79.9+0.6/-0.7 +1.8	100.0 +0.0/-0.0 at 1	
		8 yr	0.0+		0.0-				99.9	92.3 3.0 +2.2/-3.1	0.0 +0.0,				-0.0 +0.0,	89.1 +2.8/-3.7
		7 yr	99.9	97.2	99.9 0.0-/0.0+ 0.0-/0.0	95.2 +0.3/-0.3	100.0 +0.0/-0.1	96.9 +0.3/-0.4	99.9	93.0	100.0	96.6 +0.3/-0.3	100.0 +0.0/-0.1	95.3 +0.5/-0.5	100.0	94.2
		6 yr	99.9	98.1	99.9 0.0/-0.0	97.7	100.0 +0.0/-0.1	98.2	99.9	96.4	100.0	98.1	100.0	97.5	100.0	97.3
		5 yr	99.9	98.8 +0.1/-0.1	99.9	98.7 +0.1/-0.1	100.0	98.9 +0.2/-0.2	99.9 +0.1/-0.9	98.3 +0.8/-1.4	100.0	99.0	100.0	98.6	100.0	98.2 +0.8/-1.5
oility (%		4 yr	99.9	99.2 +0.1/-0.1	99.9 +0.0/-0.0	99.2 +0.1/-0.1	100.0+0.0/-0.1	99.5 +0.1/-0.1	99.9 +0.1/-0.9	98.3 +0.8/-1.4	100.0+	99.5 +0.1/-0.1	100.0+0.0/-0.1	99.3 +0.1/-0.2	100.0+	99.4 +0.4/-0.9
Probat	plant	3 yr	100.0+0.0/-0.0	99.5 +0.1/-0.1	99.9 +0.0/-0.0	99.5 +0.1/-0.1	100.0+0.0/-0.0	99.8 +0.1/-0.1	99.9 +0.1/-0.9	99.1 +0.5/-1.2	100.0	99.7 +0.1/-0.1	100.0+0.0/-0.0	99.6 +0.1/-0.1	100.0	99.4
Device Survival Probability (%)	Years After Implant	2 yr	100.0+0.0/-0.0	99.7	99.9 +0.0/-0.0	99.7 +0.0/-0.0	100.0	100.0+0.0/-0.0	99.9	99.7 +0.2/-0.8	100.0	99.9	100.0+0.0/-0.0	99.9	100.0+0.0/-0.0	99.7 +0.2/-0.8
Device	Years A] yr	100.0+0.0/-0.0	99.9	0.0/-0.0+	99.9	100.0+	100.0+	100.0+	100.0+0.0/-0.0	100.0+	100.0+	100.0+0.0/-0.0	99.9	0.0/0.0+	99.7
ŀ			gr in		8 7 5		80 75	ge 7 E	90 > E	₩ > E	20 > E	ω > ⊑	Ø > □		90 > E	
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	I	stoT	36 Excludi Normal Batte Depleti	Includii Normal Batte Depletii	49 Excludir Normal Batte Depletic	Includir Normal Batte Depletic	4 Excludir Normal Batter Depletic	Includir Normal Bat te Depletid	T Excludin Normal Batter Depletio	Includin Normal Batter Depletio	3 Excludin Normal Batter Depletio	Includin Normal Batter Depletio	T Excludin Normal Batter Depletio	Includin Normal Batter Depletio	O Excludin Normal Batter Depletio	Includir Normal Batter Depletic
ctions	toN noit promised	шоЭ	Nor	Includi Normal Batte Depleti		— Includir Normal Batte Depletic	Nora	Includir Normal Batte Depletic	Norn	Includin Normal Batter Depletio		Includin Normal Batter Depletio		Includin Normal Batter Depletio		Includir Normal Batter Depletic
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Malfunctions	etions spy Function promised spy tion Not promised	Acti Impl Non Thei Com Thei Thei Thei Com	36 Norn	Includia Normal Batte Depleti	- 49	Norm	- 4 Norm	Includis Normal Batte Depletit	I - Norse	Includin Normal Batter Depletio	- 3	Includin Normal Batter Depletio	- I	Includin Normal Batter Depletio	0	Includir Normal Batter Depletic
Malfunctions	ve US ants nal Battery etions spy Function promised spy spy spy spy spy spy	Estin Acti Impl Morri Morri Morri Dep Thei Com	1,774 — — 36 Norm	Includia Normal Batte Depleti	1,473 — — 49	Norm	582 — 4 Norm	Includion Normal Batte Depletion Depletion	24 — 1 Norm	Includin Normal Batter Depletio	797 – 3	Includin Normal Batter Depletio	347 — — 1	Includin Normal Batter Depletio	100 39 0	Includir Normal Batter Depletic
Malfunctions	nplants mated ve US ants ants etions eppromised promised gay gay gay gay etion gay	Regis US In	6,000 1,774 — — 36 Norm	Includia Normal Batte Depletic	5,000 1,473 — — 49	Norm	2,000 582 — — 4 Norm	Includion Normal Batte Depletion Dep	200 24 — — 1 Norm	Includin Normal Batter Depletio	6,000 797 - 3	Includin Normal Batter Depletio	3,000 347 – – 1	Includin Normal Batter Depletio	39 0	Includir Normal Batter Depletic
Malfunctions	flarket ase sze szentet mplants nated ve US ants ants etions spy Function promised spy Runction rapy Function	Regis US In	59,000 6,000 1,774 — — 36 Norm	Includia Normal Batte Depletic	58,000 5,000 1,473 — — 49	Norm	17,000 2,000 582 — — 4 Norm	Includion Normal Batte Depletion Dep	1,000 200 24 — — 1 Norm	Includin Normal Batter Depletio	26,000 6,000 797 3	Includin Normal Batter Depletio	18,000 3,000 347 — — 1	Includin Normal Batter Depletio	100 39 0	Includir Normal Batter Depletic

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Summary
Survival
Device

		16 yr														
		14 yr														
		12 yr	99.9 +0.1/-0.4 at 125 mo	95.1 +1.5/-2.1 at 125 mo	100.0 +0.0/-0.0 at 127 mo	76.8 +4.1/-4.9 at 127 mo	100.0 +0.0/-0.0 at 131mo	62.1 +2.9/-3.0 at 131mo	100.0 +0.0/-0.0 at 124 mo	88.9 +3.2/-4.3 at 124 mo	100.0 +0.0/-0.0 at 129 mo	73.9 +2.5/-2.7 at 129 mo				
		10 yr	99.9 +0.1/-0.4	95.1	100.0	82.3 +2.9/-3.4	100.0	75.0 +1.2/-1.3	100.0	91.4 +2.5/-3.4	100.0	81.3				
		8 yr	99.9 +0.1/-0.4	97.5 +0.8/-1.1	100.0	96.0	100.0+0.0/-0.0	93.2 +0.4/-0.4	100.0	97.3 +1.0/-1.5	100.0	93.4 +0.5/-0.6				
		7 yr	99.9 +0.1/-0.4	98.5	100.0	97.1	100.0	96.6	100.0	98.9 +0.5/-0.9	100.0	95.9 +0.4/-0.4				
		6 yr	99.9 +0.1/-0.4	99.1 +0.4/-0.6	100.0	97.8 +0.6/-0.8	100.0	98.1 +0.2/-0.2	100.0	99.2	100.0	97.3 +0.3/-0.3				
_		5 yr	99.9 +0.1/-0.4	99.2	100.0	98.6 +0.4/-0.6	100.0+0.0/-0.0+	98.9	100.0	99.2	100.0	98.2 +0.2/-0.2				
Device Survival Probability (%)		4 yr	100.0	99.8	100.0	98.8 +0.4/-0.6	100.0	99.5	100.0	99.2	100.0	98.9				
al Probal	nplant	3 yr	100.0	99.8	100.0	99.4 +0.3/-0.4	100.0	99.8	100.0	99.8	100.0	99.4 +0.1/-0.1				
e Surviva	Years After Implant	2 yr	100.0	99.9 +0.1/-0.2	100.0	99.7	100.0+0.0-0.0+	99.9	100.0	99.9	100.0	99.7 +0.1/-0.1				
Device	Years	1 yr	100.0	99.9 +0.1/-0.2	100.0	99.9 +0.1/-0.2	100.0	99.9	100.0	99.9	100.0	99.8 +0.0/-0.1	100.0 +0.0/-0.0 at 8 mo	100.0 +0.0/-0.0 at 8 mo	100.0 +0.0/-0.0 at 8 mo	100.0 +0.0/-0.0 at 8 mo
			ding tery tion	ling ery tion	ing ery ion	ing ery ion	ing ery ion	ing ery ion	ery ion	ng ery on	ng ng	ng ry on	ng ery on	ng ery on	ing ery ion	ing ery ion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
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Device Survival Summary continued

					E	Malfunctions		Device	Surviva	Device Survival Probability (%)	llity (%)								
V liu	del mber	Market ease	gistered stnalqml	bətsmi SU əvit stnslo	rmal Battery pletions	Proction Thromised Process Pro		Years /	Years After Implant	plant									
пвЯ	oM uN			ı>Α		Coi The		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Sigma 100 S	SS103, SS106	Aug-99	1,000	200	3	0	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 75 mo					
	Advisories of Interco	s: see page 1	<u>50</u> – 2005	Advisories: see page 160 – 2005 Potential Separation of Interconnect Wires	aration	(0) + (0) = (0) (advisory-related subset)	Including Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	99.5 +0.3/-1.4	99.5	98.5	98.5	96.7 +1.9/-4.5 at 75 mo					
Sigma 200 DR	SDR203	Aug-99	16,000	8,000	34	3 + 1 = 4	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+	100.0+	100.0+0.0/-0.1	100.0 +0.0/-0.1 at 89 mo				
	Advisories of Interco	s: see page 1 nnect Wires	<u>50</u> – 2005	Advisories: see $\underline{page160}-2005$ Potential Separation of Interconnect Wires	aration	(1) + (0) = (1) (advisory-related subset)	Including Normal Battery Depletion	100.0	99.9	99.9 +0.0/-0.1	99.8	99.6	99.1	98.2 +0.4/-0.6	98.0 +0.5/-0.7 at 89 mo				
Sigma 200 SR	SSR203	Sep-99	12,000	2,000	17	2 + 0 = 2	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.1	100.0+	100.0+	100.0+	100.0 +0.0/-0.1 at 89 mo				
	Advisories of Intercol	Advisories: see page 16 of Interconnect Wires	<u>50</u> – 2005	Advisories: see $\underline{page\ 160}-2005\ Potential\ Separation$ of Interconnect Wires	aration	(2) + (0) = (2) (advisory-related subset)	Including Normal Battery Depletion	100.0	99.9	99.8	99.7	99.5 +0.2/-0.2	99.4	98.7	98.7 +0.5/-0.8 at 89 mo				
Sigma 300 DR	SDR303, SDR306	Aug-99	104,000	62,000	E	54 + 8 = 62	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9	99.9	99.9	99.9	99.9 +0.0/-0.0 at 92 mo				
	Advisories of Interco	Advisories: see page 16 of Interconnect Wires	<u>50</u> – 2005	Advisories: see \underline{page} $\underline{160} - 2005$ Potential Separation of Interconnect Wires	aration	(26) + (1) = (27) (advisory-related subset)	Including Normal Battery Depletion	100.0+0.0/-0.0	99.9	99.9	99.7 +0.0/-0.1	99.5	99.2	98.5	98.4 +0.2/-0.3 at 92 mo				
Sigma 300 SR	SSR303, SSR306	Sep-99	52,000	25,000	09	11 + 1 = 12	Excluding Normal Battery Depletion	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9 +0.0/-0.0 at 90 mo				
	Advisories of Interco	Advisories: see page 16 of Interconnect Wires	<u>50</u> – 2005	Advisories: <u>see page 160</u> – 2005 Potential Separation of Interconnect Wires	aration	(5) + (0) = (5) (advisory-related subset)	Including Normal Battery Depletion	100.0+0.0/-0.0	99.9	99.8	99.7 +0.1/-0.1	99.5	99.0	98.3	98.3 +0.4/-0.5 at 90 mo				
Sigma 300 VDD	SVDD303	Sep-99	1,000	300	0	0 1 0 + 0	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0	100.0	100.0	100.0	100.0 +0.0/-0.0 at 73 mo					
	Advisories of Interco	s: see page 1	<u>50</u> – 2005	Advisories: see page 160 – 2005 Potential Separation of Interconnect Wires	aration	(0) + (0) = (0) (advisory-related subset)	Including Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	100.0+0.0/-0.0	100.0	100.0 +0.0/-0.0 at 73 mo					
Thera D	7944, 7945, 7946	Jan-95	2,000	0	175	- 5	Excluding Normal Battery Depletion	99.9 +0.0/-0.3	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.7 +0.3/-1.3 at 111 mo			
							Including Normal Battery Depletion	99.9	99.8	98.9	97.3	93.5	90.0	82.8	66.7	47.0 +4.9/-5.1 at III mo			

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					Malfunctio	tions			Device :	Survival Probability (%)	Probab	ility (%)								
ирек	Narket sase	beretzi stnslqm	bətsm SU əvi stnsl	mal Battery oletions	rapy Function npromised	rapy ction Not pesimorqu	al		Years A	After Implant	plant									
			tэА			un∃	toT		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
7940, 7941, 7942	Jan-95	30,000	_	3,027	1	ı	37	Excluding Normal Battery Depletion	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9	99.9 +0.0/-0.1	99.8 +0.0/-0.1	99.8	99.8 +0.0/-0.1	99.8	99.8 +0.0/-0.1 at 113 mo			
								Including Normal Battery Depletion	100.0+0.0/-0.0	99.7	98.5 +0.2/-0.2	96.5 +0.2/-0.3	93.5 +0.3/-0.4	88.7 +0.5/-0.5	80.7 +0.6/-0.6	66.2 +0.9/-0.9	17.7 +2.7/-2.5 at 113 mo			
7950, 7951, 7952	Jan-95	5,000	400	236	1	I	_	Excluding Normal Battery Depletion	100.0+0.0/-0.1	100.0+	100.0+	100.0	100.0+	100.0+	100.0+	100.0+	100.0+	100.0 +0.0/-0.1 at 143 mo		
					1	ı	1	Including Normal Battery Depletion	100.0+0.0/-0.1	100.0+0.0/-0.1	99.7	99.5 +0.2/-0.3	99.2 +0.3/-0.4	98.5 +0.4/-0.5	97.3 +0.6/-0.7	95.9 +0.7/-0.9	86.6	54.9 +4.0/-4.2 at 143 mo		
8944, 8945, 8946	Jan-95	3,000	001	84	1	ı	8	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	99.9	99.8	99.8	99.8	99.8 +0.2/-0.5	99.8	99.8 +0.2/-0.5	99.8 +0.2/-0.5 at 136 mo		
								Including Normal Battery Depletion	100.0	99.9	99.5	98.4 +0.5/-0.8	96.7 +0.9/-1.2	95.9	93.2	88.5 +2.1/-2.6	70.0	66.4 +4.5/-5.0 at 136 mo		
8940, 8941, 8942	Jan-95	14,000	200	818	1	ı	91	Excluding Normal Battery Depletion	100.0+0.0/-0.0	99.9 +0.0/-0.1	99.9	99.8 +0.1/-0.1	99.8 +0.1/-0.1	99.8	99.8	99.8	99.8	99.8 +0.1/-0.1 at 139 mo		
					I	I	1	Including Normal Battery Depletion	99.8	99.5	99.0	97.7 +0.3/-0.3	96.2 +0.4/-0.4	93.3 +0.6/-0.6	87.7 +0.8/-0.9	77.1	53.3 +2.2/-2.2	46.6 +2.5/-2.6 at 139 mo		
7964i, 7965i, 7966i	Oct-95	3,000	1,000	114	1	1	_	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0 +0.0/-0.2 at 132 mo		
								Including Normal Battery Depletion	100.0	99.9	99.6	99.5 +0.2/-0.4	99.1 +0.3/-0.5	97.6 +0.6/-0.8	96.3 +0.8/-1.0	93.8 +1.1/-1.4	80.4	70.3 +4.1/-4.6 at 132 mo		
7960i, 7961i, 7962i	Oct-95	122,000	22,000	5,227	1	ı	50	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	99.9	99.9	99.9	99.9	99.9 +0.0/-0.0 at 137 mo		
								Including Normal Battery Depletion	100.0+0.0/-0.0	99.9	99.7 +0.0/-0.0	99.5 +0.0/-0.0	99.0	98.2 +0.1/-0.1	96.6	93.1 +0.2/-0.2	73.7 +05/-0.5	47.4 +2.4/-2.4 at 137 mo		
7968i	96-In(4,000	400	216	1	ı	3	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	99.9	99.9 +0.1/-0.2	99.9 +0.1/-0.2	99.9	99.9 +0.1/-0.2	99.9	99.9 +0.1/-0.2 at 112 mo			
								Including Normal Battery Depletion	100.0+0.0/-0.0	99.8	99.5 +0.2/-0.3	98.6 +0.4/-0.6	97.0 +0.6/-0.8	94.1	88.8	76.7 +2.3/-2.5	54.7 +4.2/-4.4 at 112 mo			

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		8 yr 10 yr 12 yr 14 yr 16 yr	100.0 100.0 100.0 100.0 100.0 100.0 100.0 +0.0/-0.3 +0.0/-0.3 +0.0/-0.3 at 132 mo	-0.9 96.4 92.8 88.6 92.9 1.5/-1.8 42.5/-3.2 at 132 mo	2 100.0 100.0 100.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0.0 0.0	98.2 +0.2/-0.2 +0.2/-0.2 94.7 83.1 69.6 +0.3/-0.3 +0.8/-0.8 +2.1/-2.3 at 137 mo	100.0 100.0	-0.4 +0.4/-0.6 +1.7/-2.1 +3.0/-3.6 at 130 mo		
		5 yr 6 yr 7 yr	100.0 +0.0/-0.3 +0.0/-0.3 +0.0/-0.3	99.3 98.9 98.2 97.5 96.4 +0.3/-0.5 +0.4/-0.6 +0.5/-0.8 +0.7/-0.9 +0.9/-1.2	100.0 +0.0/-0.0 +0.0/-0.0	98.9 98.2 97.0 +0.1/-0.1 +0.2/-0.2 +0.2/	0.00-0.00+ 0.00-0.00+ 0.00-0.00+	99.3 99.2 99.2 +0.2/-0.4 +0.3/-0.4		
Device Survival Probability (%)	ıplant	3 yr 4 yr	100.0 100.0 100.0 100.0 100.0 100.0 100.0 +0.0/-0.3 +0.0/-0.3		100.00 100.00 100.00 100.00 +0.0/-0.0 +0.0/-0.00 +0.0/-	99.4 +0.1/-0.1	100.0 100.0 100.0+	99.6 99.6 +0.1/-0.3 +0.2/-0.3		
Device Surviva	Years After Implant	1 yr 2 yr		99.9 99.8 99.8 +0.0/-0.2 +0.1/-0.3		100.0 +0.0/-0.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0		100.0 +0.0/-0.1 +0.1/-0.2	100.0 +0.0/-0.0 at 8 mo	100.0
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery
			Nor	Nora	Norm	Nor	Norm	Norm	Norm	Norms
Maitunctions	Proction Tpromised Proposition Mot Ction Mot Tpromised Sl	The The	l Norm	Norm	Norm	Norm	0 Norm	Norm	0 = 0 + 0	Norms
Maltunctions	rapy Yqsy otion Mot noromised	Act More Dep The Con The The The	-	Norm		Norm	O Norm	Norm	0 = 0 +	Norms
Malfunctions	ristered implants in a leaded	Regarded Month of Mon	4,000 1,000 45 - 1	Norm	50,000 8,000 1,133 7	Norm	5,000 1,000 67 — 0 Norm	Norm	11,000 10,000 0 0 + 0 = 0 Norm	Norm
Maltunctions	Market ease jistered implants ive US ive US sive US si	Rela Regardance Most Most Most Most Most Most Most Most	1,000 45 — — 1	Norm	8,000 1,133 7	Norm	1,000 67 — 0 Norm	Norm	10,000 0 + 0 = 0 Norm	Norms



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

Model		Estimated Long	evity					
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators			
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**			
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**			
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**			
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**			
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**			
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.			
Elite	7074, 7075, 7076, 7077	Low 2.5 V, 0.36 ms (A, RV) Nominal 3.3 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	11.8 8.6 6.7	13.2 11.0 9.4	**			
EnPulse DR	EIDROI, EIDRO3, EIDRO6	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse DR	EIDR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**			
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	妆妆			
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**			
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	**			
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**			
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**			

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated Long	evity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	***
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend	8416, 8417, 8417 M , 8418, 8419	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	15.6 11.3 9.0	17.7 14.5 12.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva D	7068	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**

 $^{{\}rm **Telemetry\ indication.\ Rate\ and\ mode\ change\ to\ 65\ ppm\ and\ VVI\ respectively\ (VOO/65\ with\ magnet)}.$



Reference Chart continued

Estimated Longevity

		Estimated Lon	igevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Preva ST DR	7078	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.
Prodigy D	7864, 7865, 7866	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy S	8164, 8165, 8166	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia DR	SEDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera D	7944, 7945, 7946	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.6 5.5 3.7	8.8 7.1 5.6	**
Thera DR-40	7940, 7941, 7942	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.6 5.5 3.7	8.7 7.0 5.6	**
Thera DR-50	7950, 7951, 7952	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	12.2 9.1 6.7	14.0 11.6 9.3	**

 $^{{\}rm **Telemetry\ indication.\ Rate\ and\ mode\ change\ to\ 65\ ppm\ and\ VVI\ respectively\ (VOO/65\ with\ magnet)}.$



Reference Chart continued

		Estimated L	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Thera S	8944, 8945, 8946	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.5 6.1 4.8	8.2 7.2 6.2	**
Thera SR	8940, 8941, 8942	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.0 4.8	8.0 7.1 6.1	**
Thera-i D	7964i, 7965i, 7966i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i DR	7968i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 5.4 3.9	8.3 6.9 5.5	**
Thera-i S	8964i, 8965i, 8966i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

 $^{{\}rm **Telemetry\ indication.\ Rate\ and\ mode\ change\ to\ 65\ ppm\ and\ VVI\ respectively\ (VOO/65\ with\ magnet)}.$

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 20 years with its multicenter chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads which are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, multicenter study designed to monitor the performance of market-released cardiac therapy products. The SLS is the unification of the Chronic Lead Study (CLS) for pacing leads and the Tachyarrhythmia Chronic Systems Study (TCSS) for ICD leads, which have been ongoing in several geographies since 1983 and 1991, respectively. More than 35 centers participating as CLS study sites or TCSS study sites, or both, are expected to complete the unification to become SLS study sites in 2007. Through these studies, Medtronic has over 20 years of lead data from over 70,000 leads studied. More than 19,000 of these leads are currently active.

Patients are eligible for enrollment in the study if

- 1 They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2 They participated in a qualifying study of a market-released Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

Lead Complications

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance

Method for Estimating Lead Performance continued

The Standard Actuarial Method is used to determine estimates of lead survival.

- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is electively abandoned or explanted, or the patient is no longer available for follow-up. The data analyses assume that the patient is still part of the study and there are no lead complications at the time of the report cutoff date unless specifically reported by the center or by correlation with returned product analysis. Implant times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, patient leaves the study or the lead is no longer being used), or the cutoff date of the report.

If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are reported in PPR tables.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in one year intervals, the curves are actually computed and plotted using three-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Method for Estimating Lead Performance continued

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

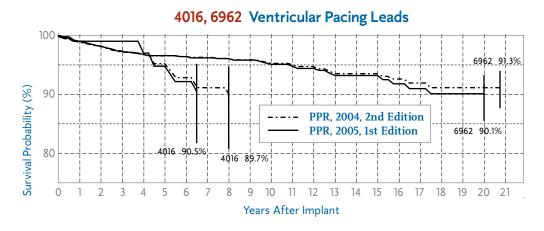
Chronic Lead Data Resolution

Because an accurate estimate of lead survival depends on an accurate estimate of the number of leads in service, it is important not to overstate the number of devices in service. Since the inception of the CLS and TCSS studies, the mechanism of patient follow-up has changed due to evolution in hospital follow-up practices and extrinsic issues such as the impact of the Health Insurance Portability and Accountability Act for US centers. As a result, some patients who were thought to be active participants in the study are actually no longer available for study follow-up. Therefore, Medtronic has initiated an additional data resolution process to verify lead status for all active study patients. This process is ongoing and is expected to conclude in 2007. Combined with our

prospective study monitoring practices, this process aligns with our continuous efforts to improve product performance reporting. The survival curves in this edition of the Product Performance Report reflect this additional process.

This data resolution process can change survival estimates when patients in whom leads were thought to be active at the time of the previous analysis have since been determined to no longer be available for follow-up. This has the effect of shortening the curve if leads that were previously presumed to be among those with the longest survival are no longer active at that time. Such a determination also decreases the number of leads remaining in the analysis cohort, which generally lowers the estimated probability of survival.

As the data resolution process proceeds, survival curves can change from one issue of the PPR to the next. For example, as noted in the figure below, the curve for the ventricular lead model 4016 extends to 8 years with an estimated survival probability of 89.7% in the 2004 Second Edition PPR, but extends to 6.5 years with an estimated survival probability of 90.5% in the 2005 First Edition. In contrast, the curve for the ventricular lead model 6962 extends to 20.75 years with an estimated survival probability of 91.3% in the 2004 Second Edition, but extends to 20 years with an estimated survival probability of 90.1% in the 2005 First Edition. The confidence intervals at the ends of the curves are included here for consistency with those in the rest of the report. In general, these confidence intervals are not statistically comparable for assessing whether survival probability has changed between different editions of the PPR.



Method for Estimating Lead Performance continued

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

Lead malfunctions are divided into three categories: Implant Damage, Electrical, and Other. Typical examples of implant damage are stylet perforation, cut or torn insulation, bent or distorted conductors, over-retracted helixes, and conductor fracture due to overtorquing. An electrical malfunction is defined as a hardware malfunction resulting in a break in the insulation or a break in the conductor that could affect the electrical performance of the lead. A break in the insulation is defined as a breach allowing entry of body fluids, or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions. environmental stress cracking (ESC), and metal ion oxidation (MIO). A break in the conductor of a lead is defined as the loss of continuity in the metallic components that could interrupt the current flow or voltage. Examples include fractured conductors and defective crimps.

Leads damaged after explant or damaged due to failure to heed warnings or contraindications in the labeling are not considered device malfunctions.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides estimates for the number of leads implanted in the United States and the number remaining active in the United States. The number of US implants is estimated based on the total number of leads sold in the United States. The number of active implants is estimated using the total number of leads sold and projections for normal patient mortality, elective replacement, and lead failure. The number of implanted leads and active leads is adjusted for underreporting of patient mortality, elective replacement, and lead failure.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

Left-Heart Leads

2187 Attain

Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEY	Returned Product Analy	sis
Estimated US Implants	17,200	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Implant Damage	7
Estimated US Active	10,700	Polarity	Unipolar	Electrical Malfunction Other	0 16
Advisories	None	Steroid	No	O tile!	

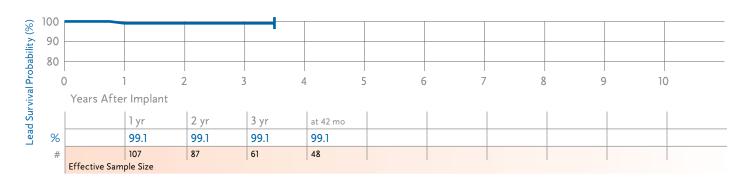
System Longevity Study Results

Qualifying Complications

1 Total

Number of Leads Enrolled in Study	133
Cumulative Months of Follow-Up	5,162

Failure to Capture



2188 Attain

Product Characteristics

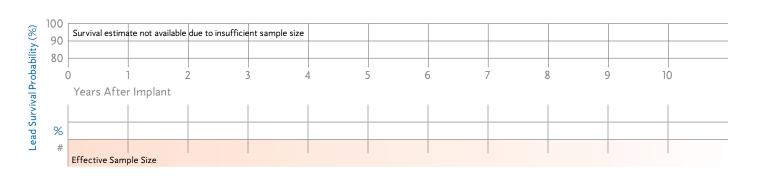
US Market Release	Aug-01	Serial Number Prefix	LEB	Returned Product Ana	lvsis	
Estimated US Implants	stimated US Implants 2,800		Transvenous, Coronary Sinus/ Cardiac Vein, Canted	Implant Damage		
Estimated US Active	1,500	Polarity	Bipolar	Electrical Malfunction Other	1	
Advisories	None	Steroid	No	Other	Ū	

System Longevity Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	14
Cumulative Months of Follow-Up	356

Extra Cardiac Stimulation



Left-Heart Leads continued

4193 Attain

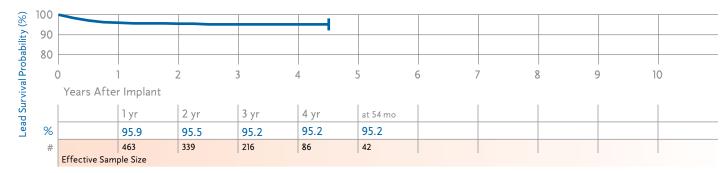
Product Characteristics

US Market Release	May-02	Serial Number Prefix	BAA	Returned Product Ana	llvsis
Estimated US Implants	104,700	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Implant Damage	59
Estimated US Active	78,600	Polarity	Unipolar	Electrical Malfunction Other	17 63
Advisories	None	Steroid	Yes	o inci	33

System Longevity Study Results

Qualifying Complications 28 Total

Number of Leads Enrolled in Study	671	Conductor Fracture	1
Cumulative Months of Follow-Up	17.788	Extra Cardiac Stimulation	4
	,	Failure to Capture	9
		Lead Dislodgement	11
		Unspecified Clinical Failure	3



4194 Attain

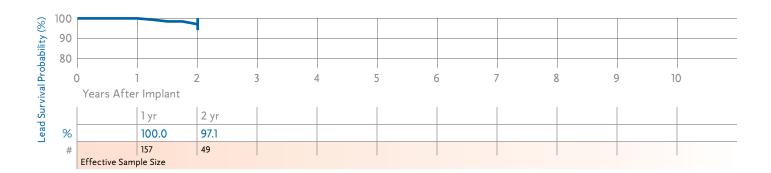
Product Characteristics

US Market Release	Aug-04	Serial Number Prefix	LFG	Returned Product Ana	alvsis	
Estimated US Implants 57,600		Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Implant Damage		
Estimated US Active	50,500	Polarity	Bipolar	Electrical Malfunction Other	1 6	
Advisories	None	Steroid	Yes	Other	Ū	

System Longevity Study Results

Qualifying Complications 3 Total

Number of Leads Enrolled in Study	318	Failure to Capture	1
Cumulative Months of Follow-Up	4 693	Lead Dislodgement	2



Left-Heart Leads continued

Lead Survival Summary (95% Confidence Interval)

Model Number	Family	US Market Release	Leads Enrolled	Qualifying Complications	Cumulative Months of Follow-Up in Study	Years A	Survival F after Imp	lant	I .	5 yr	6 yr	7 yr	8 Vr	9 yr	10 yr
2187	Attain	Aug-01	133	1	5,162	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3 at 42 mo	3 yr	o yr	/ yr	8 yr	9 yr	10 yr
2188	Attain	Aug-01	14	1	356	Survival e	stimate no	t available		ficient san	iple size				
4193	Attain	May-02	671	28	17,788	95.9 +1.4/-1.9	95.5 +1.4/-2.1	95.2 +1.5/-2.2	95.2 +1.5/-2.2	95.2 +1.5/-2.2 at 54 mo					
4194	Attain	Aug-04	318	3	4,693	100.0	97.1 +2.0/-6.4								

Source: System Longevity Study Data as of January 31, 2007

Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
2187	Attain	Aug-01	17,200	10,700	7	0	16
2188	Attain	Aug-01	2,800	1,500	1	1	0
4193	Attain	May-02	104,700	78,600	59	17	63
4194	Attain	Aug-04	57,600	50,500	62	1	6

Source: Returned Product Analysis Data as of January 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1BI
4193	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1BI

6721 93.4%

Defibrillation Leads

6721, 6921 Epicardial Patch

Product Characteristics

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	Returned Product Ana	alvsis
Estimated US Implants	9,000	Type and/or Fixation	Epicardial Defib Patch, Suture		_
Estimated US Active	2,100	Polarity	Defib Electrode only	Implant Damage Electrical Malfunction	5 79
Advisories	None	Steroid	No	Other	0

System Longevity Study Results

100

90

Qualifying Complications 28 Total

Number of Leads Enrolled in Study	407	Conductor Fracture	20
Cumulative Months of Follow-Up	18,070	Failure to Capture Impedance Out of Range Insulation (not further defined)	2 3 3



6930 Sprint Fidelis

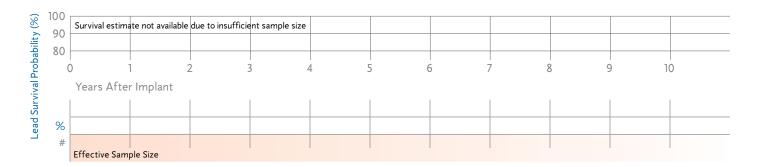
Product Characteristics

US Market Release	Jun-04	Serial Number Prefix	LFK	Returned Product Ana	lvsis
Estimated US Implants	300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	0
Estimated US Active	300	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	0
Advisories see page 159 – 2007 Poter Conductor Wire Fracture	1 Itial	Steroid	Yes	Other	v

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	1
Cumulative Months of Follow-Up	4



6931 Sprint Fidelis

Product Characteristics

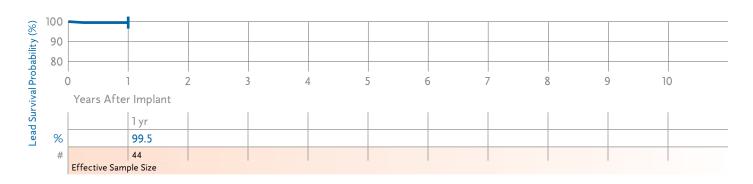
US Market Release	Sep-04	Serial Number Prefix	LFL	Implant Damage 19 Electrical Malfunction 39	lysis
Estimated US Implants	7,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in		19
Estimated US Active	6,300	Polarity	True Bipolar/One Coil		39 0
Advisories see page 159 – 2007 Poter Conductor Wire Fracture		Steroid	Yes	o anei	v

System Longevity Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	212	Lead Dislodgement	1

Cumulative Months of Follow-Up 2,195



6932 Sprint

Product Characteristics

US Market Release	Aug-96	Serial Number Prefix	TCA	Returned Product Analysi	
Estimated US Implants	15,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	16
Estimated US Active	6,500	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	37 7
Advisories	None	Steroid	Yes	Other	,

System Longevity Study Results

Qualifying Complications 8 Total

Number of Leads Enrolled in Study	410	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	19,557	Failure to Capture	2
		Failure to Sense	2
		Oversensing	3



6933, 6937, 6937A, 6963 SVC/CS **Product Characteristics US Market Release** Serial Number Prefix TAT, TBU, or TAF Dec-93 Returned Product Analysis Estimated US Implants 17,400 Type and/or Fixation Transvenous CS or SVC Defib Implant Damage 31 **Estimated US Active** 5,600 Polarity One Defib Coil **Electrical Malfunction** 192 Advisories None Steroid No Other 13 System Longevity Study Results **Qualifying Complications** 23 Total Number of Leads Enrolled in Study 966 Conductor Fracture Lead Dislodgement Failure to Capture Unspecified Clinical Failure 3 1 Cumulative Months of Follow-Up 47,123 Impedance Out of Range 2 Insulation (not further defined) 2 100 Lead Survival Probability (%) 90 80 8 9 10 18 19 20 3 5 11 12 14 15 16 21 13 Years After Implant Lead Group Overall ····· Individual Lead Models 1 yr | 2 yr | 3 yr 4 yr 5 yr 6 yr 7 yr | 8 yr | 9 yr | 10 yr | 11 yr 98.6 97.0 96.4 95.2 94.6 93.9 92.8 92.8 596 408 326 246 183 139 97 Effective Sample Size

6936, 6966 Transvene **Product Characteristics** TAV or TAL **US Market Release** Dec-93 Serial Number Prefix Returned Product Analysis Transvenous, Vent, Defib and Estimated US Implants 24,600 Type and/or Fixation Implant Damage 90 Pace/Sense, Screw-in **Electrical Malfunction** 457 **Estimated US Active** 5,900 Polarity True Bipolar/One Coil Other 19 Advisories None Steroid No System Longevity Study Results Qualifying Complications 143 Total Number of Leads Enrolled in Study 1,349 Conductor Fracture 17 Oversensing 90 Extra Cardiac Stimulation 2 Unspecified Clinical Failure Cumulative Months of Follow-Up 66,656 Failure to Capture 8 Failure to Sense Impedance Out of Range 4 Insulation (not further defined) 13 100 ead Survival Probability (%) 90 80 70 6966 61.7% 60 6936 63.2% 50 2 8 18 19 20 21 Years After Implant Lead Group Overall Individual Lead Models 2 yr | 3 yr | 4 yr | 5 yr | 6 yr 8 yr | 9 yr | 10 yr | 11 yr 141 mo 99.2 98.4 97.0 96.0 92.8 87.5 79.5 75.5 70.0 66.6 64.1 63.1 1,042 861 Effective Sample Size

6939, 6999 Sub-Q Patch

Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TBA or TAP	Returned Product Ana	lvsis
Estimated US Implants	4,300	Type and/or Fixation	Subcutaneous Defib Patch, Suture		
Estimated US Active	900	Polarity	Defib Electrode Only	Implant Damage Electrical Malfunction	4 32
Advisories	None	Steroid	No	Other	1

System Longevity Study Results

Qualifying Complications 20 Total

Number of Leads Enrolled in Study	384	Conductor Fracture	10
Cumulative Months of Follow-Up	17,668	Failure to Capture Insulation (not further defined) Unspecified Clinical Failure	2 6 2



6942 Sprint

Product Characteristics

	US Market Release Jul-97 Estimated US Implants 18,100 Estimated US Active 8,300		97 Serial Number Prefix		TCB			Returned Product Analysis				
			18,100	Type and/or Fixation		Transvenous, \Pace/Sense, T		d	Implant Damage			
			8,300		Polarity		Integrated Bip	olar/Two Coils	5	Electrical Malfunction Other		
	Advisories		None		Steroid		Yes				Other	
stem	Longevity St	tudy Result:	S			Qualifyi	ng Complication	ns 7 Total				
	Number of I	Leads Enrolle	ed in Study	352			Conductor Fractu	re 1				
	Cumulative	Months of F	ollow-Up	14,621			Failure to Sen					
							Lead Dislodgeme					
						Unspec	Oversensing 3 ecified Clinical Failure 1					
100						'						
90												
80												
	0	1	2	3	4	5	6	7	8	9	10	
	Years Afte	er Implant	_		·						. •	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 87 m	0		
%		98.9	98.9	97.8	97.2	96.3	96.3	96.3	96.3			

Effective Sample Size

6943 Sprint

Product Characteristics

US Market Release	Oct-97	Serial Number Prefix	TCE	Returned Product Ana	lvsis
Estimated US Implants	21,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Implant Damage	50
Estimated US Active	9,900	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	63 8
Advisories	None	Steroid	Yes	Other	ŭ

System Longevity Study Results

Qualifying Complications 45 Total

Number of Leads Enrolled in Study	1,309	Conductor Fracture	8	Lead Dislodgement	1
Cumulative Months of Follow-Up	60,060	Failure to Capture	4	Oversensing	22
•	•	Failure to Sense	3	Unspecified Clinical Failure	3
		Impedance Out of Range	3		

Insulation (not further defined)



6944 Sprint Quattro

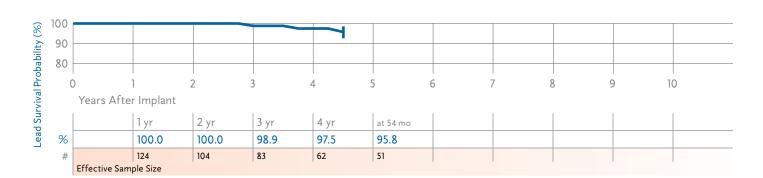
Product Characteristics

US Market Release	Dec-00	Serial Number Prefix	TDC	Returned Product Ana	alvsis
Estimated US Implants	28,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Implant Damage	23
Estimated US Active	18,700	Polarity	True Bipolar/Two Coils	Electrical Malfunction Other	31 8
Advisories	None	Steroid	Yes	Other	Ü

System Longevity Study Results

Qualifying Complications 3 Total

Number of Leads Enrolled in Study	170	Oversensing	2
Cumulative Months of Follow-Up	6 374	Unspecified Clinical Failure	1



6945 Sprint

Product Characteristics

777	pprint			Product Charact	teristics						
	US Market Release	Sep-97		Serial Number Pre	efix TI)A			Returned Pro	duct Anal	vsis
	Estimated US Implants	44,000		Type and/or Fixati		Transvenous, Vent, Defib and Pace/Sense, Screw-in			Implant Damage		
	Estimated US Active	21,800		Polarity Integrated Bipolar/Two Coils			Electrical Malf	unction Other	9(1		
	Advisories	None		Steroid	roid Yes					Other	
tem l	ongevity Study Result:	5		Qı	ualifying C	omplications	20 Total				
	Number of Leads Enrolle	ed in Study	1,158		Cond	uctor Fracture	2	ı	mpedance Ou	of Range	2
	Cumulative Months of Fo	ollow-Up	51,615			ac Stimulation	1			ersensing	9
	cumulative Months of Follow-op					ure to Capture ailure to Sense	1 4	Uı	nspecified Clini	cal Failure	
100											
90 80 %								4			
80											
(0 1	2	3	4 5	-	6	7	8	9	10	
	Years After Implant										
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo		
%	99.6	99.1	99.0	98.3	97.4	96.9	96.9	95.5	95.5		
#	912	746	623	489	383	274	153	58	47		
	Effective Sample Size										

6947 Sprint Quattro Secure

Product Characteristics

	US Market Release	Nov-01		Serial Number	Prefix	TDG			Returned	Product Ana	lvsis
	Estimated US Implan	ts 130,500		Type and/or F	ixation	Transvenous, Ven Pace/Sense, Screv			Impla	int Damage	228
	Estimated US Active	92,300		Polarity		True Bipolar/Two	Coils		Electrical I	Malfunction Other	90 12
	Advisories	None		Steroid		Yes				Other	12
System	Longevity Study Res	ults			Qualifyi	ng Complications	15 Total				
	Number of Leads Enr	olled in Study	1,354		(Conductor Fracture	2		Lead	Dislodgement	3
	Cumulative Months o	f Follow-Up	45,712		lana a	Failure to Sense	1			Oversensing	5
				In		dance Out of Range ot further defined)	1		Unspecified	Clinical Failure	2
~ 100											
% > 90											
Lead Survival Probability (%) %											
Prob	0 1	2	3	4	5	6 7	7	8	9	10	
vival	Years After Implan	t									
Sur	1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo					
% eac	99.3	99.2	98.8	98.3	98.3	98.3					
- #	1,059 Effective Sample Size	906	652	320	82	40					

6948 Sprint Fidelis

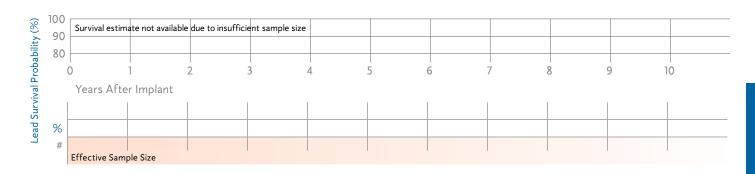
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	Returned Product Anal	vsis
Estimated US Implants	9,500	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	8
Estimated US Active	8,500	Polarity	True Bipolar/Two Coils	Electrical Malfunction Other	5 3
Advisories see page 159 – 2007 Poter Conductor Wire Fracture		Steroid	Yes	Other	,

System Longevity Study Results

Qualifying Complications 0 Total

24 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 328



6949 Sprint Fidelis

Product Characteristics

654

US Market Release	Sep-04	Serial Number Prefix	LFJ	Returned Product An	alvsis
Estimated US Implants 174,600		Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	420
Estimated US Active	152,100	Polarity	True Bipolar/Two Coils	Electrical Malfunction Other	468 38
Advisories see page 159 – 2007 Pote Conductor Wire Fracture		Steroid	Yes		

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 9 Total **Conductor Fracture**

		Cumulative I	Months of Fol	low-Up	9,894							
(%)	100											
ity (90			<u> </u>								
obability	80											
Pro	()	1 :	2	3	4	5	6	7	3 !	9 1	0
viva		Years Afte	r Implant									
Sur			1 yr	2 yr	at 30 mo							
-ead	%		98.8	98.4	97.7							
_	#		315	130	44							
		Effective Sam	ple Size									

Oversensing

6996 Sub-Q Lead

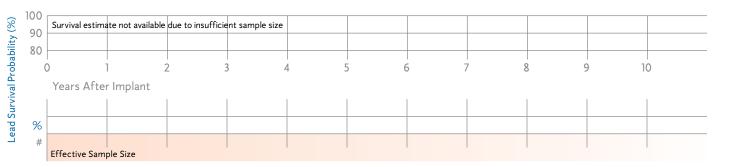
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	TCR	Returned Product Analy	vsis
Estimated US Implants	2,200	Type and/or Fixation	Subcutaneous Defib Coil, Suture		,
Estimated US Active	1,800	Polarity	One Defib Coil	Implant Damage Electrical Malfunction	0
Advisories	None	Steroid	No	Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	12
Cumulative Months of Follow-Up	182



Lead Survival Summary (95% Confidence Interval)

				ons	Cumulative Months of Follow-Up in Study	Device S	Survival Pr	obability	(%)						
Model Number	Family	US Market Release	Leads Enrolled	Qualifying Complications	nulativ ollow-l tudy		fter Impla								
N Z	Fan	NS Rel	Lea	ទីទី	of F	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr
6721, 6921	Epicardial Patch	Feb-93	407	28	18,070	100.0	98.6 +0.9/-2.3	96.0 +1.9/-3.3	95.0 +2.1/-3.8	91.6 +3.2/-4.9	84.3 +5.0/-7.0	81.9 +5.6/-7.7	81.9 +5.6/-7.7		
6930	Sprint Fidelis	Jun-04	1	-	4	Survival es	timate not	available due	to insuffic	ient sample	size				
	Advisories: S			Potentia	al										
6931	Sprint Fidelis	Sep-04	212	1	2,195	99.5 +0.4/-3.0									
	Advisories: s Conductor W			Potentia	al										
6932	Sprint	Aug-96	410	8	19,557	99.4 +0.4/-1.8	98.4 +0.9/-2.3	98.4 +0.9/-2.3	98.4 +0.9/-2.3	97.7 +1.3/-2.8	97.7 +1.3/-2.8	97.7 +1.3/-2.8	96.4 +2.1/-5.1	96.4 +2.1/-5.1 at 99 mo	
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	966	23	47,123	99.6 +0.3/-0.8	99.2 +0.4/-1.0	99.2 +0.4/-1.0	98.6 +0.7/-1.4	97.0 +1.2/-2.0	96.4 +1.4/-2.2	95.2 +1.8/-2.8	94.6 +2.0/-3.1	92.8 +2.8/-4.6	92.8 +2.8/-4.6 at 141 mo
6936, 6966	Transvene	Dec-93	1,349	143	66,656	99.2 +0.4/-0.7	98.4 +0.6/-1.0	97.0 +0.9/-1.3	96.0 +1.1/-1.6	92.8 +1.7/-2.2	87.5 +2.4/-3.1	79.5 +3.5/-4.0	75.5 +3.9/-4.5	66.6 +5.0/-5.6	63.1 +5.7/-6.5 at 141 mo
6939, 6999	Sub-Q Patch	Dec-93	384	20	17,668	99.1 +0.6/-2.0	98.7 +0.8/-2.3	98.2 +1.1/-2.6	98.2 +1.1/-2.6	94.2 +2.6/-4.8	91.2 +3.5/-5.7	87.8 +4.6/-7.0	84.7 +5.6/-8.6		
6942	Sprint	Jul-97	352	7	14,621	98.9 +0.8/-2.2	98.9 +0.8/-2.2	97.8 +1.3/-3.1	97.2 +1.5/-3.6	96.3 +2.0/-4.2	96.3 +2.0/-4.2	96.3 +2.0/-4.2	96.3 +2.0/-4.2 at 87 mo		
6943	Sprint	Oct-97	1,309	45	60,060	98.8 +0.5/-0.8	98.1 +0.6/-1.0	97.1 +0.8/-1.3	96.5 +1.0/-1.4	95.3 +1.3/-1.7	94.8 +1.4/-2.0	94.8 +1.4/-2.0	94.1 +1.8/-2.5	94.1 +1.8/-2.5 at 99 mo	
6944	Sprint Quattro	Dec-00	170	3	6,374	100.0	100.0	98.9 +0.9/-6.6	97.5 +1.9/-7.2	95.8 +2.8/-8.6 at 54 mo					
6945	Sprint	Sep-97	1,158	20	51,615	99.6 +0.2/-0.7	99.1 +0.5/-0.9	99.0 +0.5/-1.0	98.3 +0.7/-1.2	97.4 +1.0/-1.6	96.9 +1.1/-1.9	96.9 +1.1/-1.9	95.5 +2.2/-4.1	95.5 +2.2/-4.1 at 99 mo	
6947	Sprint Quattro Secure	Nov-01	1,354	15	45,712	99.3 +0.3/-0.7	99.2 +0.4/-0.7	98.8 +0.5/-0.9	98.3 +0.7/-1.2	98.3 +0.7/-1.2	98.3 +0.7/-1.2 at 63 mo				
6948	Sprint Fidelis	Sep-04	24	0	328	Survival es	timate not	available due	to insuffic	ient sample	size				
	Advisories: s Conductor W			Potentia	al										
6949	Sprint Fidelis	Sep-04	654	9	9,894	98.8 +0.7/-1.5	98.4 +0.9/-1.8	97.7 +1.3/-3.0 at 30 mo							
	Advisories: s Conductor W			Potentia	ıl										
6996	Sub-Q Lead	Jun-01	12	0	182	Survival es	timate not	available due	to insuffic	ient sample	size				

Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
6721, 6921	Epicardial Patch	Feb-93	9,000	2,100	5	79	0
6930	Sprint Fidelis	Jun-04	300	300	0	0	0
6931	Sprint Fidelis	Sep-04	7,100	6,300	19	39	0
6932	Sprint	Aug-96	15,300	6,500	16	37	7
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	17,400	5,600	31	192	13
6936, 6966	Transvene	Dec-93	24,600	5,900	90	457	19
6939, 6999	Sub-Q Patch	Dec-93	4,300	900	4	32	1
6942	Sprint	Jul-97	18,100	8,300	31	37	5
6943	Sprint	Oct-97	21,300	9,900	50	63	8
6944	Sprint Quattro	Dec-00	28,600	18,700	23	31	8
6945	Sprint	Sep-97	44,000	21,800	197	90	11
6947	Sprint Quattro Secure	Nov-01	130,500	92,300	228	90	12
6948	Sprint Fidelis	Sep-04	9,500	8,500	8	5	3
6949	Sprint Fidelis	Sep-04	174,600	152,100	420	468	38
6996	Sub-Q Lead	Jun-01	2,200	1,800	0	2	0

Reference Chart

Model			Pin Conf	figuration	Lead Body	Insulation,			
Number	Family	Туре	Pace/ Sense	High Voltage	Diameter	Lead Body	Fixation, Steroid		
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture		
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture		
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid		
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid		
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid		
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive		
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid		
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active		
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive		
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive		
6939	Sub-Q Patch	SQ Patch	-	DF-1	One Size	Silicone, Single Lumen	Suture		
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid		
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid		
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid		
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid		
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid		
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid		
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid		
6963	SVC/CS	Endo SVC/CS Coil	-	6.5 mm	7 Fr	Silicone, Single Lumen	Passive		
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active		
6996	Sub-Q Lead	SQ Coil	-	DF-1	7.5 Fr	Silicone, Single Lumen	Passive		
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture		

Pacing Leads

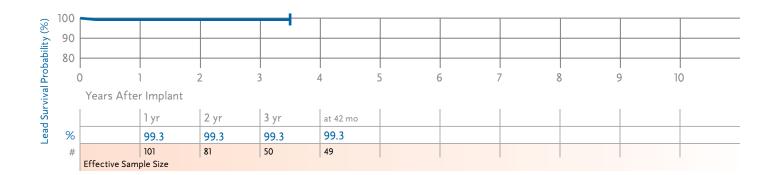
3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	Serial Number Prefix LFF		sis
Estimated US Implants	7,300	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	6,500	Polarity	Bipolar	Implant Damage Electrical Malfunction	13 1
Advisories	None	Steroid	Yes	Other	i

Atrial Placement

Qualifying Complications System Longevity Study Results 1 Total Number of Leads Enrolled in Study 142 Failure to Sense Cumulative Months of Follow-Up 4,285

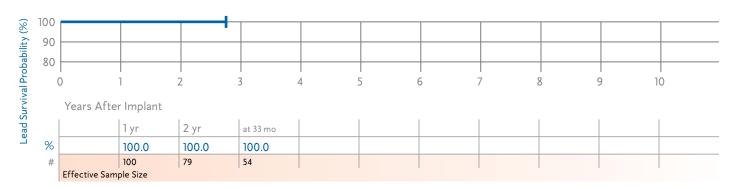


Ventricular Placement

System Longevity Study Results

Qualifying Complications 0 Total

135 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 4,241



4003, 4003M CapSure

Product Characteristics

US Market Release	Jul-86	Serial Number Prefix	IH or LAX	Returned Product Analysis
Estimated US Implants	40,000	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	7,100	Polarity	Unipolar	Implant Damage 24 Electrical Malfunction 57
Advisories	None	Steroid	Yes	Other 2

Ventricular Placement

System Longevity Study Results

Qualifying Complications 10 Total

Number of Leads Enrolled in Study	711	Extra Cardiac Stimulation	2
Cumulative Months of Follow-Up	44.869	Failure to Capture	6
	,	Oversensing	2



4004, 4004M CapSure

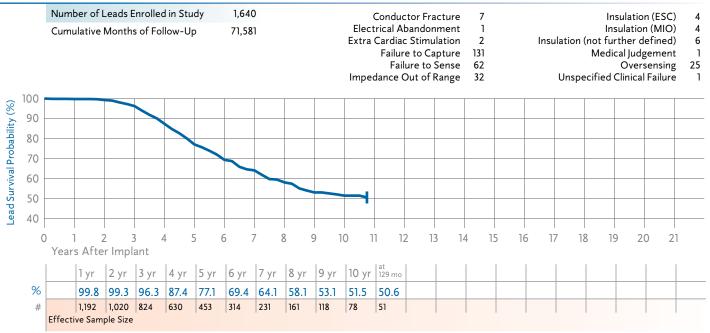
Product Characteristics

US Market Release	Feb-89	Serial Number Prefix	PS or LAV	Returned Product Anal	lv
Estimated US Implants	74,500	Type and/or Fixation	Transvenous, Vent., Tines		_
Estimated US Active	2,800	Polarity	Bipolar	Implant Damage Electrical Malfunction	
Advisories	1	Steroid	Yes	Other	
see page 165 – 1993 Lead	Survival				
Below Expectations					

Ventricular Placement

System Longevity Study Results

Qualifying Complications 276 Total



4011 Target Tip

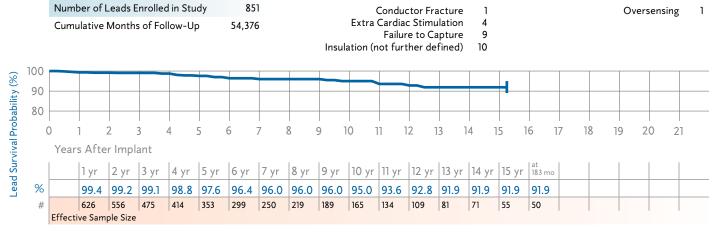
Product Characteristics

US Market Release	Nov-82	Serial Number Prefix	IB	Returned Product Analysis
Estimated US Implants	64,000	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	7,200	Polarity	Unipolar	Implant Damage 29 Electrical Malfunction 141
Advisories	None	Steroid	No	Other 5

Ventricular Placement

System Longevity Study Results

Qualifying Complications 25 Total



4012 Target Tip

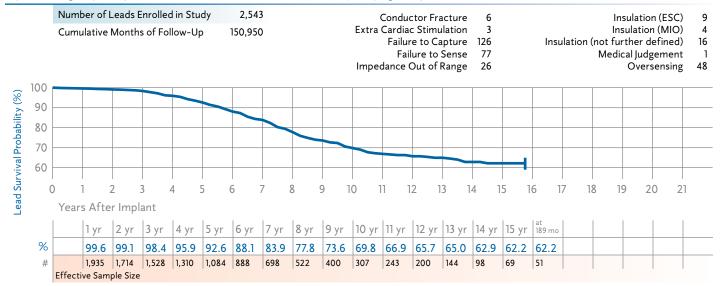
Product Characteristics

US Market Release	Jul-83	Serial Number Prefix	HQ	Returned Product An
Estimated US Implants	96,800	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	5,700	Polarity	Bipolar	Implant Damage Electrical Malfunction
Advisories	1	Steroid	No	Other
see page 166 – 1991 Lead S Below Expectations	Survival			

Ventricular Placement

System Longevity Study Results

Qualifying Complications 316 Total



4023 CapSure SP

Product Characteristics

US Market Release	S Market Release Aug-91		LAK	Returned Product Analysis				
Estimated US Implants	43,700	Type and/or Fixation	Transvenous, Vent., Tines					
Estimated US Active	14,900	Polarity	Unipolar	Implant Damage Electrical Malfunction	48 19			
Advisories	None	Steroid	Yes	Other	6			

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 19 Total

		Numb	ber of L	_eads E	nrolled	l in Stu	dy	1,158	3	Extra Cardiac Stimulation			1			Lead Dislodgement			ent 2					
		Cumu	ulative	Month	s of Fol	low-Up)	60,527	•		Insula	Imped ation (n	dance (e to Ca Out of I her de	Range	14 1 1								
(%)	100																					\top		-
	90																					-		-
Probability	80																							
Pro	() 1	1 2	2 3	3 4	1 5	5 6	5 7	7 8	3 9) 1() 1	1 1:	2 1:	3 14	4 15	16	17	7 18	3 19	9 2	20	21	
vival		Year	s Afte	r Impl	ant																			
ead Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr											
-eac	%		99.9	99.3	98.8	98.6	98.6	98.2	97.1	96.7	96.7	95.6	94.1											
_	#		886	765	683	602	504	352	245	175	91	67	49											
		Effecti	ve Sam	ple Size																				

4024 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAJ	Returned Product Analysis
Estimated US Implants	229,200	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	84,600	Polarity	Bipolar	Implant Damage 264 Electrical Malfunction 103
Advisories	None	Steroid	Yes	Other 34

Ventricular Placement

System Longevity Study Results

Qualifying Complications 3 Total

Number of Leads Enrolled in Study	1,215	Failure to Capture
Cumulative Months of Follow-Up	51.157	



4033 CapSure Z

Product Characteristics

US Market Release	not US released	Serial Number Prefix	LCA	Returned Product Analy	vsis
Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	n/a	Polarity	Unipolar	Implant Damage Electrical Malfunction	2
Advisories	None	Steroid	Yes	Other	Ö

Ventricular Placement

System Longevity Study Results Qualifying Complications 9 Total

Number of Leads Enrolled in Study	541	Conductor Fracture	1
Cumulative Months of Follow-Up	28.053	Failure to Capture	8



4057, 4057M Screw-In

Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	XQ or LAN	Returned Product Analysis
Estimated US Implants	12,100	Type and/or Fixation	Transvenous, V or A, Screw-in	,
Estimated US Active	2,800	Polarity	Unipolar	Implant Damage 39 Electrical Malfunction 6
Advisories	None	Steroid	No	Other 4

Ventricular Placement

System Longevity Study Results 7 Total **Qualifying Complications**

Number of Leads Enrolled in Study Cumulative Months of Follow-Up	259 15,216	Conductor Fracture 2 Extra Cardiac Stimulation 2 Failure to Capture 2 Failure to Sense 1



4058, 4058M Screw-In

Product Characteristics

US Market Release	Jan-89	Serial Number Prefix	ZY or LAW	Returned Product Analysis
Estimated US Implants	111,100	Type and/or Fixation	Transvenous, V or A, Screw-in	,
Estimated US Active	25,900	Polarity	Bipolar	Implant Damage 388 Electrical Malfunction 228
Advisories	None	Steroid	No	Other 23

Atrial Placement

Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 32 Total

	5	,	0.0.)							*	J. J.	5				- · · · ·												
					d in Stu llow-Up	,	2,363 131,020					Failur Fail	c Stimu e to Ca lure to : Out of I	pture Sense	1 15 7 4		Insu	lation	•	d Disl	er defir odgem versen	nent	1 3 1					
100					_																							
90															-						_	_						
80																												
					1																I							
() 1		2	3	4	5 (5 7	7	3 !	9 1	0 1	1 1	2 1	3 1	4 1.	5 10	5 1	7 1	8	19	20	21						
	Years	Afte	r Impl	ant																								
					L	l_	1	-			120	1	120	122	1.4	at		ı	ı	1	1							
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	/ yr	8 yr	9 yr	10 yr	II yr	IZ yr	13 yr	14 yr	174 mo												
%		99.9	99.6	99.5	99.1	98.7	98.3	98.2	97.5	97.5	96.1	96.1	96.1	95.1	95.1	95.1												
#		1,756	1,547	1,336	1,156	993	791	611	457	338	223	158	118	88	57	48												
	Effecti	ve Samı	ple Size																									

Ventricular Placement

System Longevity Study Results

Qualifying Complications 50 Total

						•					Cardiac Failur	Stimu e to Ca	lation pture	3 3 22 10		Insu		(not	furth ad Dis	er defii lodgen	ned) nent	6 4 1 1
Yoars	2 After) 3		4 !	5 (5 7	7 8	8 9) 10	0 1	1 12	2 1	3 14	4 15	16	5 1	7	18	19	20	21	
!	l yr 99.4	2 yr 99.2	3 yr 99.1	4 yr	5 yr	6 yr		8 yr	-			86.6	85.2									
	Cumul 1 Years	Cumulative N	Cumulative Months 1 2 3 Years After Impla 1 yr 2 yr 99.4 99.2	Cumulative Months of Fol	Cumulative Months of Follow-Up 1 2 3 4 ! Years After Implant 1 yr 2 yr 3 yr 4 yr 99.4 99.2 99.1 98.7	Cumulative Months of Follow-Up 1 2 3 4 5 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 99.4 99.2 99.1 98.7 97.9	Cumulative Months of Follow-Up 76,590 1 2 3 4 5 6 7 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 99.4 99.2 99.1 98.7 97.9 96.9	Cumulative Months of Follow-Up 76,590 1 2 3 4 5 6 7 8 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 99.4 99.2 99.1 98.7 97.9 96.9 94.6	Cumulative Months of Follow-Up 76,590 1 2 3 4 5 6 7 8 9 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6	Cumulative Months of Follow-Up 76,590 1 2 3 4 5 6 7 8 9 10 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5	Cumulative Months of Follow-Up 76,590 Extra 0 1 2 3 4 5 6 7 8 9 10 1 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8	Cumulative Months of Follow-Up 76,590 Extra Cardiac Failur Fail 1 2 3 4 5 6 7 8 9 10 11 12 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8 89.0	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimu Failure to Cardiac Failure to	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation Failure to Capture Failure to Sense 1 2 3 4 5 6 7 8 9 10 11 12 13 14 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 14/17 mo 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8 89.0 86.6 85.2	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 22	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr at 147 mo 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8 89.0 86.6 85.2	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 Insufficient	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 Insulation 3 Failure to Sense 10 Insulation 10 Failure to Sense 10 Insulation	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 Insulation (not Less Failure to Sense 10 Less Failure to Sense 10 Sense 10 Insulation (not Less Failure to Sense 10 Sens	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 Co 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 147 mo 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8 89.0 86.6 85.2	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture 22 Failure to Sense 10 Insulation (not further defined Dislodgen Oversen Sense 10 Sense 1	Cumulative Months of Follow-Up 76,590 Extra Cardiac Stimulation 3 Failure to Capture Failure to Sense 10 Insulation (not further defined) Lead Dislodgement Oversensing 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 14 mo 99.4 99.2 99.1 98.7 97.9 96.9 94.6 93.6 91.5 89.8 89.0 86.6 85.2

4067 CapSureFix

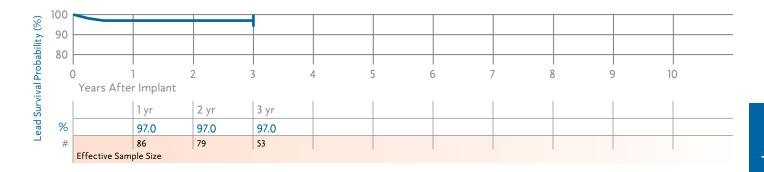
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LCV	Returned Product Analysis
Estimated US Implants	1,300	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	500	Polarity	Unipolar	Implant Damage 3 Electrical Malfunction 1
Advisories	None	Steroid	Yes	Other 1

Atrial Placement

System Longevity Study Results **Qualifying Complications** 6 Total

Number of Leads Enrolled in Study	108	Failure to Capture	5
Cumulative Months of Follow-Up	5 877	Oversensing	1



4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	Returned Product Analy	vsis
Estimated US Implants	131,700	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	57,500	Polarity	Bipolar	Implant Damage Electrical Malfunction	406 81
Advisories	None	Steroid	Yes	Other	11

Atrial Placement

Lead Survival Probability (%)

Lead Survival Probability (%)

System Longevity Study Results

Oualifying Complications 48 Total

stem	Longe	vity St	uay Re	esuits						Ų	ualityi	ng Co	mplica	ations	48 I	otal							
			_eads E Months			,	2,40 114,150				Extra		Stimi e to Ca ure to	ulation apture Sense	1 1 19 11 2			Unspe		ad Dis O	ation (lodger verser iical Fa	nent ising	2 8 3 1
100 90 80) Year	l 2	2 3	, -	1	5 6	5 7	7 {	3)](0 1	1 12	2 1	3 14	15	5 16	5 1	7 1	8	19	20	21	
% #		1 yr 99.0 1,897	2 yr 98.8 1,620 ple Size	3 yr 98.3 1,352	98.0 1,067	5 yr 97.5 782	6 yr 97.4 537	7 yr 97.2 385	8 yr 96.4 269		10 yr 96.0 68												<u> </u>

Ventricular Placement

System Longevity Study Results

Qualifying Complications 32 Total

	-ongevity of	tud) ites	uits.			Y dam jing	Complication	32 100	32 10101			
	Number of Leads Enrolled in Study Cumulative Months of Follow-Up		ulative Months of Follow-Up 81,140 Extra Cardiac Failure			nductor Fractur rdiac Stimulatio ailure to Captur Failure to Sens	c Stimulation 2 re to Capture 19 lure to Sense 3					
100						Impedar	oce Out of Rang Oversensin			—		
80												
() Years Afte	1 er Implan	2 nt	3	4	5	6	7	8	9	10	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 114 mo	

		'									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 114 mo
%		99.3	98.8	98.8	98.4	98.0	97.6	96.6	96.0	93.7	93.7
#		1,426	1,215	1,034	764	548	339	209	111	72	53
	Effective Sam	ple Size									

4073 CapSure Sense

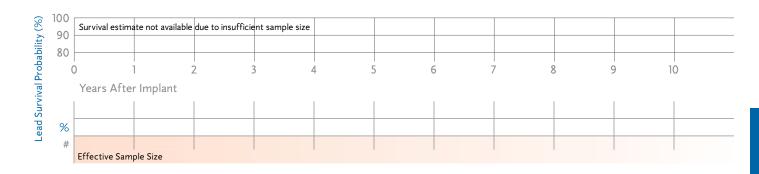
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	Returned Product Analysis
Estimated US Implants	500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	400	Polarity	Unipolar	Implant Damage 1 Electrical Malfunction 0
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

System Longevity Study Results **Qualifying Complications** 0 Total

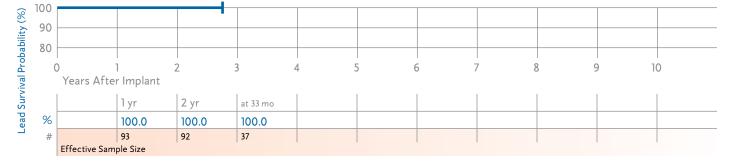
Number of Leads Enrolled in Study Cumulative Months of Follow-Up 34



Ventricular Placement

Qualifying Complications System Longevity Study Results

> Number of Leads Enrolled in Study 99 Cumulative Months of Follow-Up 3,300



0 Total

4074 CapSure Sense

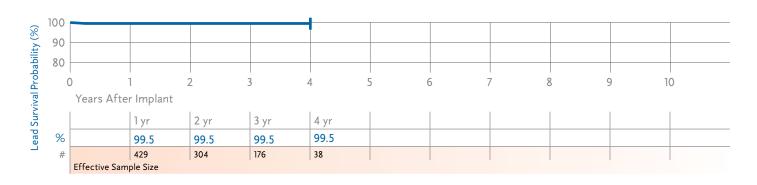
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBD	Returned Product Analysis
Estimated US Implants	48,500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	38,700	Polarity	Bipolar	Implant Damage 12 Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 1

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 3 Total

umber of Leads Enrolled in Study	611	Failure to Sense	
Cumulative Months of Follow-Up	15,441	Lead Dislodgement	2



4076 CapSureFix Novus

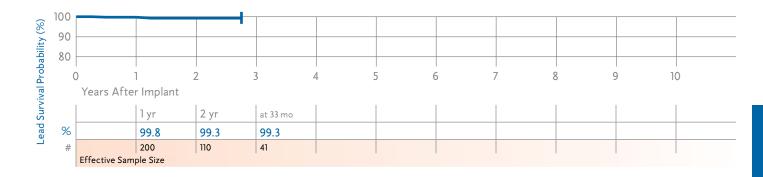
Product Characteristics

US Market Release	Feb-04	Serial Number Prefix	BBL	Returned Product Ana	lvsis
Estimated US Implants	120,600	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	104,700	Polarity	Bipolar	Implant Damage Electrical Malfunction	51 3
Advisories	None	Steroid	Yes	Other	5

Atrial Placement

System Longevity Study Results **Qualifying Complications** 2 Total

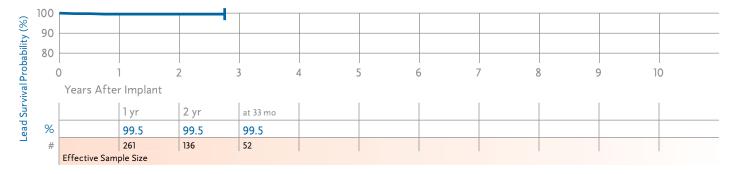
Number of Leads Enrolled in Study	512	Failure to Capture	1
Cumulative Months of Follow-Up	7.482	Lead Dislodgement	1



Ventricular Placement

Qualifying Complications System Longevity Study Results 2 Total

Number of Leads Enrolled in Study	507	Failure to C
Cumulative Months of Follow-Up	8,765	



4081 Target Tip

Product Characteristics

US Market Release	Jul-89	Serial Number Prefix	LAC	Returned Product Analys	sis
Estimated US Implants	4,100	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	900	Polarity	Unipolar	Implant Damage Electrical Malfunction	4 5
Advisories	None	Steroid	No	Other	0

Ventricular Placement

System Longevity Study Results

Qualifying Complications 3 Total

Number of Leads Enrolled in Study 260 **Conductor Fracture** 2 Failure to Sense Cumulative Months of Follow-Up 9,783



4092 CapSure SP Novus

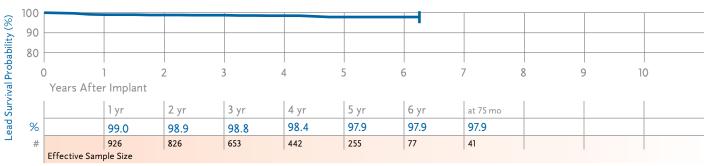
Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEP	Returned Product Anal	vsis
Estimated US Implants	139,700	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	90,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	32 11
Advisories	None	Steroid	Yes	Other	5

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 16 Total

Number of Leads Enrolled in Study	1,144	Conductor Fracture	2
Cumulative Months of Follow-Up	46,393	Extra Cardiac Stimulation Failure to Capture	1 8
		Impedance Out of Range	1



4503, 4503M CapSure

Product Characteristics

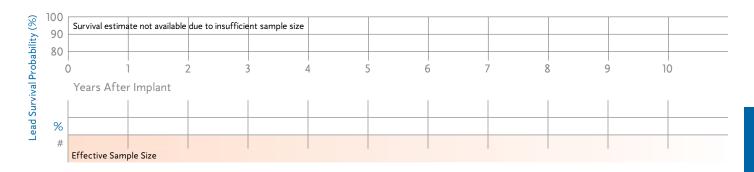
US Market Release	Jul-86	Serial Number Prefix	MQ, LAY	Returned Product Anal	vsis
Estimated US Implants	9,000	Type and/or Fixation	Transvenous, Atrial-J, Tines		,
Estimated US Active	1,400	Polarity	Unipolar	Implant Damage Electrical Malfunction	2 11
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

System Longevity Study Results Qualifying Complications

Number of Leads Enrolled in Study	59	Failure to Sense	1
	2.772		

Cumulative Months of Follow-Up 3,179



4504, 4504M CapSure

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	QM or LBA	Returned Product Analysis
Estimated US Implants	16,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	,
Estimated US Active	1,600	Polarity	Bipolar	Implant Damage 5 Electrical Malfunction 171
Advisories	1	Steroid	Yes	Other 4
	Survival			
see page 164 – 1996 Lead Below Expectations	Survival	Steroid	163	Other

Atrial Placement

System Longevity Study Results Qualifying Complications 48 Total

		Leads Enrolled Months of Fo	,	368 19,861		Extra Car Fa	al Abandonment diac Stimulation ailure to Capture Failure to Sense	3 1 14 16	II	mpedance Out o Insulatio Lead Disloo Ove	on (MIŎ)	9 1 1 3
t (9))											
sabili 80)											
2 70)									1		
Survival Probability (%) 80 70 60)									1		
d Sur	0		2	3	4	5	6	7	8	9	10	
Lead	Years Afte	er Implant										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 105 mo		
%	5	100.0	100.0	99.1	98.2	90.3	82.2	73.0	69.9	66.1		
#	<i>‡</i>	294	260	220	186	145	109	74	59	47		
	Effective San	nple Size										

4512 Target Tip

Product Characteristics

US Market Release	Jul-83	Serial Number Prefix	PF	Returned Product Anal	lysis
Estimated US Implants	11,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damaga	,
Estimated US Active	1,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	83
Advisories	None	Steroid	No	Other	8

Atrial Placement

Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 35 Total

sterri	Longe	vity St	uay Re	esuits						Ų	ualityi	ng Co	mpiica	tions	35 I	otai							
		ber of I ulative				•	600 39,749					Failur Fail dance (bandon e to Ca ure to ! Out of I ulation	pture Sense Range	1 6 14 3 2		Insu	ılation	(not	furthe Id Disl	tion (M er defin odgem versens	ed) ent	4 2 1 2
100 90 80	0	1 :	2 :	3	4	5	6 7	7 8	8	9 1	0 1	1 1	2 1	H	4 1	5 10	6 1	7	18	19	20	21	
	Year	s Afte	r Impl	ant 3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 159 mo								
%		99.6	99.6	99.1	98.0	96.7	95.6	94.7	91.5	89.7	87.5	84.8	84.8	83.6	83.6								
#	-cc	454	410	370	326	272	224	190	157	129	105	88	71	53	49								

4523 CapSure SP

Effective Sample Size

Number of Leads Enrolled in Study

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	ZE	Returned Product Analysis
Estimated US Implants	12,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	3,500	Polarity	Unipolar	Implant Damage 5 Electrical Malfunction 2
Advisories	None	Steroid	Yes	Other 1

Impedance Out of Range

Atrial Placement

Lead Survival Probability (%)

System Longevity Study Results **Qualifying Complications** 4 Total 121

	Cumulative	Months of Fo	llow-Up	6,967		Lead I	Dislodgement Oversensing	2			
100		1						T	ı		
90					1						
80											
() Years Afte	1 r Implant	2	3	4	5	6	7 8	3	9 1	0
		1 yr	2 yr	3 yr	4 yr	at 57 mo					
%		98.1	98.1	98.1	98.1	98.1					
#		95	81	71	58	50					

Effective Sample Size

4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	Returned Product Analysis
Estimated US Implants	106,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	38,200	Polarity	Bipolar	Implant Damage 47 Electrical Malfunction 21
Advisories	None	Steroid	Yes	Other 8

Atrial Placement

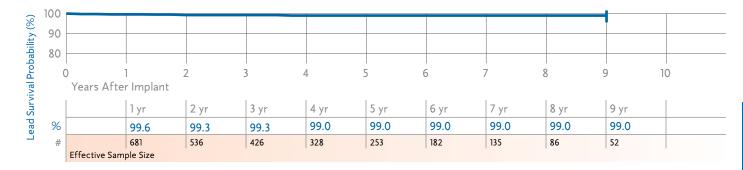
System Longevity Study Results

Qualifying Complications 6 Total

Number of Leads Enrolled in Study 910

Failure to Capture 3

Number of Leads Enrolled in Study910Failure to Capture3Cumulative Months of Follow-Up38,794Failure to Sense2Lead Dislodgement1



4533 CapSure Z

Product Characteristics

US Market Release	not US released	Serial Number Prefix	LCB	Returned Product Analys	sis
Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	n/a	Polarity	Unipolar	Implant Damage Electrical Malfunction	0
Advisories	None	Steroid	Yes	Other	Ö

Atrial Placement

	Longevity St	udy Results				Qualifying	Complications	4 Total			
		eads Enrolled	,	206 11,038		Fa	1				
						Lea	d Dislodgement Oversensing	1			
§ 100 § 90											
ability 08											
ğ	0 Years Afte		2	3	4	5	6	7	8	9	10
Survi		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 78 mo			
% ad		100.0	99.4	98.8	97.9	97.9	97.9	97.9			
# #		176	158	132	101	77	60	51			
	Effective Sam	ple Size									

4557, 4557M Screw-In

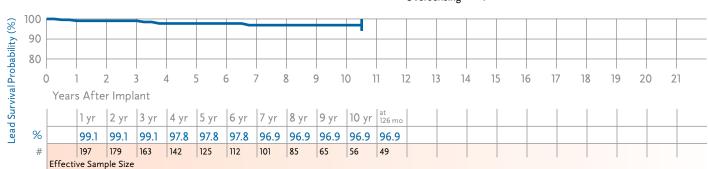
Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	VQ or LAM	Returned Product Analy	/sis
Estimated US Implants	22,500	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	5,200	Polarity	Unipolar	Implant Damage Electrical Malfunction	53 14
Advisories	None	Steroid	No	Other	4

Atrial Placement

System Longevity Study Results **Qualifying Complications** 6 Total

Number of Leads Enrolled in Study	294	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	18,286	Failure to Capture Failure to Sense Oversensing	3 1 1



4558M Screw-In

Product Characteristics

US Market Release	Nov-94	Serial Number Prefix	LDC	Returned Product Ana	lysis
Estimated US Implants	21,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	6,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	111 11
Advisories	None	Steroid	No	Other	1

Atrial Placement

System Longevity Study Results **Qualifying Complications** 11 Total

Number of Leads Enrolled in Study	539	Electrical Abandonment	1	Oversensing	2
Cumulative Months of Follow-Up	21,989	Failure to Capture Failure to Sense Impedance Out of Range Insulation (not further defined)	3 2 2	Ü	



4568 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDD	Returned Product Ana	alvsis
Estimated US Implants	72,800	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	37,900	Polarity	Bipolar	Implant Damage Electrical Malfunction	197 6
Advisories	None	Steroid	Yes	Other	4

Atrial Placement

System Longevity Study Results

Qualifying Complications 28 Total

Number of Leads Enrolled in Study	576	Failure to Capture	19
Cumulative Months of Follow-Up	20,494	Lead Dislodgement	8
'	•	Medical Judgement	1



4574 CapSure Sense

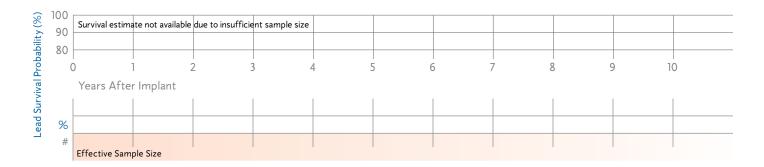
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBE	Returned Product Analysis
Estimated US Implants	31,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	24,600	Polarity	Bipolar	Implant Damage 6 Electrical Malfunction 1
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

System Longevity Study Results **Qualifying Complications** 0 Total

Number of Leads Enrolled in Study	5
Cumulative Months of Follow-Up	116



4592 CapSure SP Novus

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	LER	Returned Product Analy	/sis
Estimated US Implants	70,800	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	44,500	Polarity	Bipolar	Implant Damage Electrical Malfunction	12 3
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

System Longevity Study Results

Qualifying Complications 5 To	Qualifying	${\color{blue}Complications}$	5	To
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otal

Number of Leads Enrolled in Study	243	Failure to Capture	2
Cumulative Months of Follow-Up	9.505	Failure to Sense	1
	-,	Lead Dislodgement	2



5023, 5023M CapSure SP

Number of Leads Enrolled in Study

Product Characteristics

US Market Release	Nov-88	Serial Number Prefix	SX or LAS	Returned Product Analysis
Estimated US Implants	10,600	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	2,900	Polarity	Unipolar	Implant Damage 15 Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other 0

Conductor Fracture

Ventricular Placement

Qualifying Complications System Longevity Study Results 10 Total 1,351

	Cumulative	Months of Fol	low-Up	62,593		Extra Cardiac Failur Impedance C	e to Capture	2 6 1			
100											
90									•		
80											
	0	 1	l 2 3	 2	l 1 5	l 5 (l -	l 7 8] }	 	 ∩
`	Years Afte	r Implant	_		Ť	,	,		, ,	, !	3
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 105 mo	
%		99.7	99.6	99.5	99.4	99.4	99.4	98.2	98.2	98.2	
#		1,049	921	773	605	452	306	190	100	51	

Effective Sample Size

Lead Survival Probability (%)

5024, 5024M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	SY or LAT	Returned Product Analysis
Estimated US Implants	211,400	Type and/or Fixation	Transvenous, Vent., Tines	,
Estimated US Active	72,800	Polarity	Bipolar	Implant Damage 723 Electrical Malfunction 106
Advisories	None	Steroid	Yes	Other 29

Ventricular Placement

System Longevity Study Results

Effective Sample Size

Oualifying Complications 45 Total

stem	Longe	evity St	uuy Ke	Suits				Qualifying Complications						45 1	otai								
Number of Leads Enrolled in Study Cumulative Months of Follow-Up						,	8,142 421,081				Extra (Cardiad Failur Fail	tor Fra Stimu e to Ca ure to S Out of F	lation pture Sense	3 2 24 2 2		Insu	lation ((not f	urthe d Disl	tion (E r defin odgem versens	ed) ent	1 5 5 1
. 100																							
90																				+		+	
80																							
00	'																						
	0	1 :	2 3	3 4	4 !	5 6	5 7	7 8	8 9	9 10	1 C	1 1	2 13	3 14	4 1.	5 16	5 17	7]	8	19	20	21	
	Year	rs Afte	r Impl	ant																			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr							
%		99.7	99.6	99.5	99.5	99.4	99.3	99.3	99.1	98.9	98.8	98.6	98.6	98.6	98.6	98.6							
#	ŧ	6,123	5,272	4,473	3,742	3,098	2,400	1,822	1,301	909	601	403	245	154	93	44							

5026 CapSure

Lead Survival Probability (%)

Product Characteristics

US Market Release	Feb-88	Serial Number Prefix	RZ	Returned Product Analysis
Estimated US Implants	7,800	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	1,300	Polarity	Bipolar	Implant Damage 60 Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other 1

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 4 Total

Number of Leads Enrolled in Study	168	Electrical Abandonment	1
Cumulative Months of Follow-Up	9.522	Failure to Capture	3



5033 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	Returned Product Analy	vsis
Estimated US Implants	2,500	Type and/or Fixation	Transvenous, Vent., Tines		_
Estimated US Active	1,000	Polarity	Unipolar	Implant Damage Electrical Malfunction	6 1
Advisories	None	Steroid	Yes	Other	3

Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 25 Total Cardiac Perforation

	Cumulative Months of Follow-Up 90,664						4	Conductor Fracture Failure to Capture Impedance Out of Range Insulation (not further defined) Lead Dislodgement						ture nge ned)	5 11 5 1 2									
00																								
90													1											
_																								
30																				+			_	
0)	1	2	3	4	5	6		7	8	9	10	11	12	13	14	1.	5 1	6	17	18	19	20	21
	Year	rs Af	ter In	nplan	it																			
	ı	1	1	1	1				1	1	1	1	Lat		1			1	1	1	1	1	1	1

	Year	s Afte	r Impla	ant													
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	126 mo					
%		99.7	99.6	99.1	99.0	98.7	98.3	97.7	97.1	96.0	96.0	96.0					
#		1,414	1,140	939	783	655	527	414	312	213	90	46					
	Effective Sample Size																

5034 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDF	Returned Product Analy	/sis
Estimated US Implants	58,700	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	23,000	Polarity	Bipolar	Implant Damage Electrical Malfunction	85 29
Advisories	None	Steroid	Yes	Other	11

Ventricular Placement

System Longevity Study Results Qualifying Complications 13 Total

1,901

		Number of Leads Enrolled in Study						1,596				(Conduc	tor Fra	cture	1			L	ead Dis	lodgen	nent	1
		Cumi	ılative I	Months	of Foll	low-Up)	78,752				Imped	Fail	e to Ca ure to S Out of F	Sense	9 1 1							
(9	100											4											
Lead Survival Probability (%)	90											•										_	
babil	80																					_	—
Pro	C)]	1 2	. 3	4	5	6	7	8	9	10) 11	12	2 13	3 14	15	16	17	18	19	20	21	
vival		Years	s Afte	r Impla	ant																		
Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 123 mo										
-ead	%		99.7	99.5	99.3	99.2	99.2	99.2	98.9	98.2	98.2	98.2	98.2										
_	#		1,271	1,054	883	706	550	447	310	206	135	67	41										
	Effective Sample Size																						

5054 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEH	Returned Product Analysis
Estimated US Implants	82,500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	50,000	Polarity	Bipolar	Implant Damage 40 Electrical Malfunction 13
Advisories	None	Steroid	Yes	Other 6

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 11 Total

Number of Leads Enrolled in Study	1,392	Failure to Capture	7
Cumulative Months of Follow-Up	53,726	Failure to Sense Impedance Out of Range Lead Dislodgement	1 1 2



5068 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	Returned Product Ana	alvsis
Estimated US Implants	108,000	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	52,300	Polarity	Bipolar	Implant Damage Electrical Malfunction	455 61
Advisories	None	Steroid	Yes	Other	15

Atrial Placement

System Longevity Study Results **Qualifying Complications** 5 Total

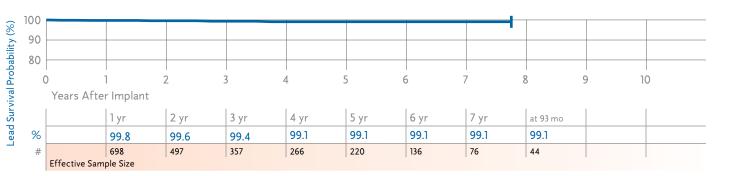
Number of Leads Enrolled in Study	969	Failure to Capture	2
Cumulative Months of Follow-Up	32,259	Impedance Out of Range Lead Dislodgement Oversensing	1 1 1



Ventricular Placement

System Longevity Study Results	Oualifying Complications	5 Total

Number of Leads Enrolled in Study	1,360	Conductor Fracture	1
Cumulative Months of Follow-Up	34.937	Failure to Capture	3
	,-	Lead Dislodgement	1



5072 SureFix

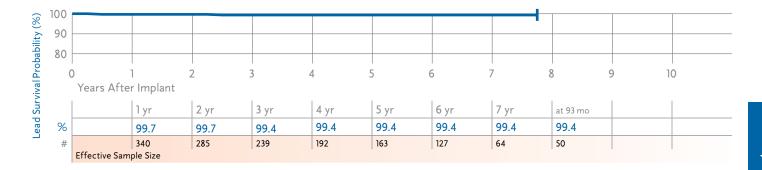
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEM	Returned Product Ana	lvsis
Estimated US Implants	8,900	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	5,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	26 4
Advisories	None	Steroid	Yes	Other	i

Atrial Placement

System Longevity Study Results **Qualifying Complications** 2 Total

Number of Leads Enrolled in Study	450	Cardiac Perforation	1
Cumulative Months of Follow-Un	20.567	Failure to Capture	1



5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	Returned Product Ana	alvsis
Estimated US Implants	838,700	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	625,300	Polarity	Bipolar	Implant Damage Electrical Malfunction	691 156
Advisories	None	Steroid	Yes	Other	51

Atrial Placement

System Longevity Study Results

Qualifying Complications 13 Total

Number of Leads Enr	olled in Study	2,466	Cardiac Perforation	1	Lead Dislodgement	3
Cumulative Months o	f Follow-Up	73,716	Conductor Fracture Extra Cardiac Stimulation	1 2	Oversensing	1
			Failure to Capture Impedance Out of Range	3		



Ventricular Placement

Lead Survival Probability (%)

System Longevity Study Results

Qualifying Complications 8 Total

		Leads Enrolle Months of Fo	,	1,507 44,927		Failur Fail	e Perforation e to Capture ure to Sense Out of Range	1 3 1		Lead Dislodg	gement 2	<u>!</u>
100						_	1	I		T		_
0.0						•						
90												_
80												_
							1					
(0	1	2	3	4	5	6	7 8	3	9 1	0	
	Years Afte	r Implant										
	ı	1	1	1	1	ı	I.	1	ı	1	ı	

	'		- ~	*		,		0	-	
	Years After	r Implant								
		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo			
%		99.6	99.4	99.4	99.2	99.2	99.2			
#		1,024	801	560	354	181	57			
	Effective Samp	ple Size								

5092 CapSure SP Novus

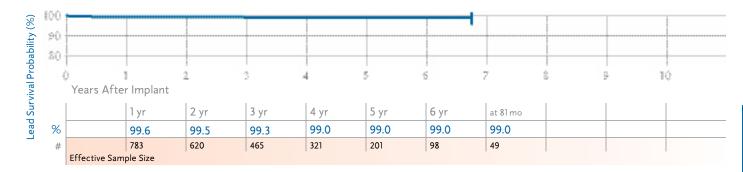
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	Returned Product Ana	lvsis
Estimated US Implants	105,900	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	68,400	Polarity	Bipolar	Implant Damage Electrical Malfunction	46 20
Advisories	None	Steroid	Yes	Other	11

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 8 Total

Number of Leads Enrolled in Study	1,171	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	37,536	Failure to Capture Lead Dislodgement	2 5



5524, 5524M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	Returned Product Analysis
Estimated US Implants	63,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	•
Estimated US Active	23,400	Polarity	Bipolar	Implant Damage 66 Electrical Malfunction 21
Advisories	None	Steroid	Yes	Other 7

Atrial Placement

Lead Survival Probability (%)

System Longevity Study Results Qualifying Complications 37 Total

	Num	ber of I	_eads E	nrolled	l in Stu	dy	4,433	3				Condu	ctor Fra	acture	1		Insulat	ion (no	t furth	er defin	ed)	2
	Cumi	ulative	Month	s of Fol	low-Up)	232,128	3			Impe	Fai	re to Ca lure to Out of I	Sense	22 4 1			L		lodgem versens		4
100									-					+				-			-	-
90											1						_	_	1		+	
80	-	-						-	-			-	-						-		-	-
. (,	1	2	3 .	4		5	1		9 1	0 1	11 1	2 1	3 1	4 15	16	17	18	19	20	23	
	Year	s Afte	r Impl	ant																		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 159 mo							
%		99.8	99.8	99.5	99.4	99.3	99.2	98.9	98.5	98.0	97.5	96.7	96.7	96.7	96.7							
#		3,384	2,923	2,506	2,107	1,751	1,340	993	693	492	327	198	121	55	47							
	Effect	ive Sam	ple Size																			

5534 CapSure Z

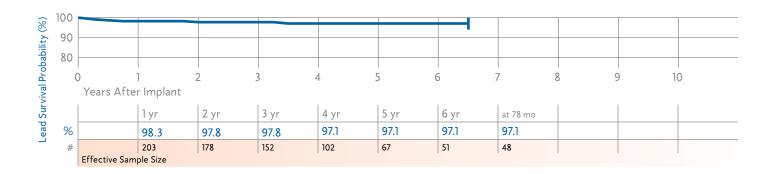
Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	Returned Product Anal	lvsis
Estimated US Implants	27,700	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	9,200	Polarity	Bipolar	Implant Damage Electrical Malfunction	29 6
Advisories	None	Steroid	Yes	Other	5

Atrial Placement

System Longevity Study Results **Qualifying Complications** 6 Total

Number of Leads Enrolled in Study	260	Failure to Capture	5
Cumulative Months of Follow-Up	12.319	Impedance Out of Range	1



5554 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEJ	Returned Product Anal	vsis
Estimated US Implants	53,000	Type and/or Fixation	Transvenous, Atrial-J, Tines		_
Estimated US Active	32,300	Polarity	Bipolar	Implant Damage Electrical Malfunction	7 6
Advisories	None	Steroid	Yes	Other	4

	Number of I	_eads Enrolle	d in Study	352		Fa	ilure to Capture	1			
	Cumulative	Months of Fo	illow-Up	15,861		Impedan	ce Out of Range d Dislodgement Oversensing	1 1 1			
00											
90											
80											
(0	1	2	3	4	5	6	7	8	9	10
	Years Afte	r Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 93 mo		
		100.0	99.1	98.6	98.0	98.0	98.0	98.0	98.0		
%		100.0	22.1	70.0	1				1		

5568 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDN	Returned Product Ana	alvsis
Estimated US Implants	62,100	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		,
Estimated US Active	42,500	Polarity	Bipolar	Implant Damage Electrical Malfunction	224 8
Advisories	None	Steroid	Yes	Other	9

Atrial Placement

System Longevity Study Results **Qualifying Complications** 4 Total

Number of Leads Enrolled in Study	891	Failure to Capture	2
Cumulative Months of Follow-Up	25,288	Failure to Sense Lead Dislodgement	1 1



5592 CapSure SP Novus

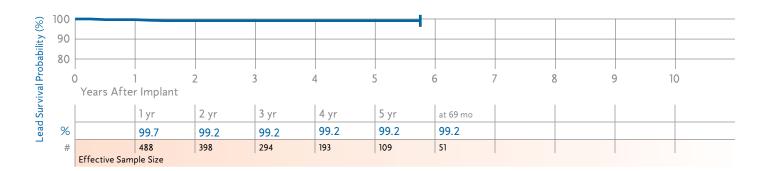
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEU	Returned Product Analys	sis
Estimated US Implants	25,500	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	17,900	Polarity	Bipolar	Implant Damage Electrical Malfunction	6 3
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

System Longevity Study Results **Qualifying Complications** 4 Total

Number of Leads Enrolled in Study	666	Failure to Capture	2
Cumulative Months of Follow-Up	22 653	Lead Dislodgement	2



5594 CapSure SP Novus

Product Characteristics

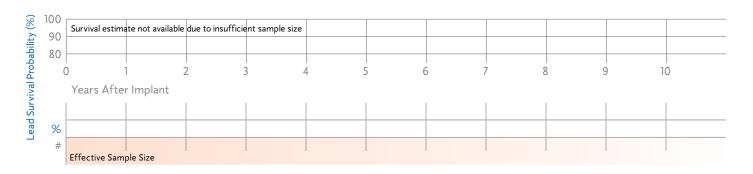
US Market Release	Jun-01	Serial Number Prefix	LFD	Returned Product Analysi	is
Estimated US Implants	9,300	Type and/or Fixation	Transvenous, Atrial-J, Tines		_
Estimated US Active	7,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	0
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 17 Cumulative Months of Follow-Up 802



6907R

Product Characteristics

US Market Release	May-79	Serial Number Prefix	FY	Returned Product Analysis
Estimated US Implants	18,500	Type and/or Fixation	Transvenous, Vent., Flange	
Estimated US Active	700	Polarity	Unipolar	Implant Damage 3 Electrical Malfunction 25
Advisories	None	Steroid	No	Other 1

Ventricular Placement

System Longevity Study Results **Qualifying Complications** 6 Total

Number of Leads Enrolled in Study	121	Failure to Capture	4
Cumulative Months of Follow-Lin	9.429	Oversensing	2



Effective Sample Size

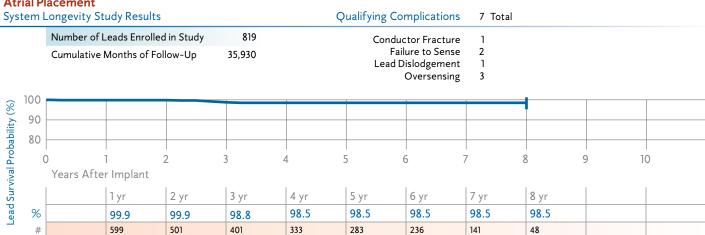
6940 CapSureFix

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	TCP	Returned Product Anal	lvsis
Estimated US Implants	26,600	Type and/or Fixation	Transvenous, A or V, Screw-in		
Estimated US Active	12,900	Polarity	Bipolar	Implant Damage Electrical Malfunction	114 19
Advisories	None	Steroid	Yes	Other	3

Atrial Placement

Lead Survival Probability (%)



6957 Spectraflex

Product Characteristics

US Market Release	Jul-79	Serial Number Prefix	VC	Returned Product Analysis
Estimated US Implants	29,100	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	2,800	Polarity	Unipolar	Implant Damage 85 Electrical Malfunction 39
Advisories	None	Steroid	No	Other 25

Atrial Placement

System Longevity Study Results

Qualifying Complications 10 Total

Number of Leads Enrolled in Study	673	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	24,255	Failure to Capture Failure to Sense Oversensing	3 5 1



Ventricular Placement

System Longevity Study Results

Qualifying Complications 41 Total

				inrolled s of Fol		,	1,853 96,047					Cardiad Failur	ctor Fra c Stimu e to Ca lure to S	lation pture	13 2 18 2		Insu		edance (not fui		efined))
00																						Π
90																						H
80																						H
C) .	1 2	2 :	3 4	4	5 (6 7	7 8	8 9	9 1	0 1	1 1	2 1	3 1.	4 1.	5 1	6 1	7 1	8 1	9 2) 2	21
	Year	s Afte	r Impl	ant																		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	at 207 mo			
%		99.6	99.3	98.9	98.3	97.8	97.1	96.9	96.2	96.2			<u> </u>	94.4	93.7	93.7	92.6	91.2	91.2			t
																						_

6957J Spectraflex

Product Characteristics

US Market Release	Sep-80	Serial Number Prefix	GG	Returned Product Ana	lvsis
Estimated US Implants	30,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	2,300	Polarity	Unipolar	Implant Damage Electrical Malfunction	74 28
Advisories	None	Steroid	No	Other	30

Atrial Placement

System

	Longe		udy Re	esults						Q	ualifyi	ng Co	mplica	tions	87 T	otal						
	Numl	oer of l	_eads E	nrolled	d in Stu	dy	2,348	3			(Conduc	tor Fra	cture	12					sulation		1
	Cumi	ulative	Month	s of Fol	low-Uբ	o	160,163	3				Failur Fail	e to Ca ure to S Out of I	pture Sense	3 48 14 1		Insu	llation (ther de Dislodg Overs		3 2 3
100																						
90																						
80																						
					1			_							4 7				0 7			
	0 Year	s Afte	z . r Impl		4 .	5	6	/	8	9 1	0 1	1	2 1	3 1	4 1.	5 1	6 1	/ 1	8 1	9 20) 21	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr		
%		99.5	99.0	98.6	97.8	97.5	96.8	96.2	95.7	94.0	93.3	92.5	92.0	92.0	91.2	91.2	90.7	88.4	87.5	86.1		
#		1.775	1.556	1.359	1.205	1.076	915	766	652	554	465	393	320	257	207	160	125	99	69	49		

6961 Tenax

Lead Survival Probability (%)

Product Characteristics

US Market Release	Jan-78	Serial Number Prefix	ТВ	Returned Product Analysis
Estimated US Implants	44,700	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	1,300	Polarity	Unipolar	Implant Damage 103 Electrical Malfunction 27
Advisories	None	Steroid	No	Other 0

Ventricular Placement

System Longevity Study Results

Effective Sample Size

Qualifying Complications 22 Total

		Numb	oer of L	eads E	inrolled	l in Stu	dy	627	,			Extra	Cardia	c Stimu	lation	4							
		Cumu	ılative I	Months	s of Fol	low-Up)	42,864	l		Insula		Fail ot furt Lead D	e to Ca lure to ther de islodge Overse	Sense fined) ement	8 6 2 1 1							
(9	100																						
Lead Survival Probability (%)	90															4_							
pabili	80																						
Pro	(ο .	1 2	2 :	3 4	4	5	5 7	7	8 9	9 1	0 1	11 1	2 1	3 1	4 1	5 1	6 1	7	18	19	20	21
vival		Years	s Afte	r Impla	ant																		
J Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 171 mo						
Leac	%		99.4	99.2	99.2	97.8	97.1	96.4	96.4	95.4	94.9	93.6	93.6	92.9	92.9	91.4	91.4						
	#			1	365	322	270	235	209	186	159	140	120	93	75	57	50						
		Effecti	ve Samı	ole Size																			

6962 Tenax

100

90 80

Lead Survival Probability (%)

Product Characteristics

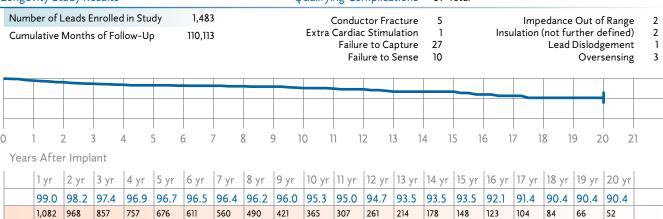
US Market Release	Jan-78	Serial Number Prefix	UB	Returned Product Analysis
Estimated US Implants	ts 70,600	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	2,400	Polarity	Bipolar	Implant Damage 170 Electrical Malfunction 84
Advisories	None	Steroid	No	Other 0

Ventricular Placement

System Longevity Study Results

Effective Sample Size

Qualifying Complications 51 Total



Lead Survival Summary (95% Confidence Interval)

		yr																	
		20																	
		18 yr																	
		16 yr						91.9 +3.1/-4.7 at 183 mo	62.2	at 189 mo					95.1 +2.0/-3.4 at 174 mo				
		14 yr						91.9 +3.1/-4.7	62.9						95.1 +2.0/-3.4	85.2 +4.7/-6.5 at 147 mo			
		12 yr			97.7 +1.1/-2.4 at 132 mo	50.6	at 129 mo	92.8 +2.7/-4.2	65.7		94.1 +2.9/-5.6 at 132 mo				96.1 +1.4/-2.1	86.6 +4.1/-5.8		96.0 +1.2/-1.8 at 123 mo	
		10 yr			97.7	51.5		95.0 +1.9/-3.0	69.8		95.6 +2.0/-3.7	99.8 +0.1/-0.7 at 117 mo	95.5 +2.5/-5.2 at 111 mo	94.4 +3.1/-6.8 at 114 mo	96.1 +1.4/-2.1	89.8 +2.9/-4.1		96.0	93.7 +2.8/-4.9 at 114 mo
		8 yr			97.7 +1.1/-2.4	58.1		96.0 +1.6/-2.4	77.8		96.7 +1.4/-2.4	99.8	96.8 +1.8/-3.9	95.7 +2.5/-5.9	97.5 +0.8/-1.3	93.6 +1.9/-2.6		96.4 +1.1/-1.5	96.0
		7 yr			98.5 +0.8/-1.8	64.1		96.0 +1.6/-2.4	83.9		97.1 +1.2/-2.0	99.8 +0.1/-0.7	97.7 +1.3/-2.6	95.7 +2.5/-5.9	98.2 +0.6/-1.0	94.6 +1.7/-2.3		97.2 +0.8/-1.1	96.6
		6 yr			98.8 +0.7/-1.5	69.4		96.4 +1.4/-2.3	88.1		98.2 +0.8/-1.4	99.8 +0.1/-0.7	97.7 +1.3/-2.6	96.8 +2.0/-5.3	98.3	96.9		97.4 +0.7-1.0	97.6
		5 yr			99.1 +0.5/-1.2	77.1		97.6	92.6		98.6 +0.6/-1.1	99.8 +0.1/-0.7	98.3	97.7 +1.6/-4.7	98.7	97.9 +0.8/-1.2		97.5	98.0
.y (%)		4 yr	99.3 +0.6/-4.4 at 42 mo		99.1	87.4		98.8 +0.7/-1.2	95.9		98.6 +0.6/-1.1	99.8 +0.1/-0.7	98.7 +0.8/-1.8	98.6	99.1 +0.4/-0.6	98.7 +0.5/-1.0		98.0	98.4 +0.6/-0.8
Probabilit	lant	3 yr	99.3 +0.6/-4.4	100.0 at 33 mo	99.4	96.3	,	99.1 +0.5/-1.2	98.4		98.8 +0.5/-1.1	99.8 +0.1/-0.7	99.1 +0.6/-1.6	99.4 +0.5/-3.5	99.5 +0.2/-0.5	99.1 +0.4/-0.8	97.0	98.3	98.8
Device Survival Probability (%)	Years After Implant	2 yr	99.3	0.001	99.4	99.3		99.2 +0.5/-1.0	99.1		99.3 +0.4/-0.9	99.8 +0.1/-0.7	99.4 +0.4/-1.4	99.4 +0.5/-3.5	99.6 +0.2/-0.4	99.2 +0.4/-0.7	97.0 +2.0/-5.9	98.8 +0.4/-0.6	98.8
Device	Years A	l yr	99.3 +0.6/-4.4	0.001	99.4 +0.4/-1.1	99.8	,	99.4 +0.4/-1.0	99.6		99.9 +0.1/-0.6	99.9 +0.1/-0.5	99.4 +0.4/-1.4	99.4 +0.5/-3.5	99.9 +0.1/-0.4	99.4 +0.3/-0.7	97.0	99.0	99.3
ve Months -Up	nulatir ollow- tudy	Эłо	4,285	4,241	44,869	71,581		54,376	150,950		60,527	51,157	28,053	15,216	131,200	76,590	5,877	114,150	81,140
	nifyin səilqn		-	0	0	276	Below	25	316	Below	19	3	6	7	32	50	9	48	32
	pəllo sp	Lead	142	135	117	1,640	Survival	851	2,543	Survival	1,158	1,215	541	259	2,363	1,690	108	2,401	1,799
1	Narke sase		Aug-05	Aug-05	Jul-86	Feb-89	- 1993 Leac	Nov-82	Jul-83	- 1991 Lead	Aug-91	Oct-91	not US released	Aug-88	Jan-89	Jan-89	Jan-97	Mar-96	Mar-96
	mper	СРЗ	Atrial	Vent	Vent	Vent	nage 165	Vent	Vent)age 166	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent
	γlin	Fam	SelectSecure	SelectSecure	CapSure	CapSure	Advisories: see page 165 - 1993 Lead Survival Below Expectations	Target Tip	Target Tip	Advisories: <u>see page 166</u> - 1991 Lead Survival Below Expectations	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In	Screw-In	CapSureFix	CapSureFix	CapSureFix
	del nber	ooM nuM	3830	3830	4003, 4003M	4004,	4004M	4011	4012		4023	4024	4033	4057, 4057M	4058, 4058M	4058, 4058M	4067	4068	4068

) yr																
		yr 20																
		18 >																
		16 yr																
		14 yr											83.6 +5.0/-6.8 at 159 mo					
		12 yr											84.8 +4.6/-6.3				96.9 +1.8/-4.4 at 126 mo	
		10 yr									66.1	at 105 mo	87.5 +3.9/-5.5		99.0 +0.6/-1.2 at 108 mo		96.9 +1.8/-4.4	93.3 +3.7/-8.0 at 105 mo
		8 yr									69.9		91.5 +2.9/-4.3		99.0		96.9 +1.8/-4.4	96.5 +2.1/-5.2
		7 yr							97.9 +0.9/-1.4 at 75 mo		73.0		94.7 +2.0/-3.2		99.0	97.9 +1.4/-4.2 at 78 mo	96.9	96.5 +2.1/-5.2
		6 yr	ηple size					98.2 +1.5/-10.5 at 63 mo	97.9 +0.9/-1.4	1ple size	82.2		95.6 +1.8/-2.8		99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	97.6 +1.6/-4.2
		5 yr	Survival estimate not available due to insufficient sample size					100.0	97.9 +0.9/-1.4	Survival estimate not available due to insufficient sample size	90.3		96.7	98.1 +1.4/-5.3 at 57 mo	99.0 +0.6/-1.2	97.9 +1.4/-4.2	97.8 +1.4/-3.6	99.3 +0.5/-1.4
y (%)		4 yr	due to insu		99.5 +0.3/-1.0			100.0	98.4 +0.7/-1.0	due to insu	98.2		98.0	98.1 +1.4/-5.3	99.0 +0.6/-1.2	97.9	97.8 +1.4/-3.6	99.3 +0.5/-1.4
Device Survival Probability (%)	ant	3 yr	ot available	100.0 at 33 mo	99.5 +0.3/-1.0	99.3 +0.5/-2.5 at 33 mo	99.5 +0.4/-1.4 at 33 mo	100.0	98.8 +0.5/-0.9	ot available	99.1		99.1 +0.6/-1.5	98.1 +1.4/-5.3	99.3 +0.4/-1.0	98.8 +0.9/-3.6	99.1 +0.7/-2.8	99.3 +0.5/-1.4
Survival P	Years After Implant	2 yr	estimate n	0.001	99.5 +0.3/-1.0	99.3 +0.5/-2.5	99.5 +0.4/-1.4	100.0	98.9 +0.5/-0.9	estimate n	0.001		99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.3 +0.4/-1.0	99.4 +0.5/-3.5	99.1 +0.7/-2.8	99.3 +0.5/-1.4
Device !	Years A	l yr	Survival	0.001	99.5 +0.3/-1.0	99.8 +0.2/-1.5	99.5 +0.4/-1.4	100.0	99.0	Survival	0.001		99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.6 +0.3/-0.7	100.0	99.1 +0.7/-2.8	99.3 +0.5/-1.4
e Months Up	nulativ ollow- tudy	∃ }o	34	3,300	15,441	7,482	8,765	9,783	46,393	3,179	19,861		39,749	6,967	38,794	11,038	18,286	21,989
	ilifying nplica		0	0	т	7	2	3	91	_	48	Below	35	4	9	4	9	=
	pəllo		_	66	119	512	507	260	1,144	59	368	d Survival	009	121	910	206	294	539
1	sase Narke		Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	98-Inl	Sep-98	Jul-86	Mar-90	- 1996 Lea	Jul-83	Aug-91	Oct-91	not US released	Aug-88	Nov-94
	mber	εчЭ	Atrial	Vent	Vent	Atrial	Vent	Vent	Vent	Atrial	Atrial	page 164	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	γlir	Fam	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	Target Tip	CapSure SP Novus	CapSure	CapSure	Advisories: see page 164 - 1996 Lead Survival Below Expectations	Target Tip	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In
	lel nber	ooM nuM	4073	4073	4074	4076	4076	4081	4092	4503, 4503M	4504,	4504M	4512	4523	4524	4533	4557, 4557M	4558M

		_																
		20 yr																
		18 yr																
		16 yr					98.6 +0.5/-0.9 at 180 mo											
		14 yr					98.6 +0.5/-0.9											96.7 +1.2/-1.9 at 159 mo
		12 yr					98.6 +0.5/-0.9		96.0 +1.5/-2.3 at 126 mo	98.2 +0.9/-1.6 at 123 mo								96.7
		10 yr				98.2 +1.0/-2.1 at 105 mo	98.8 +0.4/-0.6		96.0	98.2 +0.9/-1.6		98.3 +1.2/-3.6 at 111 mo						97.5
		8 yr				98.2 +1.0/-2.1	99.1 +0.3/-0.4		97.1 +1.1/-1.6	98.2 +0.9/-1.6		98.3 +1.2/-3.6	99.1 +0.5/-1.5 at 93 mo	99.4 +0.4/-1.9 at 93 mo				98.5
		7 yr				98.2 +1.0/-2.1	99.3 +0.2/-0.3	95.7 +2.7/-7.2 at 75 mo	97.7 +0.9/-1.4	98.9	98.0	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9			99.0 +0.6/-1.3 at 81mo	98.9
		6 yr	93.9 +2.0/-2.9	mple size	96.9	99.4 +0.3/-0.8	99.3	95.7 +2.7/-7.2	98.3 +0.7/-1.2	99.2	98.0	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.2	99.2 +0.4/-0.9 at 69 mo	99.0	99.2
		5 yr	93.9 +2.0/-2.9	estimate not available due to insufficient sample size	96.9	99.4	99.4	97.1 +2.0/-5.9	98.7	99.2	99.3	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.2	99.2 +0.4/-0.9	99.0	99.3
y (%)		4 yr	94.5 +1.8/-2.6	e due to ins	97.8 +1.4/-3.5	99.4	99.5	97.1 +2.0/-5.9	99.0	99.2	99.3	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.2	99.2 +0.4/-0.9	99.0	99.4
Device Survival Probability (%)	lant	3 yr	94.5 +1.8/-2.6	not availabl	97.8	99.5 +0.3/-0.6	99.5	98.2	99.1 +0.4/-0.7	99.3	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.4 +0.4/-1.1	99.4 +0.4/-1.9	99.5	99.4 +0.3/-0.7	99.3 +0.4/-1.0	99.5
Survival	Years After Implant	2 yr	95.8	estimater	97.8	99.6 +0.3/-0.6	99.6 +0.1/-0.2	99.2 +0.7/-4.8	99.6 +0.2/-0.4	99.5	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.6	99.7 +0.3/-1.5	99.7 +0.1/-0.4	99.4 +0.3/-0.7	99.5 +0.3/-0.8	99.8
Device	Years A	l yr	96.3	Survival	97.8	99.7 +0.2/-0.5	99.7 +0.1/-0.2	0.00	99.7 +0.2/-0.4	99.7 +0.2/-0.4	99.5	99.6	99.8 +0.1/-0.6	99.7 +0.3/-1.5	99.7 +0.1/-0.4	99.6 +0.2/-0.5	99.6	99.8
e Months -Up	nulativ ollow- tudy	∃ }o	20,494	116	9,505	62,593	421,081	9,522	90,664	78,752	53,726	32,259	34,937	20,567	73,716	44,927	37,536	232,128
g snoit	ilifying nplica	on Con	28	0	ī2	01	45	4	25	52	=	2	2	2	13	∞	∞	37
	pəllo sp	Lea	576	25	243	1,351	8,142	168	1,901	1,596	1,392	696	1,360	450	2,466	1,507	1,171	4,433
1	sase Narke		Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-88	Feb-96	Feb-96	Jun-98	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Jun-98	Mar-90
	mber	сРа	Atrial	Atrial	Atrial	Vent	Vent	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent	Vent	Atrial
	γlin	Fam	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure	CapSure Z	CapSure Z	CapSure Z Novus	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP
	del nber	oM nuM	4568	4574	4592	5023, 5023M	5024, 5024M	5026	5033	5034	5054	2068	5068	5072	5076	5076	5092	5524, 5524M

		1		g tions	ve Months -Up	Device S	evice Survival Probability (%)	robability	(%) ^										
	mper	ysrke Varke		lifying soilqr	rilatir wollow- ybu:	Years Af	Years After Implant	ant											
	СРЗ	NS N	Гез	eυQ	A fo	l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr	20 yr
3	CapSure Z Atrial	ial Feb-96	96 260	9	12,319	98.3 +1.1/-2.8	97.8 +1.3/-3.1	97.8 +1.3/-3.1	97.1 +1.6/-3.6	97.1 +1.6/-3.6	97.1	97.1 +1.6/-3.6 at 78 mo							
CapSur Novus	CapSure Z Atrial Novus	ial Jun-98	8 352	4	15,861	0.001	99.1 +0.7/-2.6	98.6 +0.9/-3.0	98.0 +1.3/-3.2	98.0 +1.3/-3.2	98.0 +1.3/-3.2	98.0	98.0 +1.3/-3.2 at 93 mo						
3	CapSureFix Atrial	ial Jan-97	7 891	4	25,288	99.9 +0.1/-0.9	99.6 +0.3/-1.2	99.6 +0.3/-1.2	99.6	98.9 +0.8/-3.0	98.2 +1.2/-3.9	98.2 +1.2/-3.9							
CapSur Novus	CapSure SP Atrial Novus	ial Jun-98	8 666	4	22,653	99.7 +0.2/-1.1	99.2 +0.5/-1.3	99.2 +0.5/-1.3	99.2	99.2 +0.5/-1.3	99.2 +0.5/-1.3 at 69 mo								
CapSur Novus	CapSure SP Atrial Novus	ial Jun-01	71 1	0	802	Survival	estimate n	ot available	due to insu	Survival estimate not available due to insufficient sample size	mple size								
(no brand name)	ld Vent	nt May-79	79 121	9	9,429	99.0	99.0	99.0	99.0	97.5 +1.9/-7.3	97.5 +1.9/-7.3	97.5 +1.9/-7.3 at 81mo							
מי	CapSureFix Atrial	ial Oct-98	86 86	7	35,930	99.9 +0.1/-0.8	99.9	98.8 +0.6/-1.6	98.5 +0.8/-1.6	98.5 +0.8/-1.6	98.5 +0.8/-1.6	98.5 +0.8/-1.6	98.5 +0.8/-1.6						
ŧ	Spectraflex Atrial	ial Jul-79	673	01	24,255	0.001	99.7 +0.3/-1.6	99.4 +0.4/-2.0	98.5 +0.9/-2.5	98.0 +1.2/-2.9	98.0	95.6 +2.3/-4.6	93.5 +3.1/-5.9	93.5 +3.1/-5.9 at 99 mo					
ŧ	Spectraflex Vent	nt Jul-79	1,853	4	96,047	99.6 +0.2/-0.5	99.3	98.9	98.3 +0.7/-1.0	97.8 +0.8/-1.2	97.1 +1.0/-1.4	96.9	96.2 +1.2/-1.7	95.4 +1.5/-2.2	94.4	93.7 +2.2/-3.2	92.6 +2.7/-4.2	91.2 +3.4/-5.4 at 207 mo	
ctr	Spectraflex Atrial	ial Sep-80	80 2,348	87	160,163	99.5 +0.2/-0.5	99.0	98.6 +0.4/-0.7	97.8 +0.6/-0.8	97.5 +0.7/-1.0	96.8 +0.8/-1.1	96.2 +1.0/-1.2	95.7 +1.0/-1.3	93.3 +1.5/-1.8	92.0	91.2 +2.0/-2.4	90.7	87.5 +3.4/-4.5	86.1 +4.0/-5.4 at 228 mo
Tenax	Vent	nt Jan-78	8 627	22	42,864	99.4	99.2 +0.5/-1.3	99.2 +0.5/-1.3	97.8 +1.1/-2.0	97.1 +1.3/-2.3	96.4	96.4	95.4	93.6 +2.5/-3.8	92.9 +2.7/-4.3	91.4 +3.5/-5.7	91.4 +3.5/-5.7 at 171mo		
Tenax	Vent	nt Jan-78	8 1,483	15	110,113	99.0	98.2 +0.7/-0.9	97.4 +0.8/-1.2	96.9 +0.9/-1.2	96.7 +0.9/-1.4	96.5 +1.0/-1.3	96.4 +1.0/-1.4	96.2 +1.0/-1.5	95.3 +1.3/-1.8	94.7	93.5 +1.8/-2.6	92.1 +2.4/-3.3	90.4	90.4 +3.1/-4.3

Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
3830	SelectSecure	Aug-05	7,300	6,500	13	1	1
4003, 4003M	CapSure	Jul-86	40,000	7,100	24	57	2
4004, 4004M	CapSure	Feb-89	74,500	2,800	55	683	19
4011	Target Tip	Nov-82	64,000	7,200	29	141	5
4012	Target Tip	Jul-83	96,800	5,700	50	820	34
4023	CapSure SP	Aug-91	43,700	14,900	48	19	6
4024	CapSure SP	Oct-91	229,200	84,600	264	103	34
4033	CapSure Z	not US released	N/A	N/A	2	0	0
4057, 4057M	Screw-in	Aug-88	12,100	2,800	39	6	4
4058, 4058M	Screw-in	Jan-89	111,100	25,900	388	228	23
4067	CapSureFix	Jan-97	1,300	500	3	1	1
4068	CapSureFix	Mar-96	131,700	57,500	406	81	11
4073	CapSure Sense	Jun-02	500	400	1	0	0
4074	CapSure Sense	Jun-02	48,500	38,700	12	3	1
4076	CapSureFix Novus	Feb-04	120,600	104,700	51	3	5
4081	Target Tip	Jul-89	4,100	900	4	5	0
4092	CapSure SP Novus	Sep-98	139,700	90,100	32	11	5
4503, 4503M	CapSure	Jul-86	9,000	1,400	2	11	0
4504, 4504M	CapSure	Mar-90	16,600	1,600	5	171	4
4512	Target Tip	Jul-83	11,600	1,100	4	83	8
4523	CapSure SP	Aug-91	12,000	3,500	5	2	1
4524	CapSure SP	Oct-91	106,900	38,200	47	21	8
4533	CapSure Z	not US released		N/A	0	0	0
4557, 4557M	Screw-in	Aug-88	22,500	5,200	53	14	4
4558M	Screw-in	Nov-94	21,000	6,100	111	11	1
4568	CapSureFix	Jan-97	72,800	37,900	197	6	4
4574	CapSure Sense	Jun-02	31,200	24,600	6	1	0
4592	CapSure SP Novus	Oct-98	70,800	44,500	12	3	0
5023, 5023M	CapSure SP	Nov-88	10,600	2,900	15	7	0
5024, 5024M	CapSure SP	Mar-90	211,400	72,800	723	106	29
5024, 502410	CapSure	Feb-88	7,800	1,300	60	7	1
5033	CapSure Z	Feb-96	2,500	1,000	6	1	3
5034	CapSure Z	Feb-96	58,700	23,000	85	29	11
5054	CapSure Z Novus	Jun-98	82,500	50,000	40	13	6
5068	CapSureFix	Jan-97	108,000	52,300	455	61	15
5072	SureFix	Jun-98	8,900	5,100	26	4	1
5076	CapSureFix Novus	Aug-00	838,700	625,300	691	156	51
5092	CapSure SP Novus	Jun-98	105,900	68,400	46	20	11
5524, 5524M	CapSure SP Novus	Mar-90	63,800	23,400	66	21	7
5534	•	Feb-96	27,700	9,200	29	6	5
5554	CapSure Z Novus	Jun-98	53,000	32,300	7	6	4
	CapSure Z Novus	<u> </u>					9
5568	CapSureFix	Jan-97	62,100	42,500	224	8	
5592	CapSure SP Novus	Jun-98	25,500	17,900	6	3	0

continued

Returned Product Analysis Summary continued

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5594	CapSure SP Novus	Jun-01	9,300	7,100	0	1	0
6907R	(no brand name)	May-79	18,500	700	3	25	1
6940	CapSureFix	Oct-98	26,600	12,900	114	19	3
6957	Spectraflex	Jul-79	29,100	2,800	85	39	25
6957J	Spectraflex	Sep-80	30,000	2,300	74	28	30
6961	Tenax	Jan-78	44,700	1,300	103	27	0
6962	Tenax	Jan-78	70,600	2,400	170	84	0

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/ Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4003, 4003M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4003) IS-1 UNI (4003M)
4004, 4004M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Porous/Steroid	3.2 mm Low Profile (4004) IS-1 BI (4004M)
4011	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	5 mm
4012	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4057, 4057M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm (4057) IS-1 UNI (4057M)
4058, 4058M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/1 Filars	2.0 mm Helix	3.2 mm Low Profile (4058) IS-1 BI (4058M)
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/ Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/ Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4081	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	IS-1 UNI w/Removable 5 mm Sleeve
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/ Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4503, 4503M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4503) IS-1 UNI (4503M)
4504, 4504M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 3/4 Filars	Porous/Steroid	3.2 mm Low Profile (4504) IS-1 BI (4504M)
4512	Target Tip	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 2/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4557, 4557M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm (4557) IS-1 UNI (4557M)
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/ Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/ Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5026	CapSure	Transvenous Ventricular Tines	Silicone	MP35N 6/4 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6907R	(no brand name)	Transvenous Ventricular Flange	Silicone	MP35N 2 Filars	Ring Tip	5 mm
6940	CapSureFix	Transvenous A or V Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1BI
6957	Spectraflex	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm
6957J	Spectraflex	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm
6961	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 3 Filars	Ring Tip	5 mm
6962	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Ring Tip	5 mm Bifurcated

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

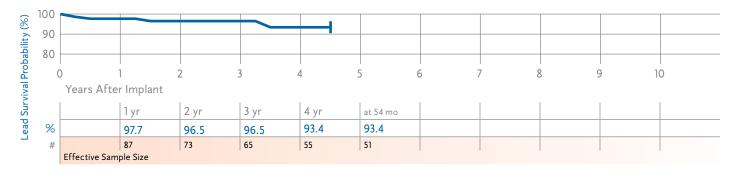
Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	Returned Product Ana	alvsis
Estimated US Implants	25,300	Type and/or Fixation	Myocardial Stab-in, V or A, Peds		
Estimated US Active	3,700	Polarity	Unipolar	Implant Damage Electrical Malfunction	15 95
Advisories	None	Steroid	No	Other	28

System Longevity Study Results

Qualifying Complications

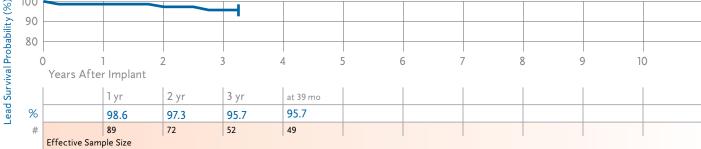
Number of Leads Enrolled in Study	179	Failure to Capture	4
Cumulative Months of Follow-Up	6.205	Failure to Sense	3
	-,	Impedance Out of Range	1
		Insulation (ESC)	1
		Insulation (not further defined)	1



4965 CapSure Epi

Product Characteristics

	US Market Release	Sep-96		Serial Number Pre	efix LBT		Returned Product Ana	lvsis
	Estimated US Implants	18,600		Type and/or Fixat	ion Epicardial Suture-0	On V or A		
	Estimated US Active	10,600		Polarity	Unipolar		Implant Damage Electrical Malfunction	8 78
	Advisories	None		Steroid	Yes		Other	2
System	Longevity Study Results			Q	ualifying Complications	8 Total		
	Number of Leads Enrolled	in Study	170		Conductor Fracture	3		
	Cumulative Months of Foll	ow-Up	4,148		Failure to Capture	2		
					Failure to Sense Oversensing	2		
~ 100								



Epi/Myocardial Pacing Leads continued

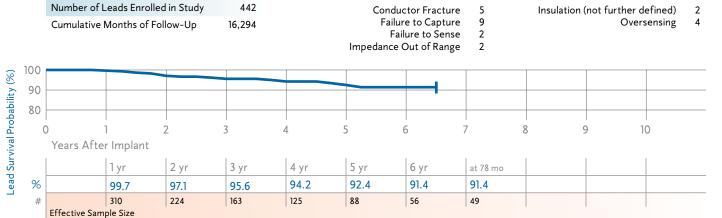
4968 CapSure Epi

Product Characteristics

Estimated US Implants 13,800 Type and/or Fixation Epicardial Suture-On V or A Estimated US Active 10,000 Polarity Bipolar Implant Damage 2 Electrical Malfunction 3 Advisories None Steroid Yes Other 0	US Market Release	Sep-99	Serial Number Prefix	LEN	Returned Product Anal	lvsis
Estimated US Active 10,000 Polarity Bipolar Electrical Malfunction 3	Estimated US Implants	13,800	Type and/or Fixation	Epicardial Suture-On V or A		,
Advisories None Steroid Yes Other 0	Estimated US Active	10,000	Polarity	Bipolar		2
	Advisories	None	Steroid	Yes		Ō

System Longevity Study Results

Qualifying Complications 24 Total



5071

Product Characteristics

210

6,171

US Market Release	Dec-92	Serial Number Prefix	LAQ	Returned Product Anal	lvsis
Estimated US Implants	34,100	Type and/or Fixation	Myocardial Screw-in Vent.		
Estimated US Active	21,100	Polarity	Unipolar	Implant Damage Electrical Malfunction	24 4
Advisories	None	Steroid	No	Other	1

System Longevity Study Results

Number of Leads Enrolled in Study

Cumulative Months of Follow-Up

Qualifying Complications 10 Total Failure to Capture

Oversensing

2

100											
% 90											
(f) 80											
ba) [) 3	} ∠	 1	l 5	5 7	, .	3) 1()
_	Years After	r Implant		,	т -	,	,		,	,	
viva		1_			l .	ı	1			1 1	
Sur		l yr	2 yr	3 yr	4 yr	at 54 mo					
Lead s		96.7	94.7	91.9	91.9	91.9					
# #		107	77	64	56	49					
	Effective Samp	ole Size									

Epi/Myocardial Pacing Leads continued

371

Effective Sample Size

319

248

197

167

137

93

84

6917, 6917A Tenax **Product Characteristics US Market Release** Jun-73 Serial Number Prefix WV or WC Returned Product Analysis Estimated US Implants Type and/or Fixation 180,100 Myocardial Screw-in Vent. Implant Damage **Estimated US Active** Polarity Unipolar 5,500 Electrical Malfunction 42 Advisories Steroid Νo None Other 1 System Longevity Study Results **Qualifying Complications** 69 Total Number of Leads Enrolled in Study 985 Impedance Out of Range Conductor Fracture Extra Cardiac Stimulation Insulation (MIO) 47,434 Cumulative Months of Follow-Up 30 18 Failure to Capture Oversensing Failure to Sense 11 100 Lead Survival Probability (%) 90 80 12 15 16 19 21 20 Years After Implant 1 yr | 2 yr | 3 yr | 4 yr | 5 yr | 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 150 mo 93.6 92.8 91.1 89.5 87.2 85.0 84.2 84.2 83.2 80.4

Spectraflex					suo		Device S	urvival P	Device Survival Probability (%)	(%)								
Example Space Spectraflex Oct-81 179 10 6,205 97.7 96.5 96.5 Spectraflex Oct-81 179 10 6,205 97.7 96.5 96.5 CapSure Epi Sep-96 170 8 4,148 98.6 97.3 95.7 CapSure Epi Sep-99 442 24 16,294 99.7 97.1 95.7 (no brand Dec-92 210 10 6,171 96.7 94.7 91.9 Tenax Jun-73 985 69 47,434 99.0 97.6 95.9 Tenax Jun-73 985 69 47,434 99.0 97.6 95.9		iliy		pəllo	gniyìilı itsəilqr	J-wollo	Years Af	ter Impl	ant									
Spectraflex Oct-81 179 10 6,205 97.7 96.5 96.5 96.5 CapSure Epi Sep-96 170 8 4,148 98.6 97.3 95.7 CapSure Epi Sep-99 170 8 4,148 98.6 97.3 95.7 CapSure Epi Sep-99 442 24 16,294 99.7 97.1 95.6 (no brand Dec-92 210 10 6,171 96.7 94.7 91.9 name) 1mn-73 985 69 47,434 99.0 976.5 95.9 Tenax 1mn-73 985 69 47,434 99.0 976.5 95.9		Fam		Enro	suQ no⊃	J ło	l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
CapSure Epi Sep-96 170 8 4,148 98.6 97.3 95.7 CapSure Epi Sep-99 442 24 16,294 99.7 97.1 95.6 (no brand name) Dec-92 210 10 6,171 96.7 94.7 91.9 Tenax Jun-73 985 69 47,434 99.0 97.6 95.9 41.9/-1.0 40.5/-1.0 90.9/-1.5 41.3/-2.0	4951, 4951M	Spectraflex	Oct-81	179	9	6,205	97.7	96.5		93.4	93.4 +3.7/-8.1 at 54 mo							
CapSure Epi Sep-99 442 24 16,294 99,7 97.1 95,6 (no brand name) Dec-92 210 10 6,171 96,7 94,7 94,7 Tenax Jun-73 985 69 47,434 99,0 97,6 95,9 Tenax Jun-73 985 69 47,434 99,0 97,6 95,9	4965	CapSure Epi	Sep-96	170	∞	4,148	98.6	97.3 +1.9/-6.0	95.7 +2.8/-7.4	95.7 +2.8/-7.4 at 39 mo								
(no brand name) Dec-92 210 10 6,171 96.7 94.7 91.9 name) 119/-4.6 +2.8/-5.7 +4.0/-7.5 +4.0/-7.5 Tenax Jun-73 985 69 47,434 99.0 97.6 95.9 H.3/-2.0	4968	CapSure Epi	Sep-99	442	24	16,294	99.7	97.1 +1.4/-2.8	95.6 +2.0/-3.5	94.2 +2.5/-4.1	92.4 +3.1/-5.1	91.4	91.4 +3.5/-5.7 at 78 mo					
Tenax Jun-73 985 69 47,434 99.0 +0.5/-1.0 97.6 +0.5/-1.0 95.9 +1.3/-2.0	5071	(no brand name)	Dec-92	210	0	171,9	96.7	94.7	91.9 +4.0/-7.5	91.9 +4.0/-7.5	91.9 +4.0/-7.5 at 54 mo							
	6917, 6917A	Tenax	Jun-73	985	69	47,434	99.0	97.6	95.9 +1.3/-2.0	93.6	92.8	91.1	89.5 +2.7/-3.4	87.2 +3.1/-4.1	84.2	83.2 +4.2/-5.3	80.4 +5.2/-6.8 at 150 mo	

Epi/Myocardial Pacing Leads continued

Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
4951, 4951M	Spectraflex	Oct-81	25,300	3,700	15	95	28
4965	CapSure Epi	Sep-96	18,600	10,600	8	78	2
4968	CapSure Epi	Sep-99	13,800	10,000	2	3	0
5071	(no brand name)	Dec-92	34,100	21,100	24	4	1
6917, 6917A	Tenax	Jun-73	180,100	5,500	115	42	1

Source: Returned Product Analysis
Data as of July 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(no brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(no brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI
6917	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	3-Turn Helix	5 mm
6917A	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	2-Turn Helix	5 mm

VDD Single Pass Pacing Leads

5032 CapSure VDD

Product Characteristics

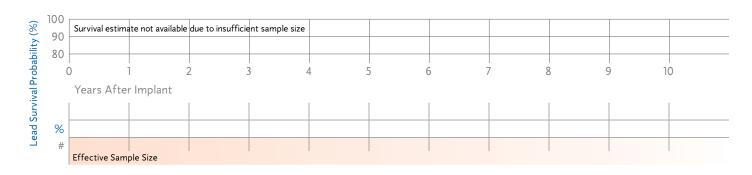
US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	Returned Product Ana	lvsis
Estimated US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent., Tines		
Estimated US Active	2,100	Polarity	Quadripolar	Implant Damage Electrical Malfunction	24 12
Advisories	None	Steroid	Yes	Other	0

System Longevity Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	38	Failure to Sense	1

Cumulative Months of Follow-Up 1,866



5038 CapSure VDD-2

Product Characteristics

	US Market Release	Sep-98	Serial Number Prefix	LEE, LEG, or LEF	Returned Product Anal	vsis
	Estimated US Implants	7,600	Type and/or Fixation	Transvenous, Atr-Vent., Tines		,
	Estimated US Active	4,400	Polarity	Quadripolar	Implant Damage Electrical Malfunction	6 2
	Advisories	None	Steroid	Yes	Other	1
System	Longevity Study Results		Qualifyin	g Complications 4 Total		

Number of Leads Enrolled in Study	545	Conductor Fracture	1
Cumulative Months of Follow-Up	19,297	Failure to Capture Failure to Sense	1 2



VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

		ŧ		ng ations	ive Months Up	Device :	Survival F	Probabilit	y (%)						
Model Number	amily	US Market Release	Leads Enrolled	Qualifying Complicati	Cumulativ of Follow⊣ in Study	Years A	fter Impl	lant 3 yr	4 vr	5 yr	6 vr	7 7	8 yr	9 yr	10 vr
5032	CapSure VDD	Mar-96	38	1	1,866	. , .	z yr stimate not		/		,	/ yr	o yı	Эуг	lo yr
5038	CapSure VDD-2	Sep-98	545	4	19,297	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.7 +0.9/-2.9	98.0 +1.3/-3.5	98.0 +1.3/-3.5	98.0 +1.3/-3.5 at 78 mo			

Source: System Longevity Study Data as of July 31, 2007

Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5032	CapSure VDD	Mar-96	5,400	2,100	24	12	0
5038	CapSure VDD-2	Sep-98	7,600	4,400	6	2	1

Source: Returned Product Analysis Data as of July 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than six-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a six-month interval, a conservative approach has been adopted whereby only the maximum charge in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

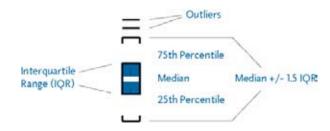
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

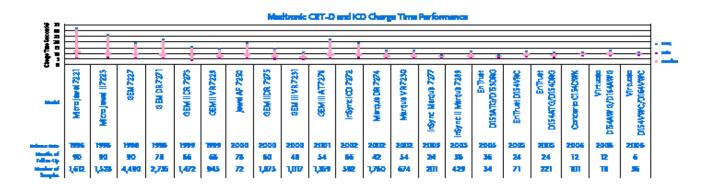
Data Presentation

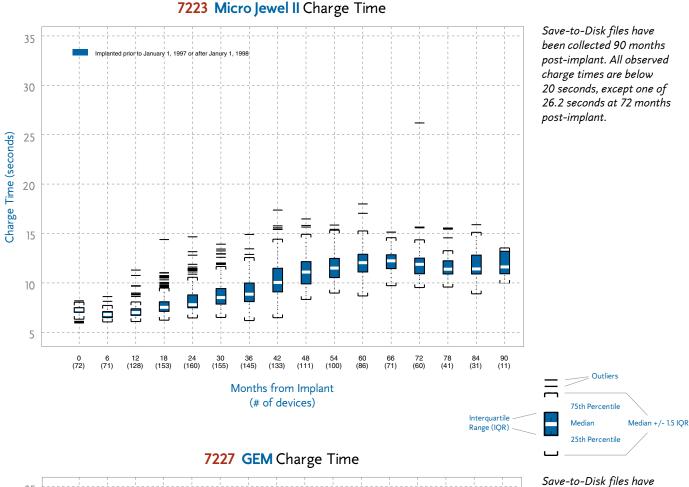
Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the 25th percentile. The brackets around the box represent the variance in charge times (analogous to a confidence interval), and are calculated as a function of the median and IQR. Individual values falling outside the brackets are labeled as outliers.

Results

As shown in the graph below, the performance of Medtronic ICD and CRT-D devices has improved. This graph shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel. A progression toward shorter mean charge times and less variation has occurred between 1996 and 2002. Models released after 2002 have limited experience, but appear to be continuing this performance.



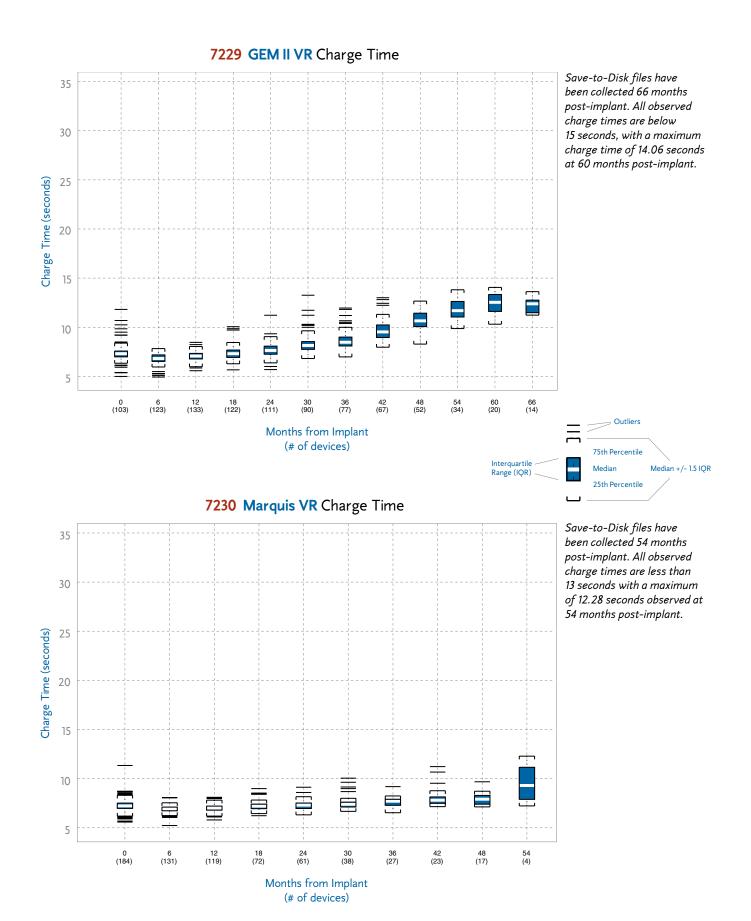


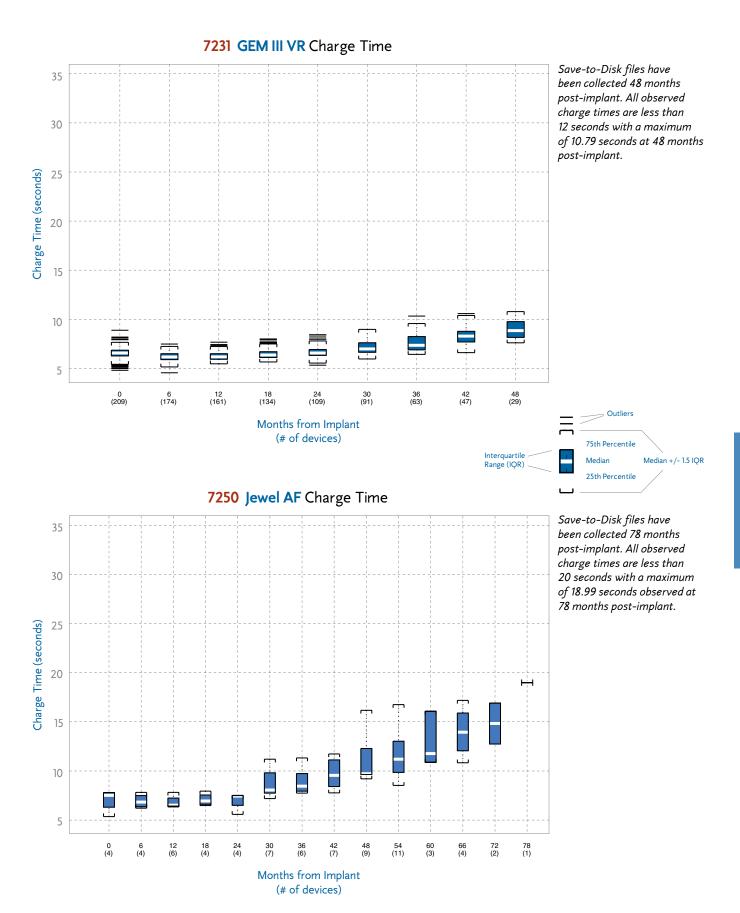


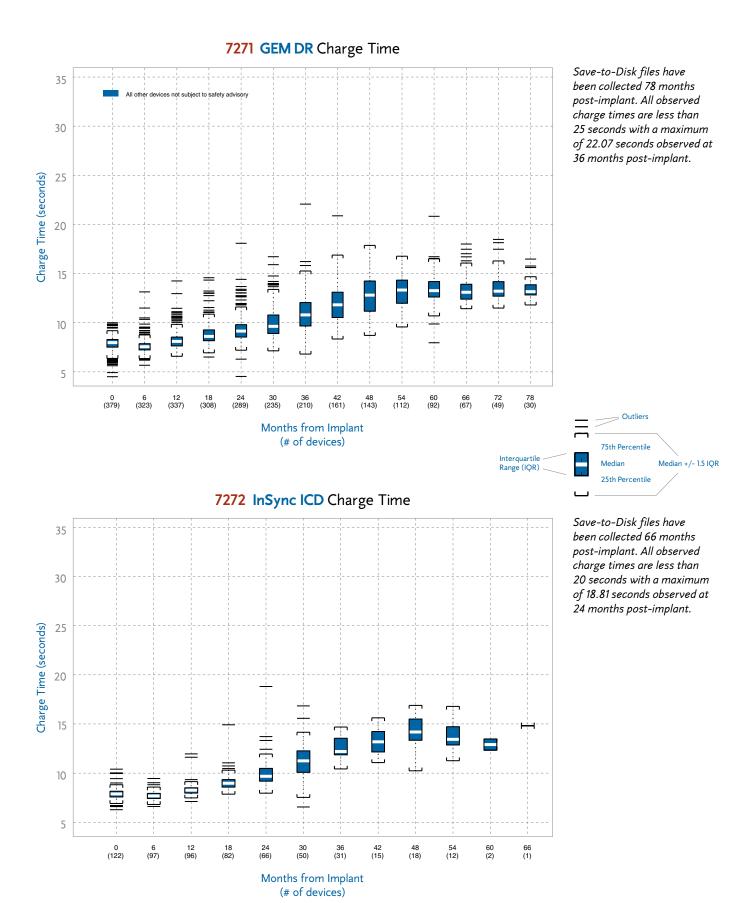
35 30 25 30 30 36 42 48 54 60 66 72 78 84 90 (573) (543) (543) (500) (460) (401) (360) (284) (241) (192) (131) (107) (65) (36) (30) (22)

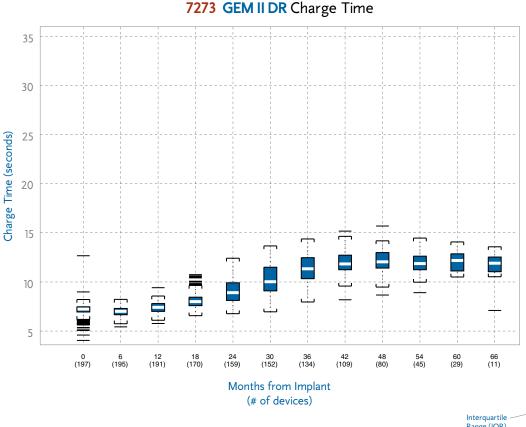
Months from Implant (# of devices)

Save-to-Disk files have been collected 90 months post-implant. All observed charge times are below 20 seconds, with a maximum charge time of 18.75 seconds at 78 months post-implant.









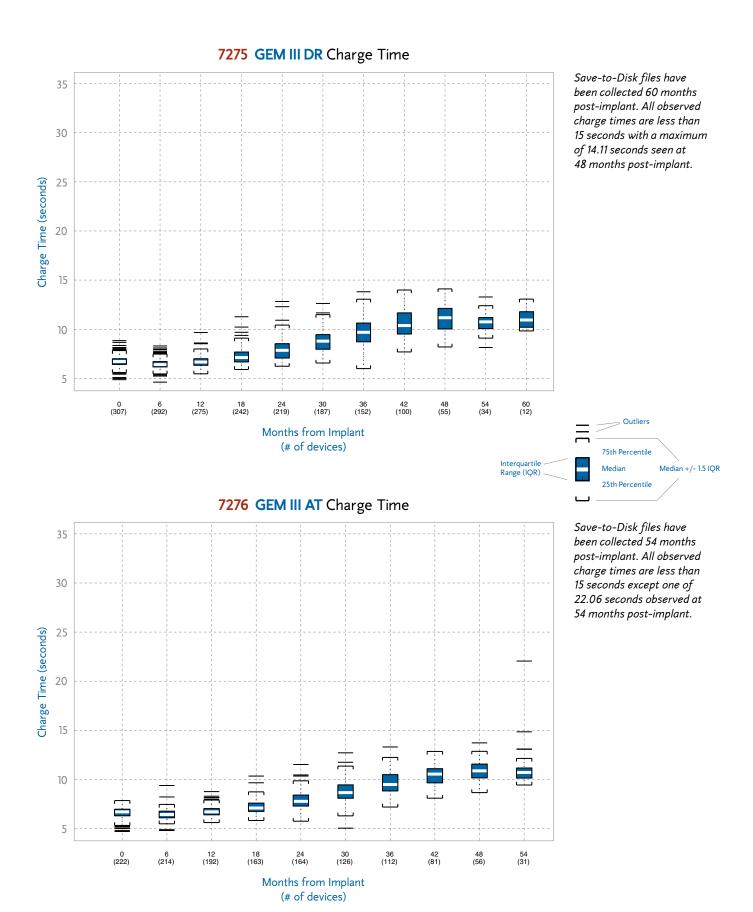
Save-to-Disk files have been collected 66 months postimplant. All observed charge times are below 20 seconds, with a maximum charge time of 15.69 seconds observed at 48 months post-implant.

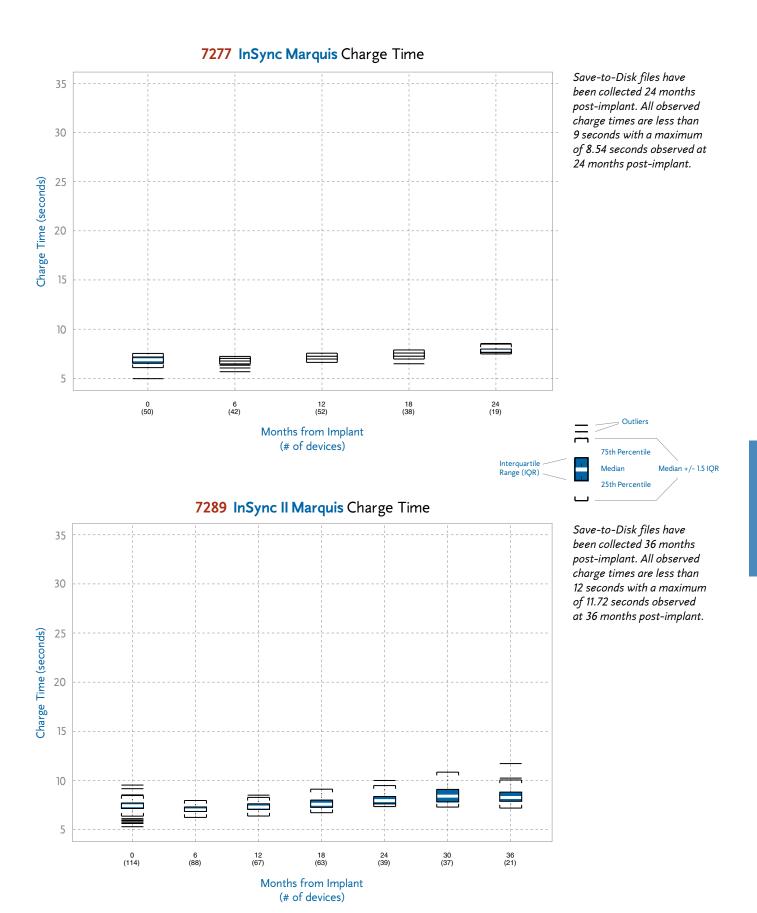


35 30 Charge Time (seconds) 25 15 10 Months from Implant

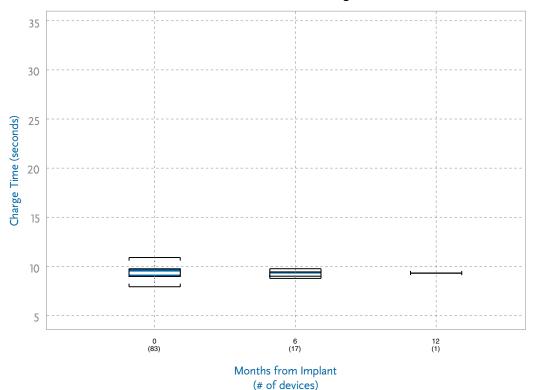
(# of devices)

Save-to-Disk files have been collected 42 months post-implant. All observed charge times are less than 13 seconds with a maximum of 12.05 seconds observed at 36 months post-implant.



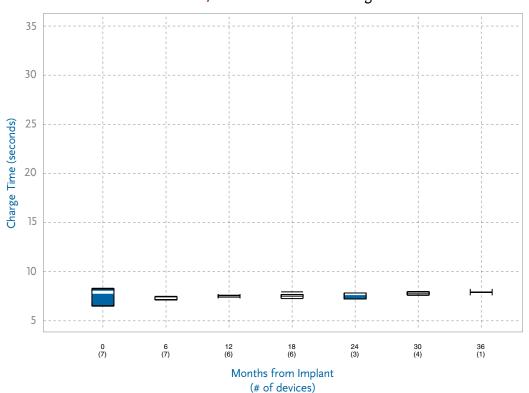






Save-to-Disk files have been collected 12 months post-implant. All observed charge times are less than 12 seconds with a maximum of 10.91 seconds observed at implant.

D153ATG, D153DRG EnTrust Charge Time



Save-to-Disk files have been collected 24 months post-implant. All observed charge times are less than 9 seconds with a maximum of 8.31 seconds observed at implant.

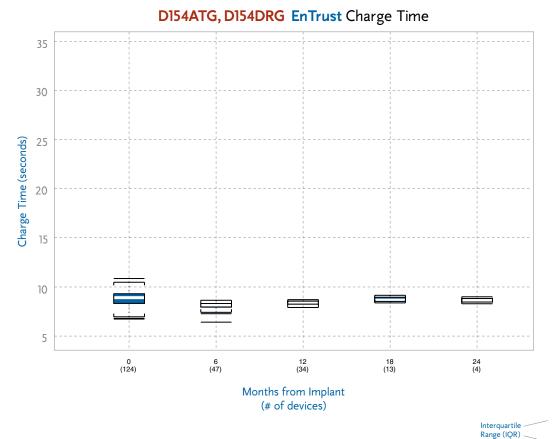
75th Percentile

25th Percentile

Median +/- 1.5 IQR

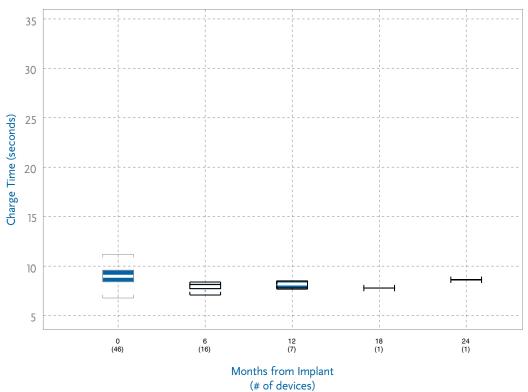
Interquartile

Range (IQR)



Save-to-Disk files have been collected 18 months post-implant. All observed charge times are less than 11 seconds with a maximum of 10.85 seconds observed at implant.



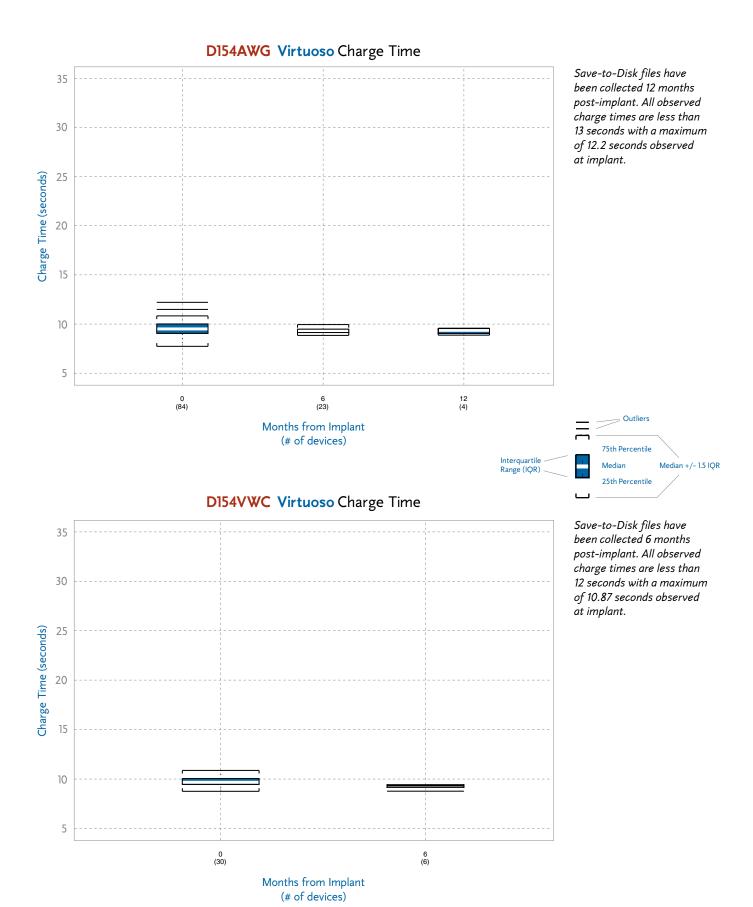


Save-to-Disk files have been collected 12 months post-implant. All observed charge times are less than 12 seconds with a maximum of 11.19 seconds observed at implant.

75th Percentile

25th Percentile

Median +/- 1.5 IQR



Advisories

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Models 6930, 6931, 6948, and 6949 Implantable Defibrillation Leads.

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

As of October 4, 2007, there have been approximately 268,000 Sprint Fidelis leads implanted worldwide and based on information available, we identified five patient deaths in which a Sprint Fidelis lead fracture may have been a possible or likely contributing factor. We had confirmed 665 chronic fractures in returned leads. Approximately 90% of these fractures occurred in the anode or cathode conductors, while 10% occurred in the high voltage conductors.

As of October 4th, 2007, Returned Product Analysis of Sprint Fidelis leads showed a survival of 99.2% at 30 months. However, Returned Product Analysis overstates actual performance since it does not account for leads that are not returned. The Medtronic SLS data for the Model 6949 Sprint Fidelis lead indicated 97.7% [+1.3/-3.0] all-cause lead survival at 30 months. This was consistent with our analysis of Medtronic CareLink Network data from approximately 25,000 Sprint Fidelis leads, which indicated 97.7% [+0.6/-0.8] survival at 30 months.

As of October 4th, 2007, these survival rates were not statistically different from the all-cause lead survival of 99.1% [+0.4/-0.8] for the Model 6947 Sprint Quattro lead at 30 months from the SLS. However, we expect this difference will become statistically significant over time if the current failure rates remain constant.

Patient Management Recommendations

Medtronic recommends you consider the following as part of routine follow-up for each patient.

To reduce the risk of inappropriate detection and therapy due to oversensing, program VF detection for initial Number of Intervals to Detect (NID) to nominal settings (18/24) or longer at physician discretion and Redetect NID to nominal settings (12/16).

- Turn ON Patient Alert for RV Pacing, RV Defibrillation, and SVC Defibrillation impedance. For Concerto and Virtuoso devices enrolled on the Medtronic CareLink Network, turn ON the Medtronic CareAlert notifications for these same parameters.
- To optimize effectiveness of the lead impedance alert:
 - Review V Pacing Lead Performance Trend to determine typical chronic impedance value for the patient (typical values for Fidelis leads should be 350-1,000 ohms).
 - Program lead impedance alert threshold for RV Pacing to 1,000 ohms, if the typical chronic impedance for the patient is ≤ 700 ohms, or
 - Program lead impedance alert threshold for RV Pacing to 1,500 ohms, if the typical chronic impedance for the patient is > 700 ohms.
 - Program lead impedance alert threshold for RV Defibrillation and SVC Defibrillation to 100 ohms.

The patient management recommendations set forth above should increase the likelihood that a fracture will be detected by Patient Alert and/or Medtronic CareAlert notifications and decrease the likelihood of inappropriate therapies. Based on our review of the available data, there does not appear to be a benefit to more frequent follow-up.

Medtronic's Independent Physician Quality Panel believes it is inappropriate to prophylactically remove Sprint Fidelis leads except in unusual individual patient circumstances. Medtronic supports this position.

Lead extraction carries risks that should be considered in patient management. Published literature suggests major complications (death or surgical intervention) from lead extraction range from 1.4-7.3%. As always, with confirmed lead failure the risk of extraction should be weighed against the risk of adding an additional lead (see Appendix D of the physician letter).



Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at http://SigmaSNList.medtronic.com.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

Our modeling predicts a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. No provocative testing can predict which devices may fail.

Patient Management Recommendations

To assist physicians in their patient care and after discussion with physician consultants, Medtronic offers the following recommendations:

- Medtronic does not recommend replacement of these devices prior to normal elective replacement (ERI), based on the low probability of occurrence of a serious event in this population.
- Continue routine follow-up in accordance with standard practice.
- Advise patients to seek attention immediately if they experience return of symptoms (e.g., syncope or light-headedness).
- Determine whether device replacement is warranted on a case-by-case basis based upon consultation with patients, review of the individual

patient's medical history, and consideration of the relative risks of an invasive procedure.

Status Update (July 2007)

The Sigma Family device performance related to the interconnect wires separation mechanism continues to be within Medtronic's engineering projections. As of July 31, 2007, 102 devices out of approximately 40,000 devices worldwide (0.24% incidence) have been confirmed as having experienced interconnect wire separation while implanted. Thirty-five (35) of these devices were returned from the United States. There have been no confirmed serious injuries or deaths due to this issue.

Fifty-seven (57) of the 102 devices were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 45 devices were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Implant duration for the 102 devices confirmed as having experienced interconnect wire separation has ranged between 17 and 61 months, with an average of 46 months.

Out of the initial advisory population of 40,000 worldwide, approximately 20,700 remain implanted. Approximately 4,800 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.



7274 Marquis DR 7230 Marquis VR

7278 Maximo DR 7232 Maximo VR

7277 InSync Marquis 7289 InSync II Marquis 7279 InSync III Marquis **7285** InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Specific model and serial numbers of affected devices are available online at http://MarquisSNList.medtronic.com.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

- Conduct quarterly (i.e., every three months) follow-up procedures.
- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly.
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.

 Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, followup care should be sought promptly.

Status Update (July 2007)

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of July 31, 2007, 91 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. Fifty-two (52) of these devices were returned from the United States. There have been no confirmed serious injuries or deaths due to this issue.

Of the 91 returns, 33 have been identified by patients reporting warmth in the ICD pocket, 36 by a regularly scheduled follow-up or during a nondevice related hospital visit, 11 by hand-held magnet test or CareLink attempt, 7 by return of bradycardia symptoms, and 4 by the Patient Alert sounding.

Implant duration for the 91 devices ranged between 11 to 53 months, with an average of 34 months.

Consistent with Medtronic projections, the observed rate of shorting is higher in the second half of device life than in the first half of device life. Of the devices that have exhibited shorting in the last half of device life, 46% occurred in the last quarter of device life and 29% in the last 10% of device life.

Out of the initial advisory population of 87,000 worldwide, approximately 33,600 remain implanted. Approximately 29,500 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Warranty

All Marquis devices are subject to a Limited Warranty. Devices returned to Medtronic and determined to be malfunctioning will be replaced or credited in accordance with the warranty terms. In addition, for devices subject to the Marquis advisory, should a physician decide to replace a device for a patient who is pacemaker dependent or who receives frequent VT/VF therapy, Medtronic will, upon receipt of a written statement from the physician setting forth the basis for early replacement of the device, provide a replacement device at no cost.



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 Dual Chamber (D, DR, and VDD) Implantable Pulse Generators have been identified by serial numbers. Hospitals and Physicians were notified. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 505-4636.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 Dual Chamber (D, DR, and VDD) Series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free-of-charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. As of July 31, 2007, 276 out of approximately 180,000 (0.15% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred thirty-nine (139) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, approximately 50,000 remain implanted.



7227Cx GEM 7229Cx GEM II VR

Original Date of Advisory: October 15, 1999

Potential Circuit Overload

Product

Model 7227Cx and Model 7229Cx Implantable Cardioverter Defibrillators supplied before October 15, 1999, with serial numbers ending in an "H." For example, PIPxxxxxxH or PJJxxxxxxH, where x is a variable numeric, may be affected. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 723-4636.

IMPORTANT REMINDER:

Medtronic strongly advises physicians who have patients under their care affected by this issue to reprogram the Patient Alert feature "ON" without delay.

Advisory

Manufacturing error in a small percentage of devices may cause circuit overload when $AX \ge B$ High Voltage energy is delivered via an integrated bipolar lead. GEM Model 7227Cx and GEM II VR Model 7229Cx devices with dedicated bipolar sensing leads are not affected by this issue. Devices affected may not be able to subsequently charge to full energy and experience "charge circuit timeout."

Patient Management Recommendations

- Assessment of all patients with the potentially affected devices implanted AND an integrated bipolar ICD lead such as the 6942 and 6945 should take place without delay.
- Reprogram polarity pathway to $B \ge AX$ for all cardioversion and defibrillation therapies.
- Confirm correct device function:
 - Perform a full energy charging sequence.
 - If "charge circuit timeout" is observed, contact your Medtronic representative.
 - If device charges normally, it has not been damaged and will function appropriately with polarity programmed $B \ge AX$.

Recent studies have demonstrated that DFTs are similar or lower in a $B \ge AX$ polarity pathway when compared to $AX \ge B$.

Devices implanted with functional dedicated bipolar leads such as the 6932, 6934S, 6936, 6943, and 6966 are not affected.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 10,000 in the United States, approximately 2,500 remain implanted. The devices affected by this advisory are nearing the end of their expected battery longevity.



4504, 4504M CapSure Atrial Lead 4582 Target Tip Atrial Lead

Original Date of Advisory: October 4, 1996

Lead Survival Below Expectations

Product

All Models 4504, 4504M, and 4582 Implantable Pacing Leads

Advisory

Lead survival probability is below expectations and is primarily associated with insulation degradation due to Metal Ion Oxidation (MIO).

Patient Management Recommendations

- Follow patients in accordance with Medicare Guidelines.
- Avoid the use of the AAI or AOO mode.
- During patient evaluation, give careful attention to lead performance such as:
 - Review patient ECG for indications of transient sensing and/or capture abnormalities.
 - Monitor in clinic for impedance less than 250 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
- Consider the use of unipolar if the pulse generator has this capability.
- At the time of pacemaker system revision (e.g., normal pulse generator or ventricular lead revision), carefully evaluate lead integrity and patient status before choosing to reuse.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 16,600 in the United States, approximately 1,600 remain implanted. According to System Longevity Study results, lead survival is estimated to be 66.1% at 8 years, 11 months.



4004, 4004M CapSure Ventricular Lead 4082 Target Tip Ventricular Lead

Original Date of Advisory: October 8, 1993

Lead Survival Below Expectations

Product

All Models 4004/4004M and 4082 Implantable Pacing Leads

Advisory

Lead survival probability is below expectations due primarily to polyurethane insulation failure (MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

- Increase, as appropriate, the frequency of patient evaluation through in-clinic visits supplemented with transtelephonic and/or ambulatory monitoring; for example, consistent with Guideline I under Medicare Pacemaker Monitoring Guidelines (50-1 Cardiac Pacemaker Evaluation Services).
- During patient evaluations, give careful attention to lead performance such as:
 - Reviewing patient ECGs carefully for indications of transient sensing and/or capture abnormalities.
 - Monitoring in-clinic for impedances less than 300 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
 - Eliciting and thoroughly investigating any patient complaints suggestive of lead failure.

- Consider whether prophylactic replacement would be appropriate, especially in patients at high risk, such as pacemaker dependent patients.
- Carefully evaluate lead integrity when performing routine pulse generator replacements. Replace lead if
 - insulation breaches are observed.
 - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
 - impedance or voltage threshold measurements vary significantly when multiple readings are taken.
 - if the risk of continued use outweighs the risk associated with implanting a new lead.
- As always, individual circumstances and medical judgment dictate patient care and frequency of follow-up.
- Consider lead replacement during normal pulse generator change-out. Carefully evaluate lead integrity and patient status before choosing to reuse.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 77,000 in the United States, approximately 3,200 remain implanted. According to System Longevity Study results, lead survival is 50.6% at 10 years, 9 months.



4012 Target Tip Ventricular Lead

Original Date of Advisory: September 26, 1991

Lead Survival Below Expectations

Product

All Model 4012 Implantable Pacing Leads

Advisory

Lead survival probability beyond 5 years is below expectations due primarily to polyurethane insulation failure (due to ESC and/or MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

Consider increasing frequency of monitoring (e.g., from quarterly to bimonthly or monthly). Consider the following activities as part of normal follow-up procedures:

- Monitor for significant changes in impedance which could be an indication of impending failure (pulse generator must have impedance telemetry capabilities).
- Review patient ECGs carefully for indications of transient sensing and/or capture abnormalities. This can be done using transtelephonic or in-clinic monitoring and/or using ambulatory monitoring.
- Elicit any patient complaints suggestive of lead failure and investigate thoroughly lead integrity/ performance characteristics following reports of patient complaints or symptoms using the above techniques.

- Consider whether prophylactic replacement would be appropriate in patients at high risk, such as pacemaker dependent patients.
- Evaluate carefully the integrity of the lead during routine pulse generator replacement before choosing to reuse. Specifically, Medtronic recommends placement of a new lead if:
 - insulation breaches are observed.
 - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
 - electrical properties such as impedance and threshold vary significantly when multiple readings are taken.

As always, medical judgment must be used to establish the appropriate schedule and course of care for every individual, particularly pacemaker dependent or other patients at higher risk.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 96,800 in the United States, approximately 5,700 remain implanted. The System Longevity Study results show 62.2% lead survival at 15 years, 9 months.



Minix, Minix ST, Micro Minix IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix, Minix ST, and Micro Minix families of Implantable Pulse Generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE KEY and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 5,000 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Performance Notes

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of this Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- the amount of electrical energy expended in providing therapy to the patient
- the amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- the energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

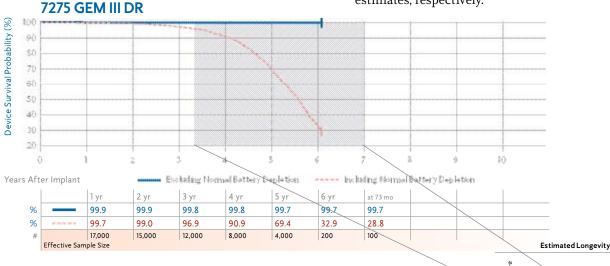
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates, originally published in the device Technical Manual, are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve for the Model 7275 ICD. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.

Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation.

Purpose of this Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients. Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.⁵ Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats.⁶ In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)7-9 or VVI 40 pacing modes¹⁰, the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/VF across pacing modes.11

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. 12,13 MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.9 However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing,13,14 may lead to endless loop tachycardia,14,15 and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications which prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony vs. ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

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AT500 Pacing System Follow-Up Protocol

Purpose of this Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below End-of-Life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform trans-telephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves at **common parameter settings** are shown in Figure 1, with special focus on device longevity when programming EGM pre-storage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON.
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM pre-storage, or Holter Telemetry features.

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/ replacement occurs prior to End-of-Life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM pre-storage is programmed ON, or higher outputs and/or pacing rates are necessary.



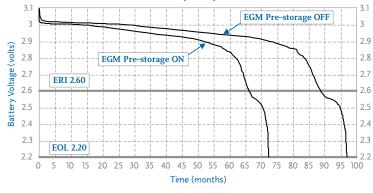


Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial - 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least 1 lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the technical article, "Clinical Management of High Voltage Lead System Oversensing."

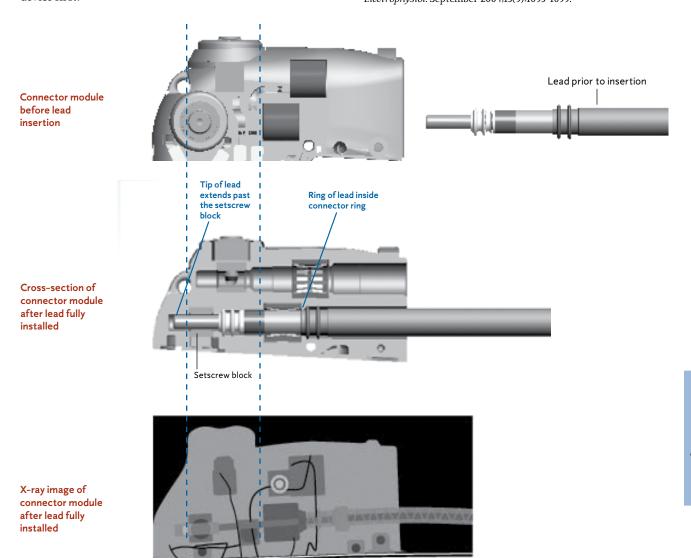
Performing the following steps can be used for each lead connection during the implant procedure.

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactures and utilizes a unique Lithium/Silver Vanadium Oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching Middle-of-Life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

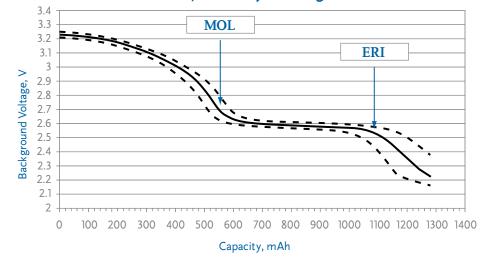
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the recently released Marquis battery has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the non-sustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture.
- Elicit and investigate any patient complaints/symptoms which may be suggestive of potential lead failure.

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert™ and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors which should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels.
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation.
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads. 1-3 Ultimately, the decision to replace an implanted lead involves medical judgment.
 - ¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. PACE. June 2002;25(6):879-882.
 - ² Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. J Am Coll Cardiol. January 1, 2003;41(1):73-80.
 - ³ Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early Failure of a Small Diameter High Voltage Implantable Cardioverter Defibrillator Lead, Heart Rhythm (2007), doi:10.1016/ j.hrthm.2007.03.041

Clinical Management of High Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T-waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus ICD systems attempt to dynamically adjust sensing of electrical events, and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T- and far field P-waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high voltage therapies. This is due, in part, to the desire to err on the side of delivering life-saving high voltage therapy rather than withholding it. Thus, an ICD system which is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/far field sensing, electromagnetic interference, T-wave sensing, connector issues, incomplete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far Field Sensing	Diaphragmatic muscle potentials in breathing, wide tip-ring (coil on integrated bipolar leads) spacing.	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks.	Check R-waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change- out to true bipolar lead, or if true bipolar lead in use, one with closer tip-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment.	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave Sensing	Drugs, ischemic tissue, exercise, long QT syndrome, electrolyte imbalance.	Sense markers seen on EGM related to T-wave. False positive detection.	Check for R-wave deterioration and characteristics. If R-wave > 3.0 mV, reprogram sensitivity. If R-wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs lif appropriate/medically viablel).
Connector Problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header.	This is an acute phenomenon seen within 6 months of implant (usually sooner).	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete Conductor Fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit.	Characterized by chaotic oversensing related to motion of the fracture site.	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead Insulation Breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking.	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives.	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement Perforation Electrolyte Imbalance Improper IPG/Lead Connection	. Increase or Decrease . Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	.Increase .Increase .Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P- and/or R-Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P- and/or R- Waves	Dislodgement Perforation Infarct at Electrode Site Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Decrease Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

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Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits (pictured right) with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab.

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Phone: 1 (800) 328-2518, ext. 44800

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